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AN ANALYSIS OF THE REGRESSION MODEL FOR
NONSATURATING LOGIC CIRCUIT ANALYSIS

by

George Donald Wood

May 10, 1968

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Report No. 273

AN ANALYSIS OF THE REGRESSION MODEL FOR
NONSATURATING LOGIC CIRCUIT ANALYSIS*

by

George Donald Wood

May 10, 1968

Department of Computer Science
University of Illinois
Urbana, Illinois 61801

*

* This work was supported in part by the Advanced Research Projects Agency as administered by the Rome Air Development Center under Contract No. US AF 30(602)4144 and submitted in partial fulfillment of the requirements for the degree of Master of Science in Electrical Engineering, June, 1968.

ACKNOWLEDGEMENT

The author acknowledges with pleasure the assistance and encouragement of Professor Richard M. Brown, whose many helpful comments and suggestions contributed greatly to this thesis project. Also, Professor Thomas A. Murrell, in whose researches the problem treated here originated, contributed much time and many useful suggestions during a number of thoughtful discussion periods.

The author would also like to express his sincere gratitude to the Department of Computer Science of the University of Illinois and to the ILLIAC IV project for providing financial support for a portion of this project.

Many thanks are also due to Mrs. Mildred Pape for her diligent and careful typing of the manuscript.

TABLE OF CONTENTS

	Page
1. INTRODUCTION	1
2. THE DEVELOPMENT OF THE REGRESSION MODEL AND ITS RELATIONSHIP TO CONVENTIONAL CIRCUIT MODELING	7
2.1 <u>Basic Modeling Elements</u>	7
2.2 <u>Small Signal Parameter Models</u>	9
2.3 <u>Piecewise Linear Model Construction</u>	13
2.4 <u>Ideal Diode Model Construction</u>	16
2.5 <u>The Regression Model</u>	21
3. COMPARISON OF TWO COMPUTER PROGRAM CIRCUIT ANALYSIS METHODS	30
3.1 <u>Discussion of a Basic Circuit Analysis Problem</u>	30
3.2 <u>Solution of the Current Convergence Problem - Matrix Partition Method</u>	30
3.3 <u>Solution of the Current Convergence Problem - Regression Model Method</u>	39
3.4 <u>Cutoff Conditions and the Regression Model.</u>	49
3.5 <u>Extension of the Regression Model</u>	53
3.6 <u>Conclusion</u>	54
4. APPLICATION OF NLAP TO LOGIC CIRCUIT ANALYSIS	63
4.1 <u>Introduction</u>	63
4.2 <u>Preparation of NLAP Input Data Deck</u>	63
4.3 <u>Solution Control Codes</u>	67
4.4 <u>Solution Output and Identification</u>	68
4.5 <u>Conclusion</u>	69
REFERENCES	72

APPENDIX

A.	A NETWORK ANALYSIS PROCEDURE	75
1.	<u>Introduction</u>	75
2.	<u>Matrix Equation Formulation</u>	75
B.	REGRESSION MODEL SUBROUTINE	84
1.	<u>Subroutine Iterate Listing</u>	84
2.	<u>Comments on Program Changes</u>	92
C.	LINEAR REGRESSION PROGRAM	93
1.	<u>Linear Regression Program Listing</u>	93
2.	<u>Typical Output</u>	99
3.	<u>Instructions for Preparing Linear Regression Program Control Cards</u>	103
4.	<u>Typical Input Data Deck</u>	106
5.	<u>Linear Regression Input Data Transformation Program</u>	108
D.	REGRESSION MODEL EFFECTIVENESS PROGRAM	109
1.	<u>Regression Model Effectiveness Program Listing</u>	109
2.	<u>Typical Output</u>	110
3.	<u>Program Comments</u>	112
4.	<u>Typical Input Data Deck</u>	114
E.	NLAP OUTPUT SUBROUTINE LISTING	115

LIST OF FIGURES

Figure	Page
1. Two Forms of Emitter Coupled Logic (ECL)	2
2. Emitter Coupled Logic Transfer Characteristic	3
3. Dependent Sources and Their Voltage-Current Characteristics	8
4. Computer Program for Calculating $I_C = f(I_B)$	14
5. Piecewise Linear Approximation of a Function	15
6. C1 Transistor Common Emitter Output Characteristic	17
7. Stepwise Development of an NPN Common Emitter Transistor Model	19
8. Comparison of Hybrid and ECAP Transistor Models	22
9. Regression Model with Equations	24
10. C1 Transistor Base to Emitter Voltage Versus Collector Current	28
11. C1 Transistor Current Gain Versus Collector Current	29
12A. Oven Heater Driving Amplifier Schematic Diagram	31
12B. Oven Heater Driving Amplifier Equivalent Circuit	32
13. Dependent Current Generator Matrix	34
14. Independent Voltage Source Matrix	35
15. Coefficient Matrix Element Values	37
16. Impedance Matrix Element Values	38
17. NLAP Common Emitter Test Circuit	41
18. ECAP Standard Branch	42
19. Nodal Conductance Matrix with BETA Explicitly Shown	47

Figure	Page
20. Nodal Equivalent Current Vector with BETA and V_{BE} Explicitly Shown	48
21. Flow Chart of Iterative Regression Model Solution Method	55
22. DC Solution Matrix Obtained Prior to Iteration . .	56
23. NL Solution Matrix Obtained After Completion of Iteration	57
24. Nodal Conductance Matrix Calculations for BETA = 50	58
25. Nodal Current Vector Calculations for BETA = 50 and $V_{BE} = -1.25$ Volts	59
26. OR Emitter Follower Voltage Offset Characteristic .	61
27. OR Emitter Follower Schematic Diagram	62
28. NLAP Calling Sequence	64
29. Typical NLAP Input Data	66
30. Typical NLAP 133 Column Solution Printed Output . .	71
A1. An Equivalent Network	76
A2. Branch Level E, JG, V, and I Matrices	77
A3. Branch Level Z and A Matrices	78
A4. Network Analysis Program	82
A5. Output of Network Analysis Test Program	83

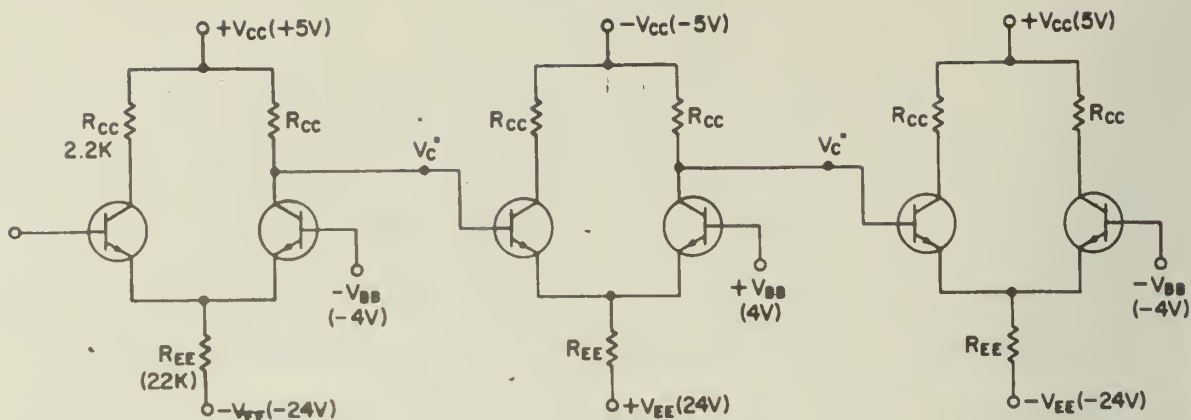
LIST OF TABLES

Table		Page
1.	Analysis of Regression Equation for BETA, $C_1 V_{CE} = 3.0 V_{DC}$	51
2.	Analysis of Regression Equation for V_{BE} , C_1 $V_{CE} = 3.0 V_{DC}$	52
3.	Summary of NLAP Output Variable Storage Arrays . . .	70

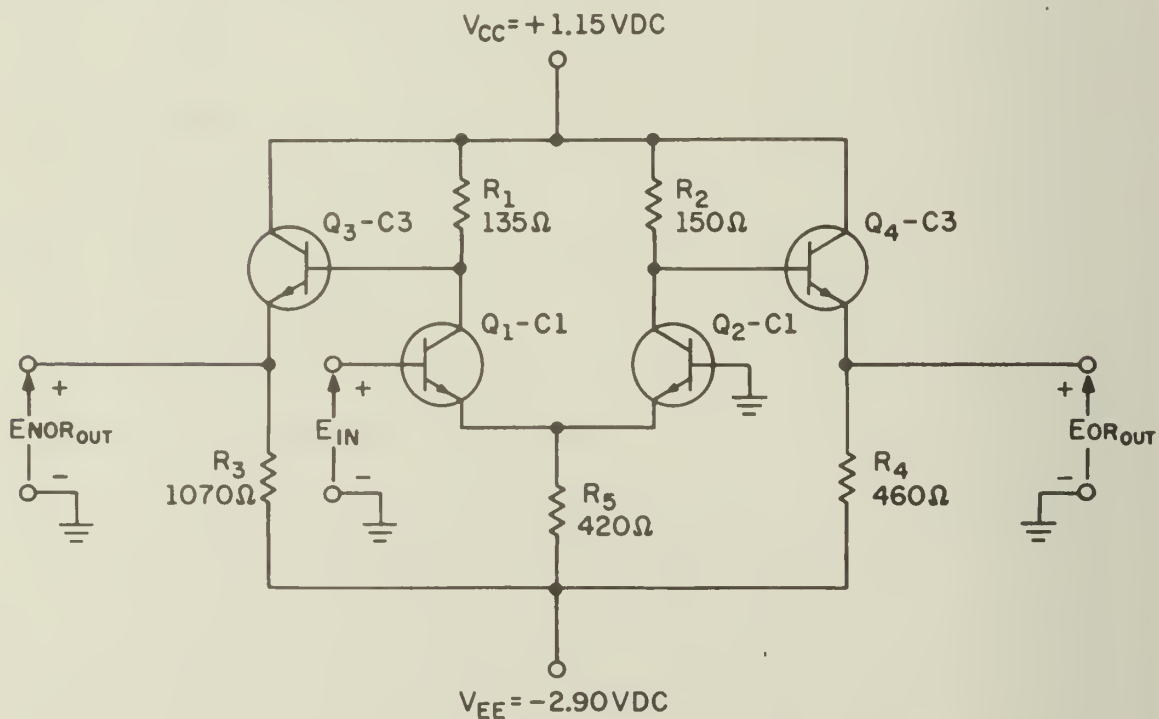
1. INTRODUCTION

Many approaches to the computer aided design problem¹ are being studied. To date these efforts have not resulted in the general availability of automatic circuit design programs². If, however, one subdivides the electronic circuit design process somewhat, one of the principle facets which emerges is the need for a through analysis capability. With such a tool available to the designer, electronic system response may be simulated over the entire space of component variations and operating conditions.

One of the fundamental steps in designing electronic circuits is the choice of the "static d.c." or quiescent operating point. Its optimization is often an iterative process. An example, from logic circuit design, occurs when designing emitter coupled logic circuits³ such as those of Figure 1. The typical design process requires that a number of interdependencies be met in order to obtain the nonsaturating output characteristics of Figure 2. The process begins with the selection of the voltage levels representing each binary state. The on and off state base-to-emitter voltages may be determined by superimposing⁴ the source line upon a set of the transistor's input characteristic curves. The output levels are next determined for various loadings, such as the next stage of Figure 1A, or the output level restoring emitter followers of Figure 1B, using the transistor's output characteristic curve family. This procedure is then repeated for varying input and output conditions to insure the convergence of the logic levels⁵ to the desired voltage levels.



A) Complementary Direct Coupled ECL



B) Emitter Follower Buffered ECL

Figure 1. Two Forms of Emitter Coupled Logic (ECL)

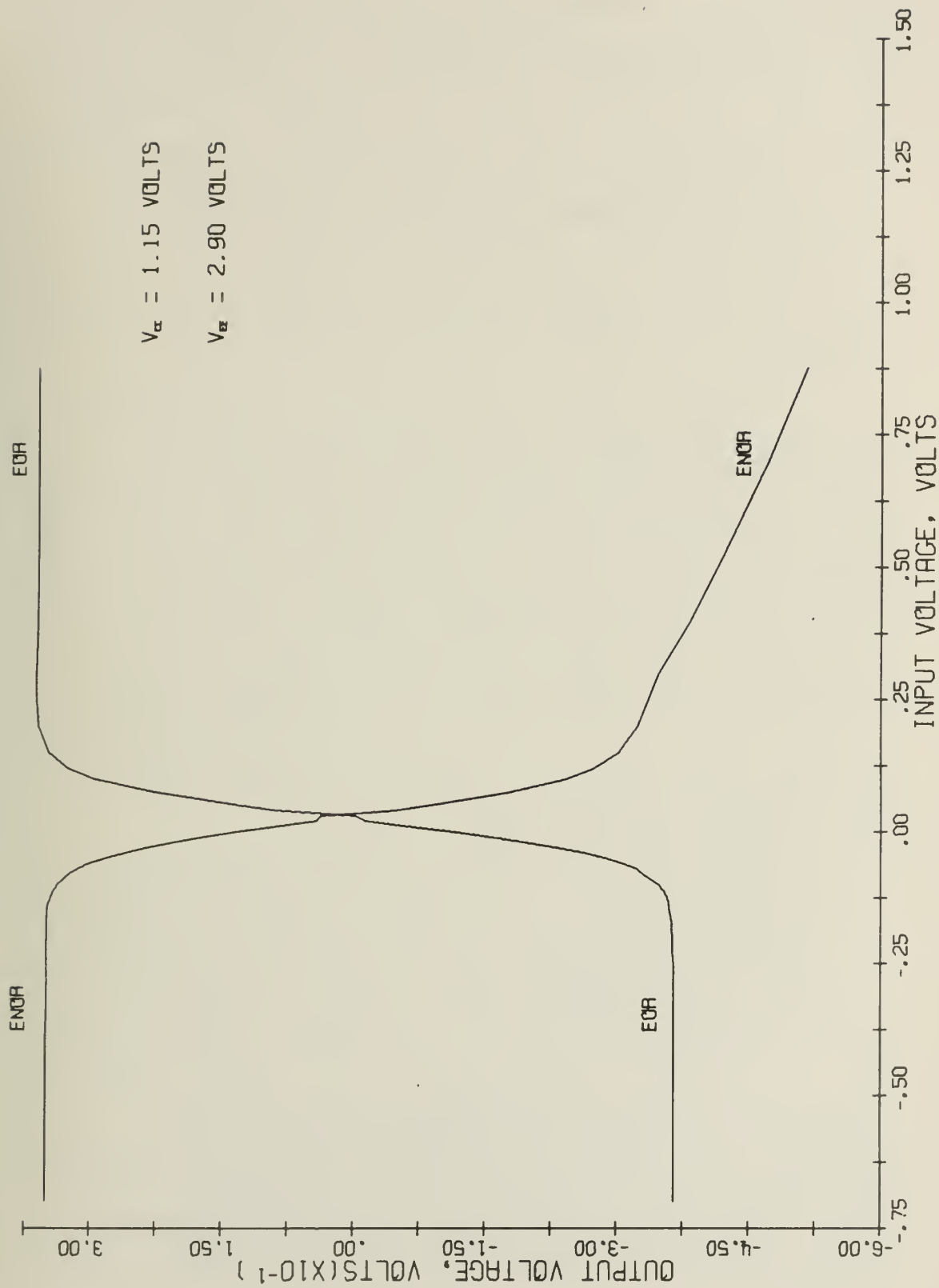


Figure 2. Emitter Coupled Logic Transfer Characteristic

The amount of calculation required for effective design of an emitter coupled logic block can be substantial due to the numerous iterations which may be needed to prove satisfactory operation under varying tolerance conditions. The point being made here is that the circuit designer could save a significant amount of computation time by employing a flexible computer program whose output could be, for example, the emitter coupled logic circuit's output voltage transfer characteristic.

The above "static" design discussion employed graphical analysis which has been a standard circuit design tool⁶ for many years. Introductory electronic circuit texts introduce this approach as being the best way to handle nonlinear circuit elements and indeed it is for simple exploratory analysis. However, for computer-aided design, such as is possible with a parameter variation program, it is necessary to enter the transistor's characteristics in the form of equations. These equations are known as the transistor modeling equations and may take many forms.

Some of the models currently used are: Ebers-Moll, Piecewise Linear, Admittance or Y Parameter, Hybrid or H Parameter, Z matrix, and the M Parameter Model. Each model evolved for the purpose of simulating some portion of a transistor's range of operation. No analysis or simulation program can be effective unless the transistor model used accurately represents the transistor's voltage-current behavior throughout the region of operation in the simulated circuit. For this reason, the basis of each of the above models will

be discussed in section 2 in order that they may be compared with a new model⁷ related to the Z matrix model but including the additional constraints:

$$\text{BETA} = A_0 + A_1 \left(\ln \frac{I_C}{I_0} \right) + A_2 \left(\ln \frac{I_C}{I_0} \right)^2$$

$$V_{BE} = B_0 + A_1 \left(\ln \frac{I_C}{I_0} \right) + A_2 \left(\ln \frac{I_C}{I_0} \right)^2$$

These additional constraints are formed by the Linear Regression program of Appendix B whose input data points are taken from measurements or from manufacturer's data sheets. This Regression Model thereby enables the designer to employ linear equation solution methods to obtain a nonlinear solution to his circuit problem. Thus the quantities BETA and V_{BE} are no longer restricted to constant values as is the usual case.

The usefulness of the Regression Model rests upon the ease of its application and upon the accuracy of its predictive capability. In an effort to satisfy the first goal, the Regression Model subroutine written by Guth⁸ was converted from IBM 1620 compatible language to FORTRAN IV for use on the IBM 360 Model 75 as a part of this thesis project.

In the process of conversion a new version of ECAP⁹ became available which provided true worst case solutions. This new version of ECAP was modified to work with an updated version of Guth's subroutine, a listing of which is given in Appendix B of this thesis.

The complete program is now called NLAP (Nonlinear Analysis Program) and is contained in the program library at the Department of Computer Science, University of Illinois. The NLAP calling sequence is given in Appendix E, together with the input and output of a test program.

The final goal posed for this thesis was to evaluate the possibility of extending the useful range of the Regression Model from the normal active region to include operation in the cutoff region as is encountered in emitter coupled logic circuit operation. The evaluation of this extension, together with a discussion of the IBM 360 ECAP network solution method, will be presented in section 3.

The application of NLAP to the solution of transistor logic circuits is discussed in section 4. The required topological codes are given for the various types of branch level statements. Two illustrative examples are presented as a further guide. It is recommended that the user consult sections 3.4 through 3.6 before undertaking use of the NL solution option discussed in section 4.3.

2. THE DEVELOPMENT OF THE REGRESSION MODEL AND ITS RELATIONSHIP TO CONVENTIONAL CIRCUIT MODELING

2.1 Basic Modeling Elements

The basic components for an electronic model are the idealized pure resistance (R), pure inductance (L), and pure capacitance (C) elements of linear and reciprocal network theory. Their elemental voltage-current relationships are simply Ohm's law. To form a compact set of elements, it is necessary to add the controlled source for modeling of the amplification process and the ideal junction diode for simulating variable amplitude, unilateral transmission.

Dependent current and voltage controlled sources are of four¹⁰ possible types; voltage controlled voltage, voltage controlled current, current controlled voltage, and current controlled current. The internal impedances of these sources are identical with their independent counterparts of linear network theory. The direction of output current flow, or of output voltage polarity, is dependent upon the driving source and may be of either polarity. The two port voltage-current relationships of each controlled source type, together with their schematics, are summarized by Figure 3.

The ideal junction diode has the voltage-current relationship:

$$i = i_0 (e^{qV/MKT} - 1).$$

This equation derives from a solution of the one-dimensional diffusion equation.¹¹ The factor M in the denominator of the exponent facilitates adjusting the theoretical V-I relationship to match that observed physically. Use of this ideal diode equation, together with the other

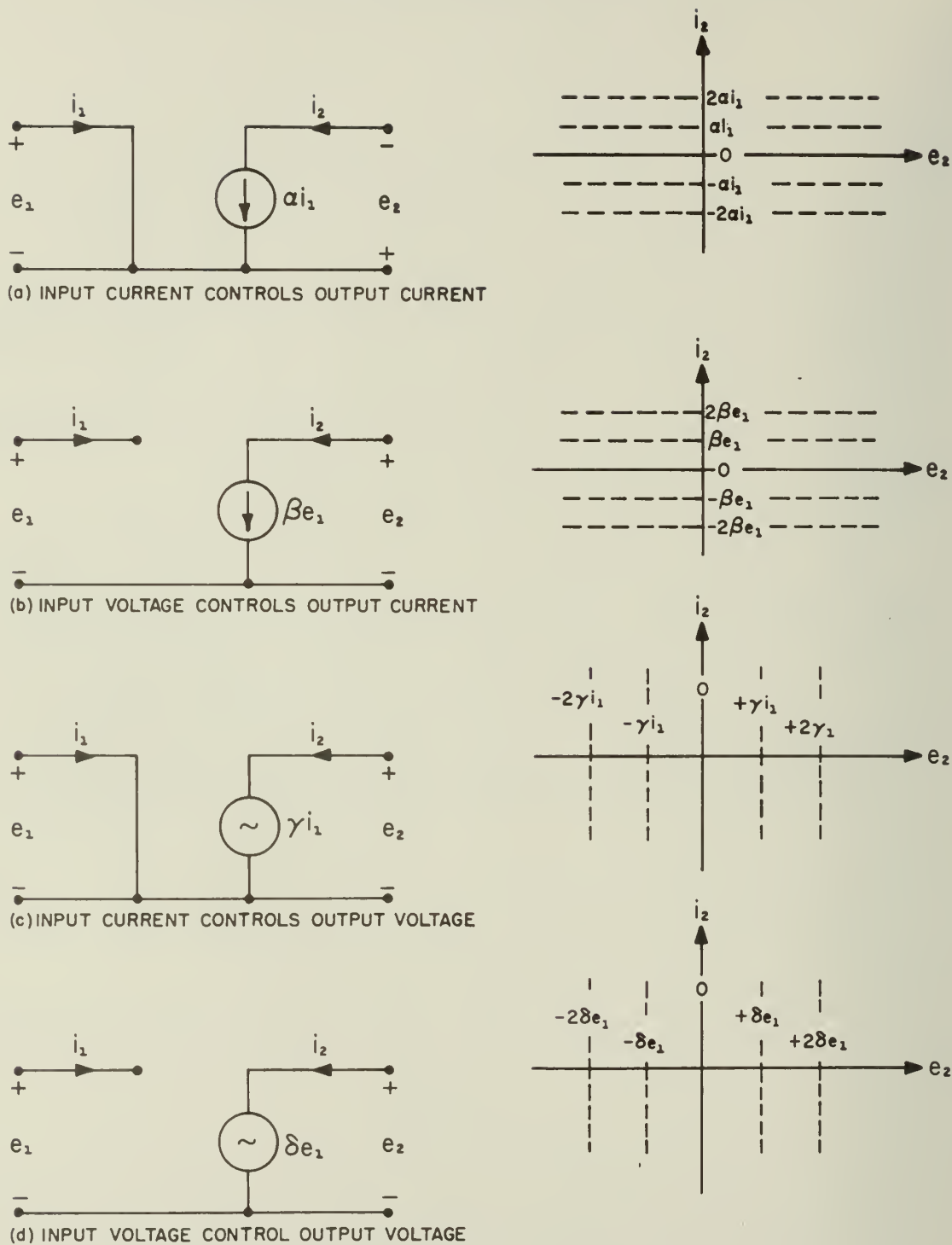


Figure 3. Dependent Sources and Their Voltage-Current Characteristics

four basic modeling elements, plus an independent current or voltage source element¹², are sufficient for most modeling work whether the circuit model be derived from basic physics or from the circuit "black box" approach.

2.2 Small Signal Parameter Models

A general network or "black box" may be described in terms of its two port parameters. At each port the voltage and input current are measured, providing four variables for network description. Any two of these quantities form a basis¹³ for the solution space of the network and, therefore, they completely characterize the network's behavior. The two port parameters may be established from a graphical plot by following the definitions established during their derivation.

One pair of general relationships between the two port voltages and current is:

$$e_1 = f(i_1, i_2)$$

$$e_2 = g(i_1, i_2)$$

These general functional relationships will in general be nonlinear. This creates the need for their transformation into linear functions for use in linear network analysis. Expanding in a Taylor series, with two independent variables, obtains:

$$e_1 (i_1, i_2) = e_1 (I_1, I_2) + \frac{\partial e_1}{\partial i_1} \left(i_1 - I_1 \right) + \frac{\partial e_1}{\partial i_2} \left(i_2 - I_2 \right)$$

$$\left| \begin{array}{l} i_1 = I_1 \\ i_2 = I_2 \end{array} \right| \quad \left| \begin{array}{l} i_1 = I_1 \\ i_2 = I_2 \end{array} \right|$$

+ higher order terms

$$e_2 (i_1, i_2) = e_2 (I_1, I_2) + \frac{\partial e_2}{\partial i_1} \left(i_1 - I_1 \right) + \frac{\partial e_2}{\partial i_2} \left(i_2 - I_2 \right)$$

$$\left| \begin{array}{l} i_1 = I_1 \\ i_2 = I_2 \end{array} \right| \quad \left| \begin{array}{l} i_1 = I_1 \\ i_2 = I_2 \end{array} \right|$$

+ higher order terms

provided $e_1 (i_1, i_2)$ and $e_2 (i_1, i_2)$ are analytic functions. The crucial point is that there are two ways for these Taylor expansions to reduce to linear functions. First, if the basic functional relationships are linear, then the value of all derivatives of higher order than one are zero. Second, if the operating point $Q (i_1, i_2)$ is selected such that the deviations $(i_1 - I_1)$ and $(i_2 - I_2)$ are small (thereby restricting the validity of related circuit calculations to "small signal") then the higher order Taylor series terms, $(i_j - I_j)^n$, become sufficiently small so as to become negligible.

Several changes of variables, such as:

$$e_j (i_1, i_2) = e_j (I_1, I_2) + \Delta e_j$$

yields the equations:

$$\Delta e_1 = \frac{\partial e_1}{\partial i_1} \left| \begin{array}{l} i_1 = I_1 \\ i_2 = I_2 \end{array} \right. \Delta i_1 + \frac{\partial e_1}{\partial e_2} \left| \begin{array}{l} i_1 = I_1 \\ i_2 = I_2 \end{array} \right. \Delta i_2$$

$$\Delta e_2 = \frac{\partial e_2}{\partial i_1} \left| \begin{array}{l} i_1 = I_1 \\ i_2 = I_2 \end{array} \right. \Delta i_1 + \frac{\partial e_2}{\partial i_2} \left| \begin{array}{l} i_1 = I_1 \\ i_2 = I_2 \end{array} \right. \Delta i_2$$

in which the quantities e_j 's and i_j 's are incremental by definition with one exception; the case where the basic function is sufficiently linear for all the higher partial derivatives to be at least close to zero.

The partial derivatives $\frac{\partial e_j}{\partial i_k}$ each have the dimensions of impedance. With this in mind, the incremental equations may be written in matrix form where the definitions of Z_{ij} are obvious by inspection.

$$\begin{bmatrix} \Delta e_1 \\ \Delta e_2 \end{bmatrix} = \begin{bmatrix} z_{11} & z_{12} \\ z_{21} & z_{22} \end{bmatrix} * \begin{bmatrix} \Delta i_1 \\ \Delta i_2 \end{bmatrix}$$

Now we arrive at the fortunate result where it is not necessary to assume¹⁴ small signal conditions in order to obtain a valid linear model of a transistor using "small signal Z parameters". However, it is necessary to locate those portions of the operating

regions for each transistor where all four z_{ij} 's are sufficiently linear before this is a valid model.

There are four¹⁵ other sets of "small signal" parameters:

A) The Y, or admittance parameters:

$$\begin{bmatrix} i_1 \\ i_2 \end{bmatrix} = \begin{bmatrix} y_{11} & y_{12} \\ y_{21} & y_{22} \end{bmatrix} * \begin{bmatrix} e_1 \\ e_2 \end{bmatrix}$$

B) The H, or hybrid parameters:

$$\begin{bmatrix} e_1 \\ i_2 \end{bmatrix} = \begin{bmatrix} h_{11} & h_{12} \\ h_{21} & h_{22} \end{bmatrix} * \begin{bmatrix} i_1 \\ e_2 \end{bmatrix}$$

C) The A, or transfer parameters:

$$\begin{bmatrix} e_1 \\ i_1 \end{bmatrix} = \begin{bmatrix} A & B \\ C & D \end{bmatrix} * \begin{bmatrix} e_2 \\ I_2 \end{bmatrix}$$

D) The M, or inverse hybrid parameters:

$$\begin{bmatrix} i_1 \\ e_2 \end{bmatrix} = \begin{bmatrix} m_{11} & m_{12} \\ m_{21} & m_{22} \end{bmatrix} * \begin{bmatrix} e_1 \\ i_2 \end{bmatrix}$$

Each of the above coefficient matrices, in its linear region may be arranged to represent common emitter, common base, or

common collector orientations through a series of well-known transformations¹⁶. In this respect this matrix representation is very useful for model construction.

In summary, the so-called small signal parameter models may form useful quiescent models in the regions where all four coefficients of each coefficient matrix are linear. However, lacking sufficient data on which to justify their use, the systems analyst should use a distinctly nonlinear model such as a Piecewise Linear Model, Ideal Diode Model, or Regression Model which is valid over the range of interest.

2.3 Piecewise Linear Model Construction

Another class of models may be generated using piecewise linear techniques¹⁷. The Piecewise Linear Models are also valid for a wide range of operating points provided a sufficient number of segments are employed. An example of a Piecewise Linear Model of a forward base-emitter diode coded in the Jovial subset of ALGOL is shown in Figure 4. In a computer program, such a model consists of logical statements defining the values at which the individual segments should be switched in and out of the model's network.

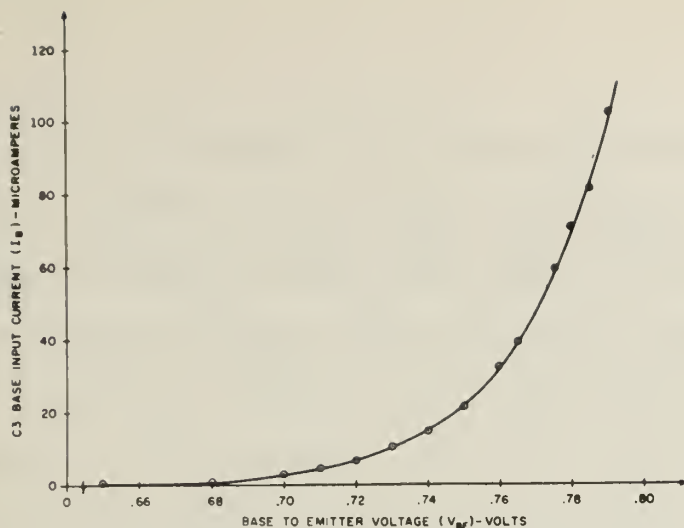
Construction of a Piecewise Linear Model begins with a graph of the objective function (Figure 5). A series of straight line segments are then constructed which, when appropriately summed, form the required objective function within the desired accuracy. An example Piecewise Linear Model for the I_B versus V_{BE} input characteristic of an NPN switching transistor is presented in Figure 5B. Several other

```

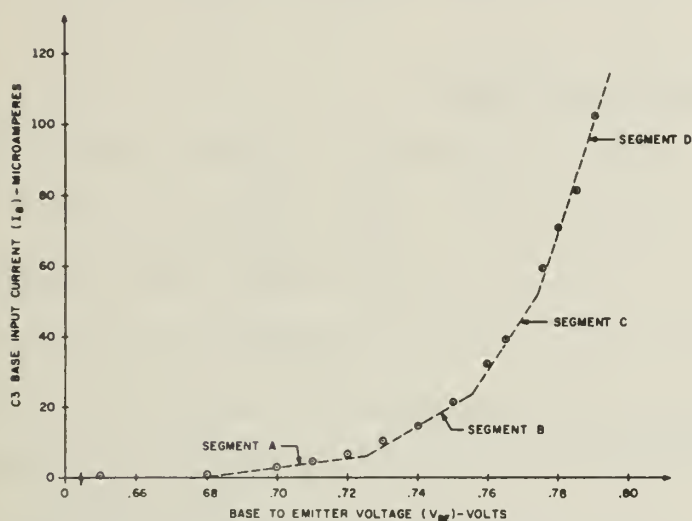
* 1.00 FLOAT;
* 2.00 READ E17;
* 3.00 Q5RS = 0.60;
* 4.00 ZO = 40;
* 5.00 FORMAT HD5,S20,C*CHARACTERISTICS OF TRANSISTOR Q5*//;
* 6.00 FORMAT HD5U,C*      IB      IC      HFE      RC      VSAT
* 7.00      VCE      VOUT      ES*/;
* 8.00 PRINT HD5;
* 9.00 PRINT HD5U;
* 10.00 FOR IB5 = 0.005, 0.005, 0.060;
* 11.00 BEGIN
* 12.00 IC5MAX = ((E17/ZO)-0.45)/13.09524;
* 13.00 IF IB5 GQ 0 AND IB5 LS 0.007;
* 14.00 IC5 = 52.5*IB5;
* 15.00 IF IB5 GQ 0.007 AND IB5 LS 0.014;
* 16.00 IC5 = 0.18 + 26.66667* 135;
* 17.00 IF IB5 GQ 0.014 AND IB5 LS 0.0325;
* 18.00 IC5 = 0.3 + 17.71429*IB5;
* 19.00 IF IB5 GQ 0.0325 and IB5 LQ IB5MAX;
* 20.00 IC5 = 0.45 + 13.09524*IB5;
* 21.00 Z1 = (E17/IC5)-ZO;
* 22.00 HFE = IC5/IB5;
* 23.00 VSAT = IC5*Q5RS;
* 24.00 VCE = IC5*Z1;
* 25.00 VOUT = E17 - IC5*(Z1+Q5RS);
* 26.00 ES = VSAT + VCE + VOUT;
* 27.00 FORMAT Q,F7.4,F10.3, F9.1,2F9.s,Sf8.2,F9.2;
* 28.00 PRINT Q,IB5,IC5,HFE,Z1,VSAT,VCE,VOUT,ES;
* 29.00 END
* 30.00 FORMAT QS,C* */ ,H8,F12.4,C* *///;
* 31.00 PRINT QS,8H(IB5MAX =),IB5MAX;
* PRINT COMPLETE

```

Figure 4. Computer Program for Calculating $I_C = f(I_B)$



A) C3 Emitter Diode Input Characteristic



B) Piecewise Linear Approximation

SegmentEquation

A $V_{BE_A} = 0.680 + 192.85 * I_B$

B $V_{BE_B} = 0.727 + 591.39 * I_B$

C $V_{BE_C} = 0.755 + 1569.23 * I_B$

D $V_{BE_D} = 0.774 + 3153.84 * I_B$

C) Piecewise Linear Equations

Figure 5. Piecewise Linear Approximation of a Function

approaches for generating piecewise linear models are given in Anner¹⁸, which is the most comprehensive reference on the subject. One constraint on the use of Piecewise Linear Models is that they must be entered into a computer program in segments whose equations must be switched in or out of the model as a function of V_{BE} by conditional program logic statements, such as the "IF statement" of FORTRAN IV¹⁹, in order for the total functional value $I_B = f(V_{BE})$ to be correct.

2.4 Ideal Diode Model Construction

Suppose a problem is given whose solution requires rather exact simulation of a transistor's output characteristic such as is depicted in Figure 6. This set of curves shows a set of measured, static characteristics of an Emitter-Coupled-Logic nanosecond switching transistor. Contrasting these with the voltage-current relationships of the controlled sources of Figure 3 suggests that with the application of appropriate mathematical nonnegativity²⁰ restrictions one could form a suitable model.

An effective way of realizing the nonnegativity restrictions is by adding ideal junction diode elements to the model. Thus, by employing the diode model in appropriate series and parallel configurations, the controlled sources for quadrant V-I characteristic may be transformed into the desired form. One possible algorithm using the current and voltage conventions of Figure 7A is:

- A) Shunt the controlled current source with an ideal resistive element, R_C , to provide a modified set of

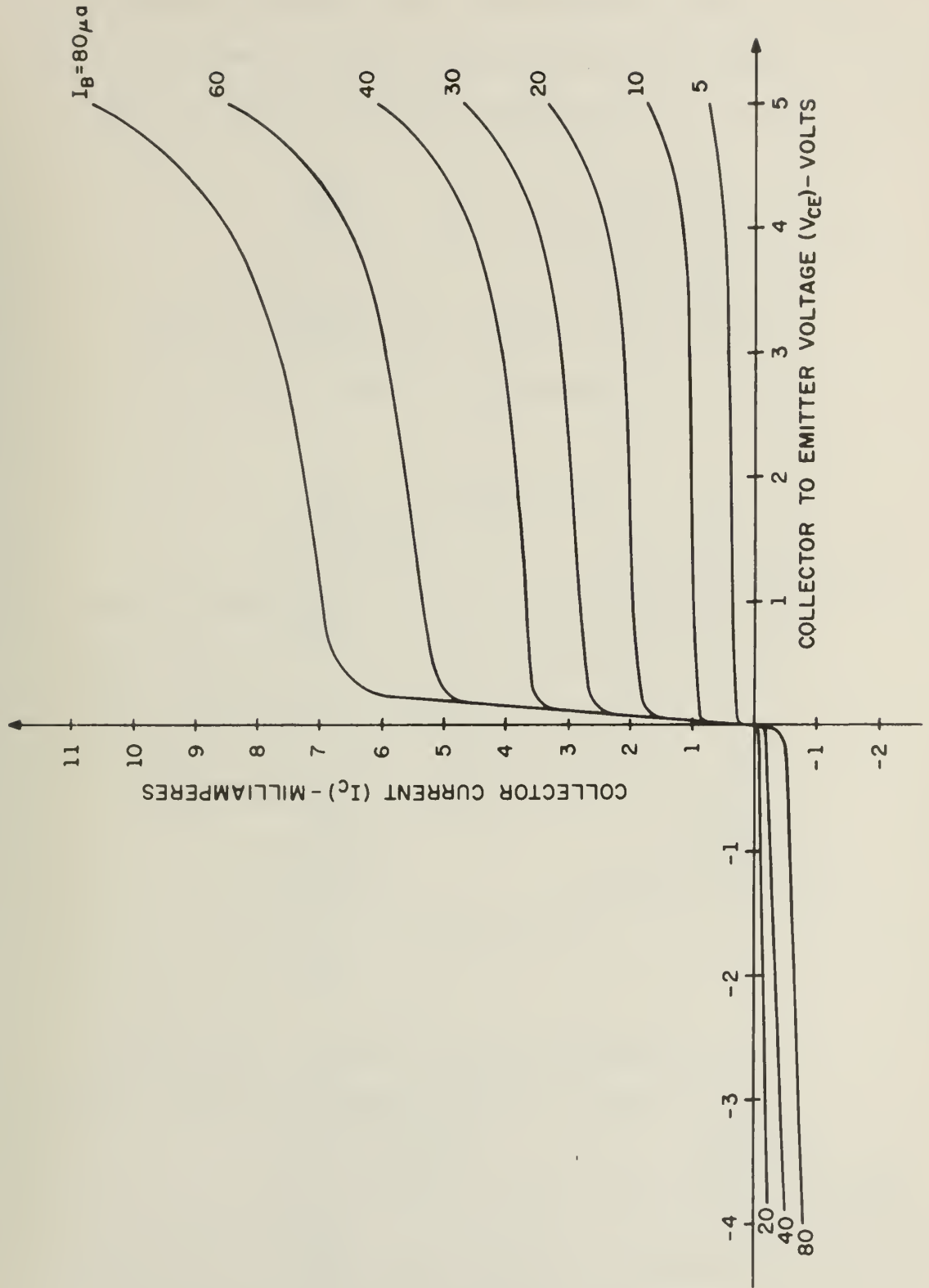


Figure 6. C1 Transistor Common Emitter Output Characteristic

V-I characteristics which have a linearly increasing positive slope of $1/R$ mhos and whose ordinate values at $V_{CE} = 0$ are unaltered as shown in Figure 7B. Thus:

$$i_C = i_1 + i_R$$

where i_R is the resistive current having a linear dependency upon the output voltage V_{CB} since

$$i_R = V_{CB}/R_C.$$

B) Inhibit the output current i_C by placing an ideal junction diode element in series with the input branch such that current i_E now flows through the ideal junction diode unidirectionally. The output current i_C becomes:

$$i_C = \partial * i_E + i_R$$

and the quasi-model has the voltage current characteristic of Figure 7C, where ∂ is the current gain of the model.

C) Shunt the terminals, across which the potential V_{CB} appears by placing the ideal junction element so

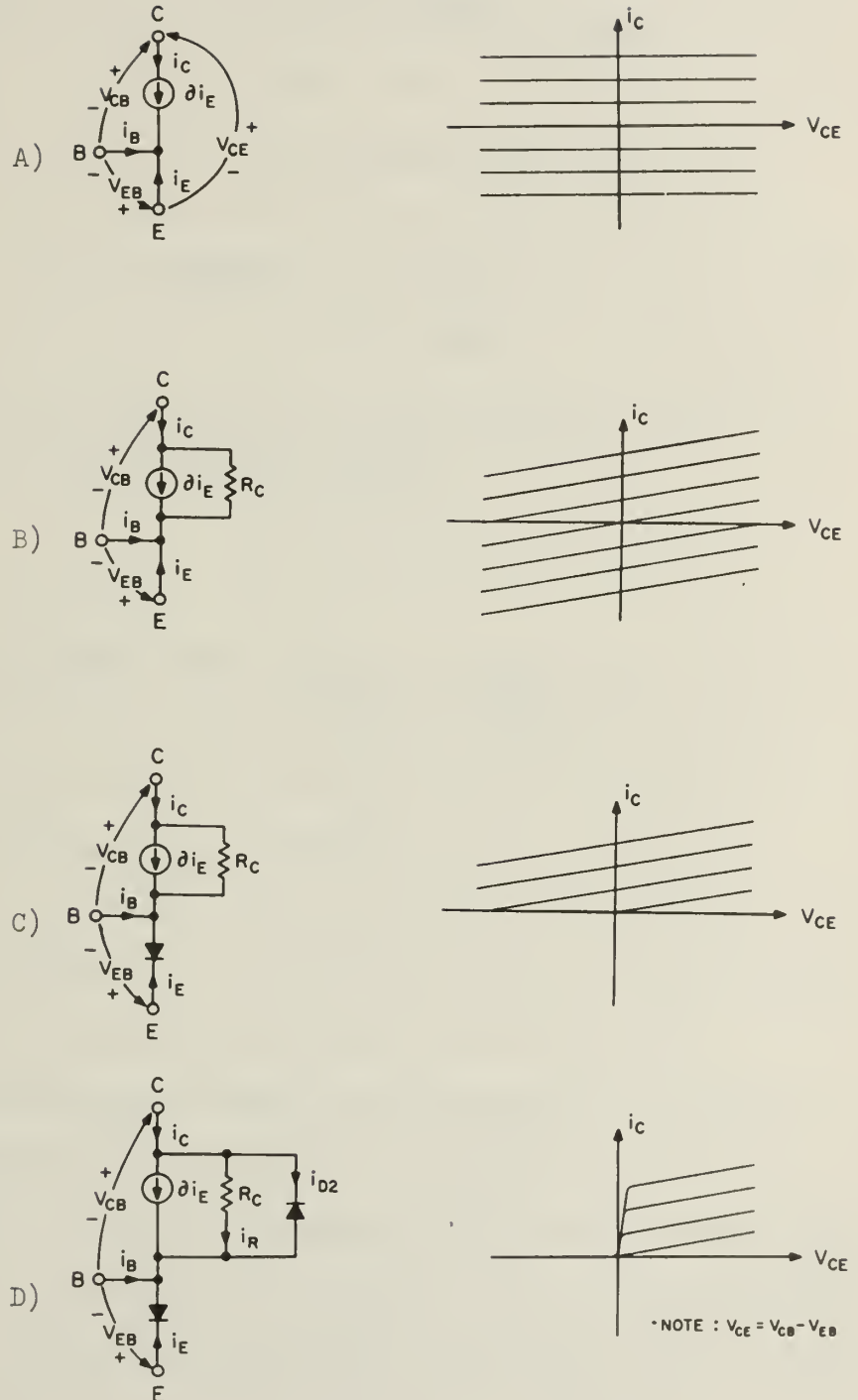


Figure 7. Step-wise Development of an NPN Common Emitter Transistor Model

as to inhibit V_{CB} from becoming negative. The output current is by KCL:

$$i_C = \alpha_F I_{O1} (e^{-qV_{EB}/Mkt} - 1) + V_{CB}/R_C - I_{O2} (e^{-qV_{EB}/Mkt} - 1)$$

while the input current is:

$$i_E = I_{O1} (e^{-qV_{EB}/Mkt} - 1).$$

By KCL and KVL these equations may be couched in normal common emitter variables; I_B instead of I_E and V_{CE} instead of V_{CB} with the result:

$$i_C = \frac{\alpha_F}{1-\alpha_F} I_B + \frac{I_{CO}}{1-\alpha_F} (e^{-q(V_{CE} - V_{BE})/Mkt} - 1)$$

$$i_B = -I_{ES} (1-\alpha_F) (e^{-qV_{BE}/Mkt} - 1) + I_{CS} (e^{-q(V_{CE} - V_{BE})/Mkt} - 1) - V_{CB}/R_C$$

which are the equations of the curves in Figure 7D.

These relations, according to Gibbons²¹, provide a representation of transistor output characteristics which is sufficiently accurate that it falls within the typical manufacturing spread for a given transistor type over most of the normal active region. Also, one finds

upon comparing the Ebers Moll Model equations²² with those of paragraph C above, that there is good agreement in the forward active region.

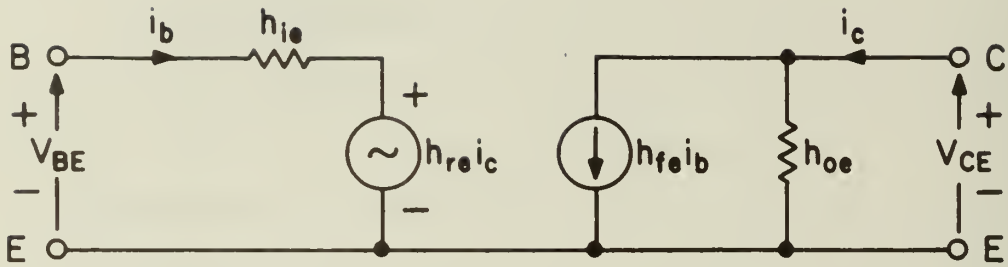
The above intuitively derived nonlinear model is easily extended to include inverse operation by adding an α_{RD2} generator, as suggested by the Ebers Moll Model, plus a shunting ideal resistor R_E to facilitate modeling of the reverse characteristic slope, of physical transistors, as shown in the third quadrant of Figure 6.

The quantities, I_{O1} , I_{O2} , α_F and R_C , in the above equations are variables and, therefore, need to be evaluated experimentally. Malmberg²³ states that evaluation of these variables requires one to make a substantial number of measurements.

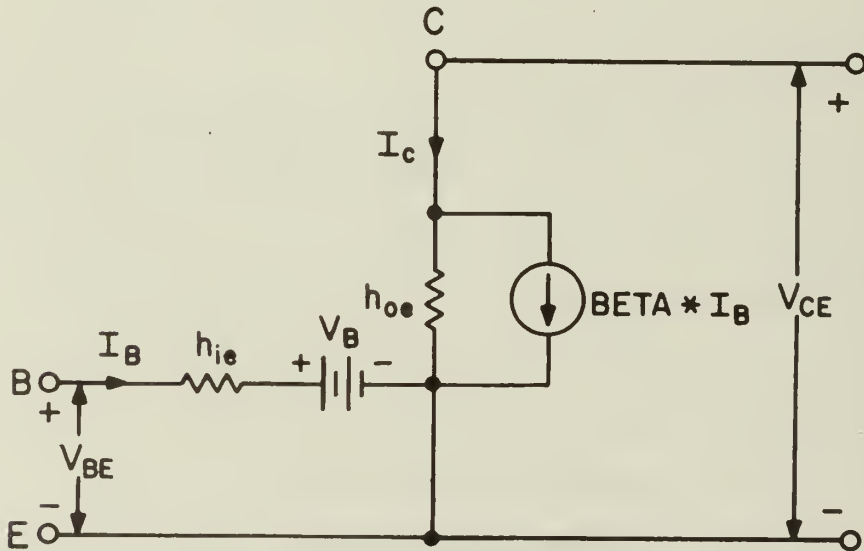
2.5 The Regression Model

The Regression Model combines the simplicity of the Hybrid parameter model with the nonlinear modeling flexibility of the nonlinear model utilizing the ideal junction diode as discussed in the previous section. No longer is one restricted to an incremental variation about the "static" or quiescent operating point as is true with the unmodified Hybrid parameter model of Figure 8. The operating range is extended by equations for BETA (I_C) and V_{BE} (I_C).

The first step in the modification process is to convert the Hybrid parameter model of Figure 6A to the ECAP direct current model of Figure 8. This is accomplished by substituting a battery V_B for the $h_{re} \cdot i_c$ voltage generator and substituting the direct current gain, BETA, for the small signal forward current gain, h_{fe} .



A. Hybrid Parameter Model

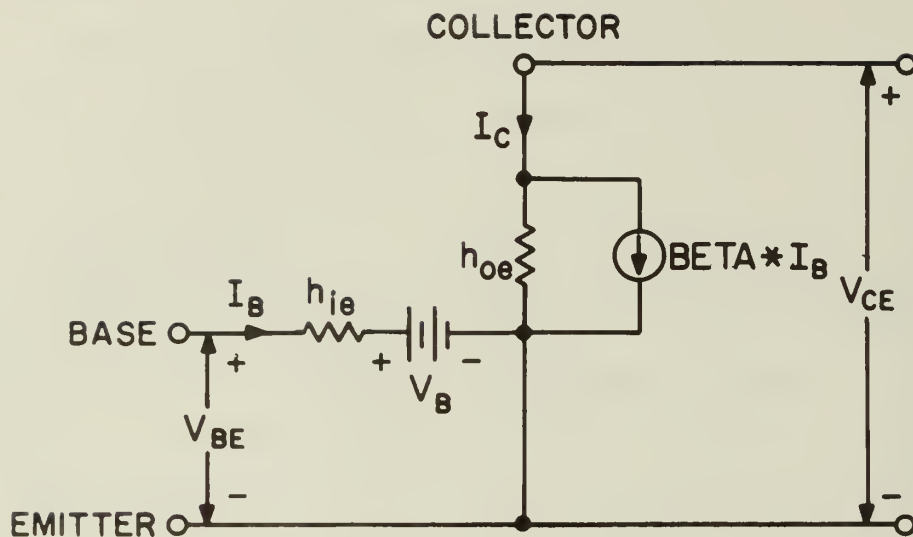


B. ECAP Direct Current Model

Figure 8. Comparison of Hybrid and ECAP Transistor Models

The final step involves the use of modeling equations developed by Guth²⁴ but in normalized form so that the natural logarithm is taken of a dimensionless quantity. These modeling equations control the base to emitter voltage drop V_{BE} and the current gain BETA of the ECAP model. The advantage of this approach is that the circuit analyst need not use the ideal junction diode as a modeling element. Instead of the exponential function and its attendant numerical evaluation problems when used in matrix equations, the user may attain the equivalent²⁵ circuit simulation range from curves derived from either measured or manufacturer's data points. The data points are fed into the Linear Regression curve fitting program of Appendix C for the purpose of generating in closed form, a mathematical equation which describes the actual variations in V_{BE} and BETA as a function of operating point (collector current, I_C) for each transistor used. In this manner the nonlinear voltage-current relations of any transistor may, in general, be established for any desired operating range below saturation.

Note that the nonlinear Regression Model of Figure 9 is an extension of Guth's model for the purpose of permitting simulation of transistor circuit operation in both the active and cutoff regions as is required, for example, for modeling nonsaturating Emitter Coupled Logic circuitry. The modification consisted of adding the program logic required to switch to a zero valued function of collector current, I_C , whenever the base current, I_B , decreased below a preselected reference level, I_0 , or reversed sign from the normal forward direction of positive amplification. Also, the base circuit is modified by setting



A) ECAP Direct Current Model

$$BETA = B_1 + B_2 \left(\ln \frac{I_C}{I_0} \right) + B_3 \left(\ln \frac{I_C}{I_0} \right)^2$$

$$V_{BE} = V_1 + V_2 \left(\ln \frac{I_C}{I_0} \right) + V_3 \left(\ln \frac{I_C}{I_0} \right)^2$$

B) Regression Equations

Figure 9. Regression Model With Equations

this circuit equal to a branch with $V_{BE} = V_\gamma$, where V_γ is the cutin voltage, in series with a resistance of five megohms, whenever $I_B \leq 0$.

Thus the solution set of the Regression Model is now restricted to positive values of BETA, I_C , and I_B , by the addition of a conceptual transistor base-emitter diode which behaves in the cutoff mode in a similar manner to the ideal junction diode of the Ideal Diode Model constructed in Section 2.4 above.

The application of this Regression Model requires the user to calculate BETA using the equation:

$$BETA = \frac{I_{C2} - I_{C1}}{I_{B2} - I_{B1}}$$

where BETA is defined as the spacing²⁶ between the common emitter output characteristic curves of the Ebers Moll Model operating in the normal active region. There is an implied extension of this definition of BETA required in the use of this model. For example, to extend the Regression Model's validity into the cutoff region, it was necessary to obtain BETA and V_{BE} data at low currents where the output characteristic curves are highly nonlinear. However, the Regression Model specifically allows BETA to be a variable whereas in the Ebers Moll Model BETA is defined as a constant. The use of the above equation is justified for currents which are near zero, since the collector current, I_C , approaches zero at a much greater rate than does the base

current, I_B . In the limit the above equation does not converge to zero as desired, but it is a simple matter to define BETA as being zero at $I_C = 0$ and $I_B = 0$, since this is consistent with all physical observations of BETA's behavior.

The base to emitter forward diode drop, V_{BE} , voltage data is obtained from the common emitter input characteristic curves. Thus, the user supplies as input to the Linear Regression program a table of I_C , BETA, and V_{BE} which contains sufficient data to completely define each transistor in the region to be modeled.

The accuracy with which the Regression Model, in conjunction with the ECAP program, will simulate circuit operation is directly affected by the "goodness of fit" of the regression equations to the experimental data. A plot of typical measured physical variations of V_{BE} and BETA as a function of the collector current, I_C , for the comparison with the Linear Regression prediction equations, is shown in Figures 10 and 11, respectively. The Linear Regression program of Appendix C was used to derive these equations. A convenient program to test the Regression Model's effectiveness is given in Appendix D.

In conclusion, this discussion of models has shown the relationship of the Regression Model to other types of transistor models currently in wide use. It is believed that this model will form the basis of a useful parameter variation simulation program.

TRANSISTOR TYPE C1
VCE = 2.0 VOLTS

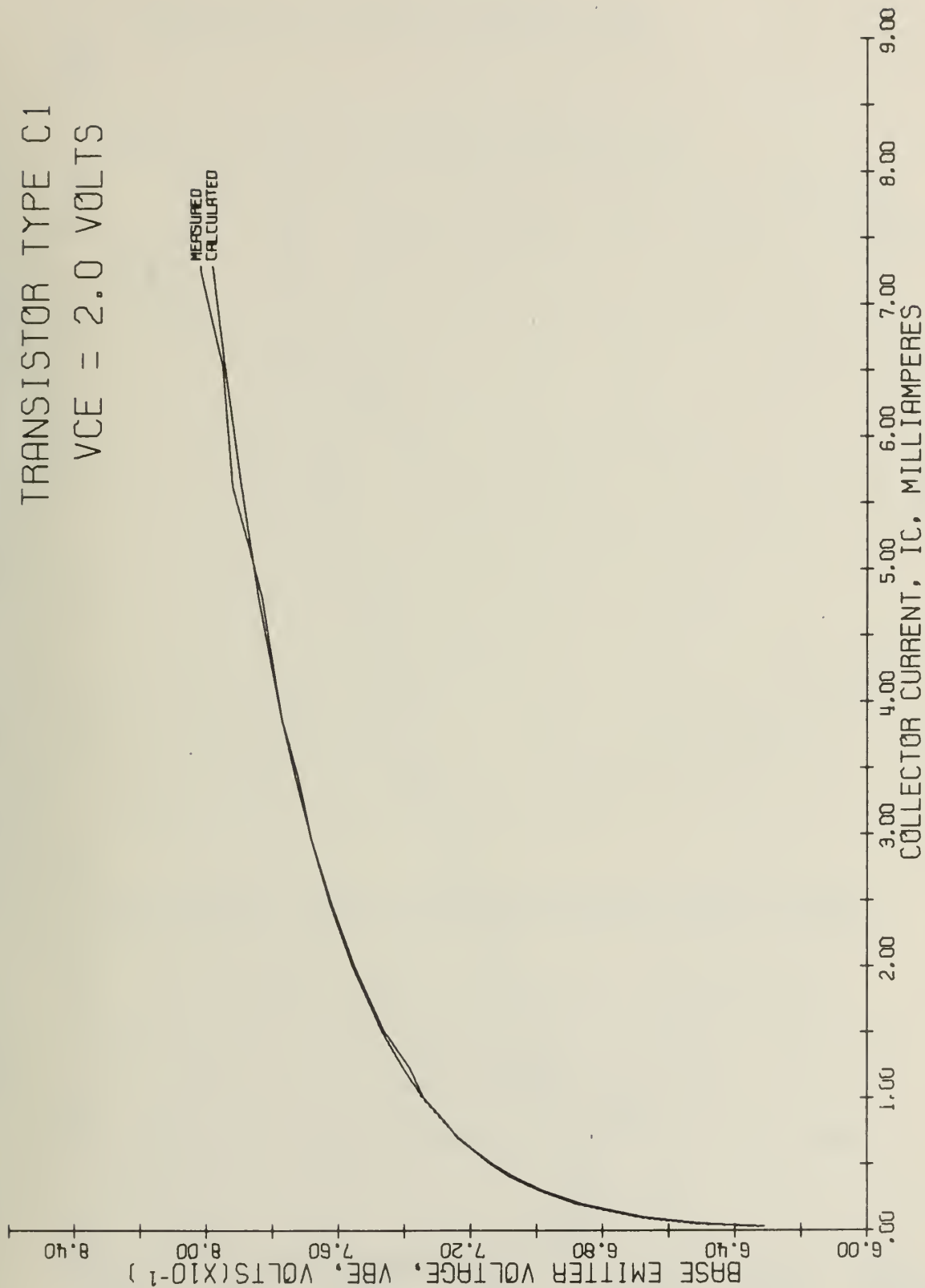


Figure 10. C1 Transistor Base to Emitter Voltage Versus Collector Current

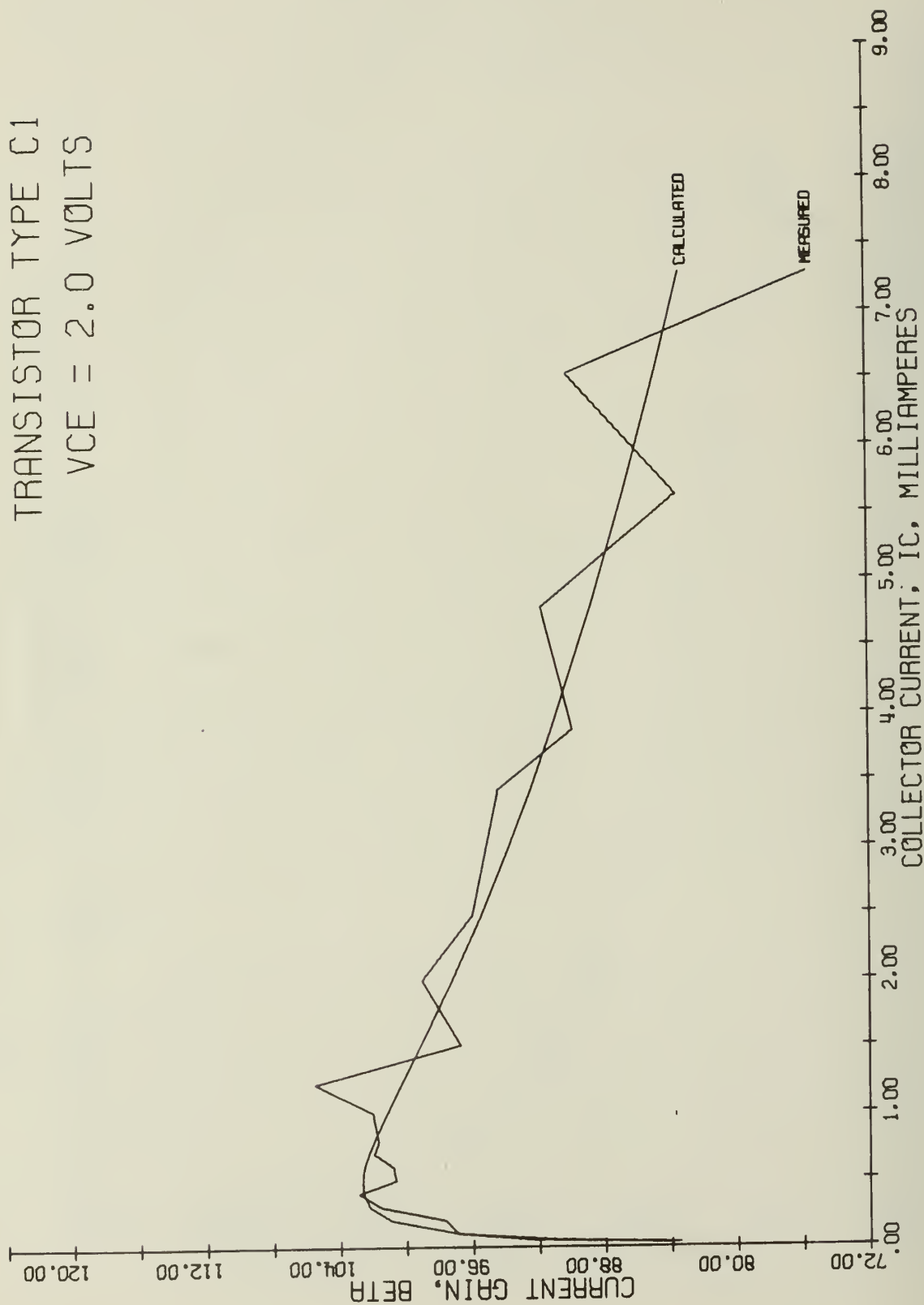


Figure 11. C1 Transistor Current Gain Versus Collector Current

3. COMPARISON OF TWO COMPUTER PROGRAM CIRCUIT ANALYSIS METHODS

3.1 Discussion of a Basic Circuit Analysis Problem

A problem often circumvented in the analysis of transistor circuits is the current convergence problem. This problem arises from the appearance of a dependent generator in the network model and the simultaneous need to satisfy the KCL and KVL equations. Specifically, whenever the circuit external to the circuit model has a direct influence upon the current gain, BETA, of one or more states, then the proper value of BETA must be determined prior to the completion of circuit solution. Two approaches for solving this problem are: the Matrix Partition Method and the Regression Model Method.

Both of the above methods utilize the matrix circuit analysis procedures as discussed by Seshu²⁷. For ease of notation interpretation it is suggested that one refer to the matrix analysis²⁸ of a simple circuit which is presented in Appendix A.

3.2 Solution of the Current Convergence Problem - Matrix Partition Method

The circuit of Figures 12A and 12B is a proportional controlled oven heater driving amplifier used for temperature stabilization of a crystal controlled computer timing oscillator. Using the methods of Appendix A, it is possible to solve for all branch and element currents.

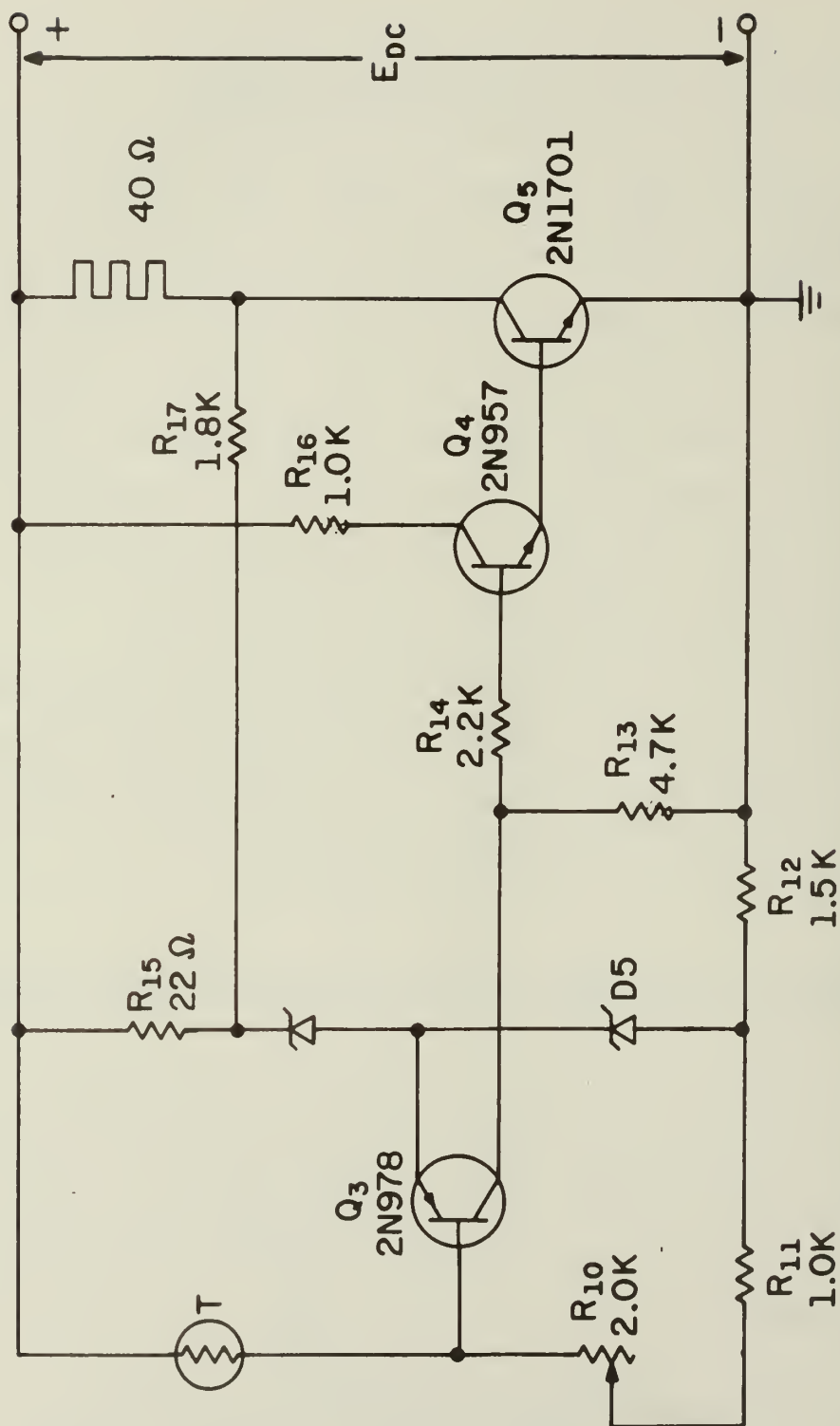


Figure 12A. Oven Heater Driving Amplifier Schematic Diagram

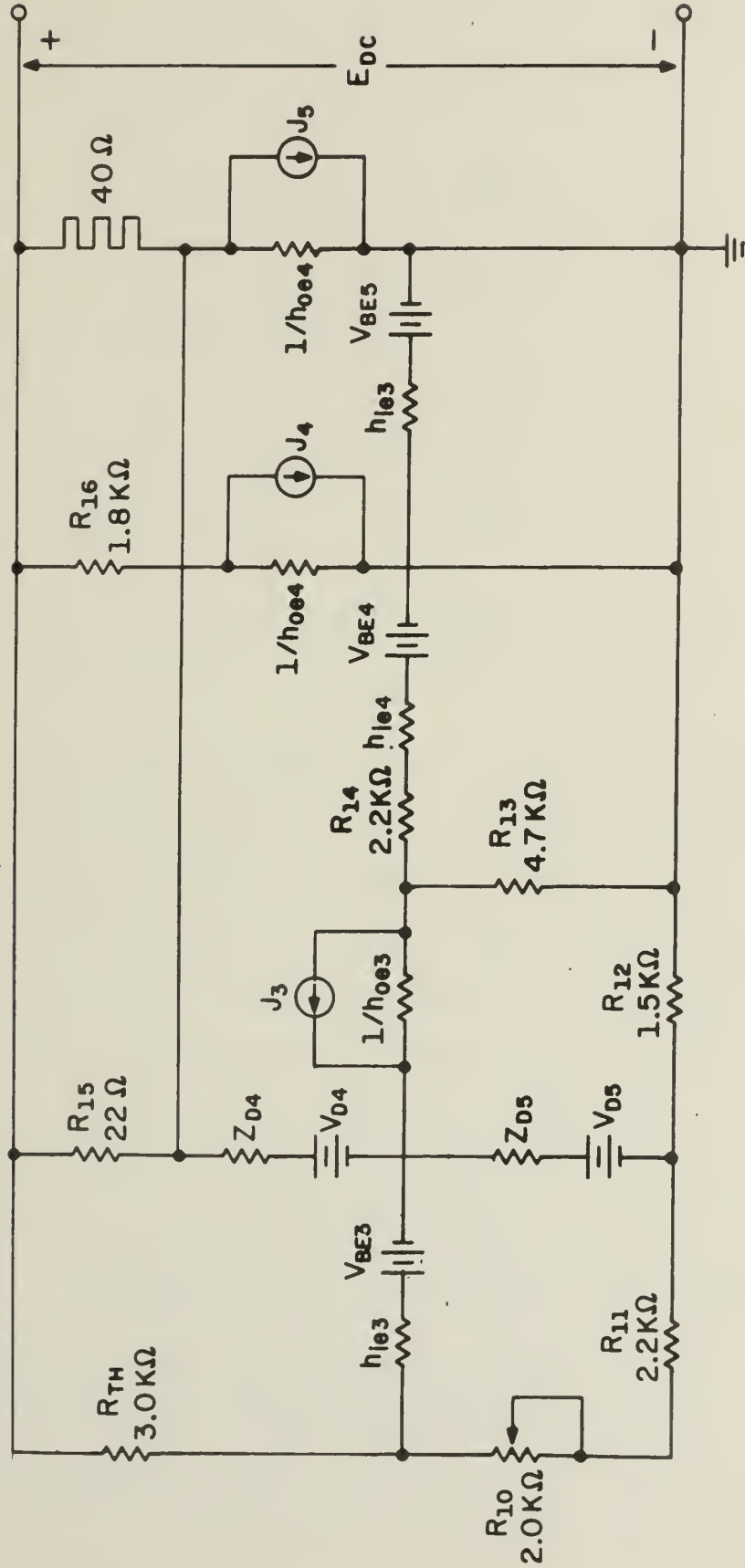


Figure 12B. Oven Heater Driving Amplifier Equivalent Circuit

The matrix equations are:

$$\begin{aligned}
 I_B &= I_M - JG \\
 &= A^T * I_M - JG \\
 &= A^T * Y_M * E_M - JG \\
 &= [A^T * Y_M * A] * E - JG \\
 &= [A^T * Y_M * A] * [E_B * E_N] - JG \\
 &= [A^T * Y_M * A] * E_B + [A^T * Y_M * A] * E_M - JG \\
 &= [A^T * Y_M * A] * E_B + [A^T * Y_M * A] * Z * JG - JG
 \end{aligned}$$

The dependent collector current generator matrix, JG , and the independent voltage source matrix, E_B , are shown in Figures 13 and 14, respectively. Note that the elements of the JG matrix are factored to show the dependent relationship between the elements of this matrix and the i_{Bj} elements of the I_B matrix for which the solution is being obtained. Therein is the current convergence problem, referred to above, in that certain of the unknown currents appear on both sides of the matrix equations. However, through the use of matrix partitioning, the dependent current values, I_{Bd} , may be obtained and the remaining independent current values, I_{Bi} , calculated. The procedure is:

$$\text{Let } J = Q * I_n \quad \text{where} \quad Q = [q_n]_{k \times l}$$

and q_n = current gain of the n^{th} transistor, $(\text{BETA})_n$.

$$J_D = \begin{bmatrix} 0 \\ h_{FE5} (-i_{B5}) \\ 0 \\ h_{FE4} (-i_{B4}) \\ 0 \\ h_{FE3} (-i_{B3}) \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ 0 \end{bmatrix} \text{ Amperes}$$

Figure 13. Dependent Current Generator Matrix

$$E_B = \begin{bmatrix} 0 \\ 0 \\ -V_{BE5} \\ 0 \\ -V_{BE4} \\ 0 \\ 0 \\ 0 \\ 0 \\ -V_{D5} \\ 0 \\ -V_{D4} \\ -V_{BE3} \\ 0 \\ 0 \\ 0 \\ 0 \\ E \end{bmatrix} \text{ Volts}$$

Figure 14. Independent Voltage Source Matrix

Thus given the A and Z matrices in Figures 15 and 16 one may solve for the branch current matrix, I_B , where:

$$I_B = [A^T * Y_M * A] * E_B + [A^T * Y_M * A] * Z * Q * I_{Bd} - Q * I_{Bd}.$$

By partitioning the I_B matrix into dependent and independent parts one obtains:

$$I_B = \begin{bmatrix} I_{Bd} \\ I_{Bi} \end{bmatrix} = Y * \begin{bmatrix} \Phi \\ E_B \end{bmatrix} + Y * \begin{bmatrix} Z * Q * I_{Bd} \\ \Phi \end{bmatrix} - \begin{bmatrix} Q * I_{Bd} \\ \Phi \end{bmatrix},$$

where Φ is an appropriately dimensioned null vector in each case.

Next the network admittance of Y matrix, where

$$Y = A^T * Y_M * A$$

may be partitioned into four parts:

$$Y_1, Y_2, Y_3, \text{ and } Y_4$$

having the respective dimensions of:

$$3 \times 3, \quad 3 \times 15, \quad 15 \times 3, \quad \text{and} \quad 15 \times 15$$

for the 18 branch equivalent circuit of Figure 12-B. The branch current matrix, upon partitioning the Y matrix, becomes:

$$I_B = \begin{bmatrix} I_{Bd} \\ I_{Bi} \end{bmatrix} = \begin{bmatrix} Y_1 & Y_2 \\ Y_3 & Y_4 \end{bmatrix} \begin{bmatrix} \Phi \\ E_B \end{bmatrix} + \begin{bmatrix} Y_1 & Y_2 \\ Y_3 & Y_4 \end{bmatrix} \begin{bmatrix} Z * Q * I_{Bd} \\ \Phi \end{bmatrix} - \begin{bmatrix} Q * I_{Bd} \\ \Phi \end{bmatrix}.$$

[illegible]

Figure 16. Impedance Matrix Element Values

From this latter equation one may obtain the relations for I_{Bd} and I_{Bi} .

$$I_{Bd} = Y_2 * E_B + Y_1 * [Z * Q * I_{Bd}] - Q * I_{Bd}$$

$$\text{or} \quad I_{Bd} = [U - Y_1 * Z * Q + Q]^{-1} * [Y_2 * E_B]$$

$$\text{and} \quad I_{Bi} = Y_4 * E_B + Y_3 * Z * Q * I_{Bd};$$

where U is the identity matrix having ones at each position along the major diagonal. Two points should be noted. First, it is necessary to develop a permutation matrix for transforming the original matrices into the desired partitive form and, second, the user must supply a value for current gain, BETA, of each transistor. From the numerical analysis viewpoint, there is no formal algorithm for deriving the permutation matrix; however, through the use of cyclical iterative analysis methods²⁹ the exact value of BETA for each transistor may be woven into the solution provided one has an equation relating the current gain, BETA, to the base of collector current of each transistor.

3.3 Solution of the Current Convergence Problem - Regression Model Method

In contrast to the solution of the previous section for the network branch currents, the Regression Model Method utilizes an existing computer circuit analysis program, ECAP³⁰, which first solves for the network node voltages, and second, solves for the resulting element voltages and currents.

Mathematically speaking both methods utilize the same matrix formulation in that the A matrix approach is used for converting the branch currents into a statement of the total currents entering each node as required by Kirchoff's Current Law (KCL).

The basic cyclical iterative analysis procedure developed by Guth³¹ in conjunction with the IBM 1620 version of ECAP was not changed upon coupling the modified iterative subroutine of Appendix B into the new IBM 360 version of ECAP³². As an aid to understanding mathematical processes used, the matrix equations for the test circuit of Figure 17 will be developed to show where Guth's cyclical iterative technique enters the circuit analysis computational process.

The matrix method of formulating circuit analysis uses a fundamental building block called the branch element. The ECAP³³ standard branch element is sketched in Figure 18. Note that this branch contains provisions for all possible driving functions as well as the corresponding response functions. The branch terminal voltage, V_B , is given by the matrix equation:

$$V_B = V_R - E$$

where V_R and E are the resistive element voltage and the voltage source column matrices, respectively.

The branch currents, I_B , flowing out of the branches, with the positive direction defined as being from the m^{th} node to the n^{th} node are given by the matrix equation:

$$I_B = I_R + J$$

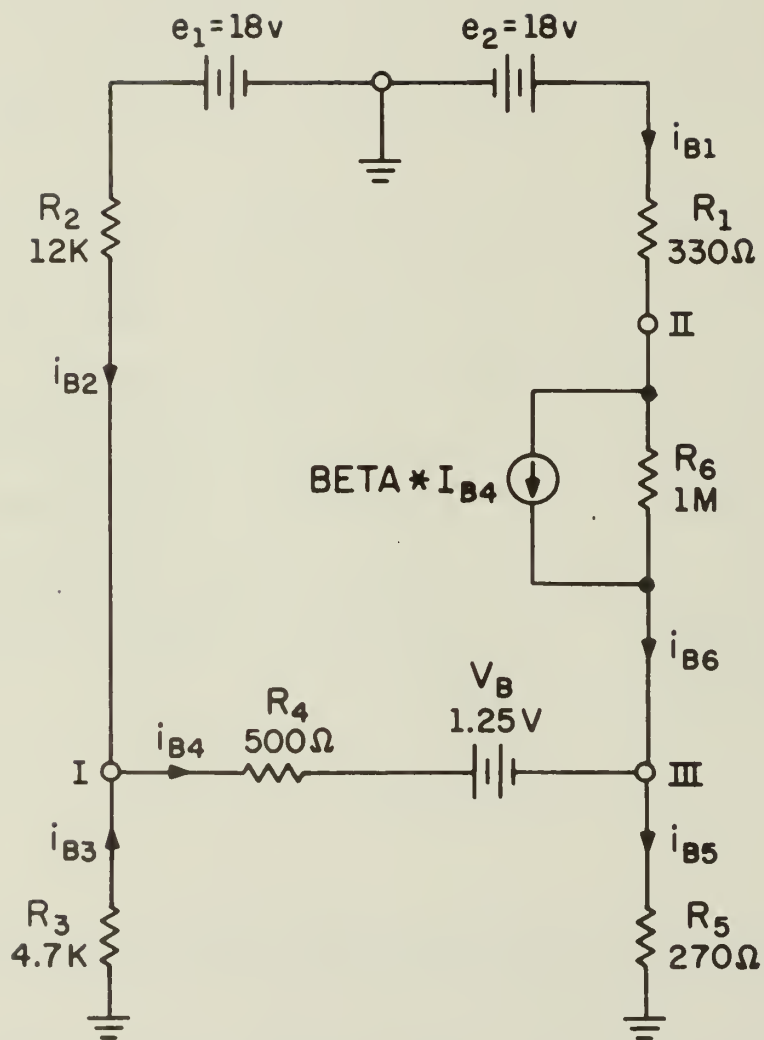


Figure 17. NLAP Common Emitter Test Circuit

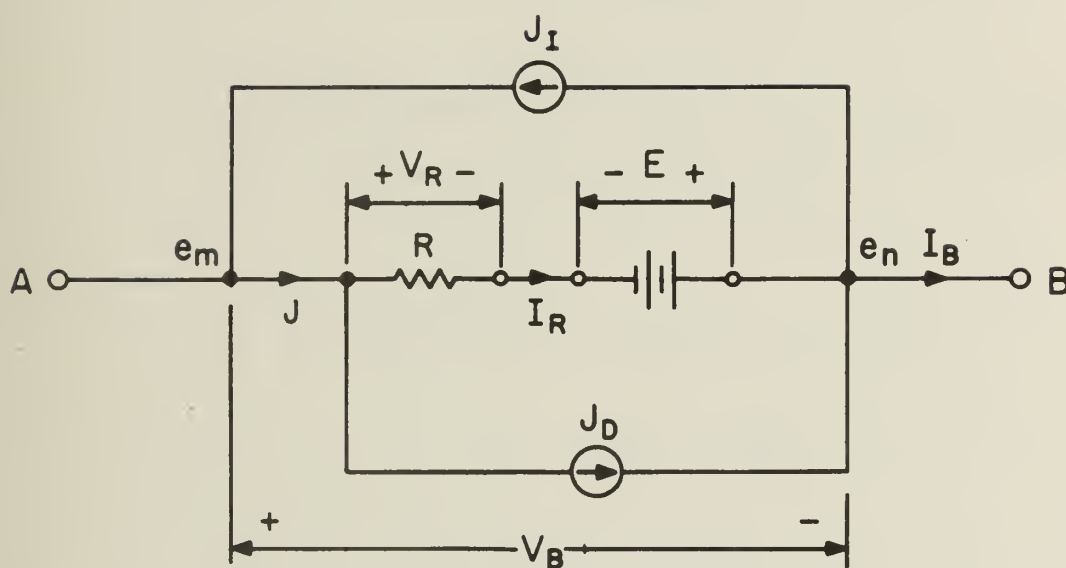


Figure 18. ECAP Standard Branch

where I_R is the current through the branch admittance element, Y_{ij} , of the circuit admittance matrix, Y , and J is the sum of the quantities J_D and J_I , which are the branch dependent and independent current generator matrices, respectively.

The network driving voltages, E , may be replaced, using Norton's Theorem, by the corresponding driving currents. Thus if E is the voltage source column matrix, the transformed source current is:

$$J' = Y * E$$

and the total driving current in the network becomes:

$$J_T = J_I + J_D + Y * E.$$

Kirchoff's Current Law in matrix form is:

$$I_N = A * I_B = 0$$

where now
$$I_B = I_R + J_T,$$

and thus, by expansion:

$$I_N = A * I_B = [A * I_R] + [A * J_T].$$

Consequently:
$$A * Y * V_R = [-A] * J_T.$$

From Kirchoff's Voltage Law in matrix form:

$$V_R = A^T * V_N.$$

Combining the two previous equations:

$$[A * Y * A^T] * V_N = [-A] * J_T;$$

and solving for the node voltage matrix, V_N :

$$\begin{aligned} V_N &= [A * Y * A^T]^{-1} * [-A] * [J_T] \\ &= [A * Y * A^T]^{-1} * [-A] * [J_I + J_D + Y * E]. \end{aligned}$$

Following through now with the illustrative example, we begin by writing the KCL equations for the circuit of Figure 17.

$$\begin{array}{cccccc} 0 & -i_2 & -i_3 & -i_4 & 0 & 0 & = & 0 \\ -i_1 & 0 & 0 & 0 & 0 & +i_6 & = & 0 \\ 0 & 0 & 0 & -i_4 & +i_5 & -i_6 & = & 0 \end{array}$$

These equations become in matrix notation $I_N = A * I_B$, or

$$I_N = \begin{bmatrix} I_{n1} \\ I_{n2} \\ I_{n3} \end{bmatrix} = \begin{bmatrix} 0 & -1 & -1 & +1 & 0 & 0 \\ -1 & 0 & 0 & 0 & 0 & +1 \\ 0 & 0 & 0 & -1 & +1 & -1 \end{bmatrix} * \begin{bmatrix} i_{B1} \\ i_{B2} \\ i_{B3} \\ i_{B4} \\ i_{B5} \\ i_{B6} \end{bmatrix}$$

The voltage and current source matrices are, respectively:

$$E = \begin{bmatrix} e_1 \\ e_2 \\ e_3 \\ e_4 \\ e_5 \\ e_6 \end{bmatrix} = \begin{bmatrix} 18.0 \\ 18.0 \\ 0 \\ V_B \\ 0 \\ 0 \end{bmatrix} = \begin{bmatrix} 18.0 \\ 18.0 \\ 0 \\ -1.25 \\ 0 \\ 0 \end{bmatrix}$$

and:

$$J_T = J_I + J_D + Y * E$$

$$J_T = \Phi + \begin{bmatrix} j_{D1} \\ j_{D2} \\ j_{D3} \\ j_{D4} \\ j_{D5} \\ j_{D6} \end{bmatrix} + [Y * E]$$

$$J_T = \Phi + \begin{bmatrix} 0 \\ 0 \\ 0 \\ 0 \\ 0 \\ \text{BETA} * i_{B4} \end{bmatrix} + [Y] * \begin{bmatrix} 18.0 \\ 18.0 \\ 0 \\ -1.25 \\ 0 \\ 0 \end{bmatrix}$$

Note that the voltage source matrix, E , clearly shows the role of V_{BE} and that the dependent current generator matrix, J_D , clearly shows the role of the transistor's current gain, $BETA$. These are the two quantities which are iteratively changed by the Regression Model. However, it is very difficult to solve the matrix equation,

$$V_N = [A*Y*A^T]^{-1} * [-A] * [J_I + J_D + Y*E],$$

when the dependent current $BETA*i_{B4}$ is not known. For this reason, it is necessary to modify the above equation slightly.

The requisite modification is obtained by writing the node equations for the circuit of Figure 17. Upon substituting the equivalent expression for i_{B4} in terms of V_1 , V_3 , V_B , and R_4 and collecting terms one obtains the matrix relation:

$$Y_N * V_N = J_T$$

where Y_N is the nodal conductance matrix³⁴ of Figure 19 and satisfies the equation:

$$Y_N = [A*Y*A^T]$$

which was discussed above. The corresponding nodal equivalent current vector is given in Figure 20. This current vector satisfies the relation:

$$J_T = J_I + J_D + Y*E$$

which was derived above.

$$Y_N = \begin{bmatrix} (1/4700 \, \Omega + 1/500 \, \Omega + 1/12000 \, \Omega) & 0.0 & -(1/500 \, \Omega) \\ (BETA/500 \, \Omega) & 1/330 \, \Omega + 1/10^7 \, \Omega & -(BETA/500 \, \Omega + 1/10^7 \, \Omega) \\ -(BETA/500 \, \Omega + 1/500 \, \Omega) & 0.0 & (BETA/500 \, \Omega + 1/500 \, \Omega + 1/270 \, \Omega + 1/10^7 \, \Omega) \end{bmatrix}$$

Figure 19. Nodal Conductance Matrix with BETA Explicitly Shown

$$J_T = \begin{bmatrix} 18/12000 \ \Omega & + & V_{BE}/500 \ \Omega \\ 18/330 \ \Omega & + & V_{BE}/500 \ \Omega \\ -V_{BE}/500 & - & V_{BE} * \text{BETA}/500 \ \Omega \end{bmatrix}$$

Figure 20. Nodal Equivalent Current Vector With BETA and V_{BE} Explicitly Shown

3.4 Cutoff Conditions and the Regression Model

The conditions which must be satisfied for each transistor in a network, which is in a nonconducting or cutoff state, are BETA equal to zero and a base to emitter voltage, V_{BE} , less than or equal to the cutin voltage³⁵, V_γ . The condition of BETA = 0 implies that the collector current, I_C , is zero, provided the collector leakage amount I_{CO} , is negligible, since at low values of I_C :

$$BETA \approx \frac{\text{Total } I_C}{\text{Total } I_B}$$

This further means that, when there is no significant base current flowing, V_{BE} is determined by the circuits external to each transistor.

From Figure 9, the Regression Model equations are:

$$BETA = B_1 + B_2 \left(\ln \frac{I_C}{I_0} \right) + B_3 \left(\ln \frac{I_C}{I_0} \right)^2$$

$$V_{BE} = V_1 + V_2 \left(\ln \frac{I_C}{I_0} \right) + V_3 \left(\ln \frac{I_C}{I_0} \right)^2$$

Since the ECAP model is a strictly linear network, the currents in the base, emitter and collector circuit branches may flow in either the conventional positive direction for an NPN transistor or in the opposite direction.

A transistor's current gain, BETA, may become zero in one of three ways. First, BETA may be made zero by using a logical operator statement, such as the FORTRAN IV code:

$$\text{IF } (I_C \leq \text{CUTOFF}) \text{ BETA} = 0.0$$

placed in Subroutine ITRATE after the BETA Regression Model equation has been evaluated. Second, it may become zero by carefully selecting the BETA regression equation which predicts a zero value for BETA at a suitably low value for the collector current, I_C . Third, a combination of the previous two methods may be used. The first method tends to generate discontinuities which make convergence difficult whenever CUTOFF is an arbitrarily selected current level. The second method gives a smooth curve down to very large negative values of BETA, as I_C becomes increasingly smaller. An example of this event is shown in Table 1. Note that in the BETA equation of Table 1, CUTOFF corresponds to a value of I_C somewhere between 1.0 and 12.0 microamperes and I_0 corresponds to 1.0 microampere. The third method involves a combination of the simplicity of the previous two, with CUTOFF chosen from the BETA equation and with the "IF statement" inhibiting negative values of BETA.

A transistor's base to emitter voltage, V_{BE} , is a function of I_C throughout the active region. The quality of fit for a typical Regression Model V_{BE} equation is shown in Table 2. Note that with the same value of CUTOFF used for calculating V_{BE} , one obtains a number close to V_γ . However, as the drive to any transistor falls below $V_{BE} = V_\gamma$, the voltage across its emitter to base terminals becomes a function of the external circuitry surrounding it. Thus at CUTOFF and below, a logical switch needs to be incorporated into Subroutine ITRATE; so that the V_{BE} may be a function of some external circuit current, I_α . A better external circuit dependent variable would be

BETA = -144.30034 + 76.79433 * LN (IC) + -5.76604 * (LN(IC)) **2					
VCE	IC	MEASURED BETA (--)	CALCULATED BETA (--)	BETA MEAS-CALC (--)	
VOLTS	(MICROAMPS)				
3.00	1.00000	0.0	-144.30034	144.30034	
3.00	12.00000	10.00000	10.92245	-0.92245	
3.00	24.70000	42.59999	42.66835	-0.06836	
3.00	38.29999	90.66699	59.02272	31.64427	
3.00	62.09999	95.20000	74.47285	20.72714	
3.00	112.29999	100.39999	89.73676	10.66324	
3.00	213.50000	101.20000	101.71530	-0.51530	
3.00	320.79980	107.29999	106.84273	0.45726	
3.00	428.29980	107.50000	109.32199	-1.82199	
3.00	535.29980	107.00000	110.57671	-3.57671	
3.00	642.39990	107.09999	111.17651	-4.07652	
3.00	748.79980	106.39999	111.38388	-4.98389	
3.00	854.79980	106.00000	111.34521	-5.34521	
3.00	1079.00000	112.09999	110.78613	1.31386	
3.00	1287.99878	104.50000	109.94238	-5.44238	
3.00	1589.00000	100.33400	108.47314	-8.13914	
3.00	2113.00000	104.79999	105.66577	-0.86578	
3.00	2620.00000	101.39999	102.92725	-1.52725	
3.00	3117.99878	99.59999	100.32104	-0.72105	
3.00	3608.00000	98.00000	97.86548	0.13452	
3.00	4094.99878	97.39999	95.53638	1.86362	
3.00	5054.99219	96.00000	91.25317	4.74683	
3.00	5929.99219	87.50000	87.66528	-0.16528	
3.00	6864.99219	93.50000	84.11670	9.38330	
3.00	7666.99219	80.20000	81.27490	-1.07491	

Table 1. Analysis of Regression Equation for BETA, $C_1 V_{CE} = 3.0 V_{DC}$

VBE = 0.49696 + 0.03842 * LN (IC) " -0.00058 * (LN(IC)) **2					
VCE	IC	MEASURED	CALCULATED	VBE	VBE
VOLTS	(MICROAMPS)	VBE	VBE	(--)	MEAS-CALC
		(--)			(--)
3.00	1.00000	0.60300	0.49696	0.10604	
3.00	12.00000	0.60300	0.58885	0.01415	
3.00	24.70000	0.60300	0.61420	-0.01120	
3.00	38.29999	0.63200	0.62931	0.00269	
3.00	62.09999	0.65200	0.64570	0.00630	
3.00	112.29999	0.67200	0.66542	0.00658	
3.00	213.50000	0.69100	0.68635	0.00465	
3.00	320.79980	0.70300	0.69936	0.00364	
3.00	428.29980	0.71000	0.70848	0.00152	
3.00	535.29980	0.71600	0.71545	0.00055	
3.00	642.39990	0.72000	0.72111	-0.00111	
3.00	748.79980	0.72400	0.72584	-0.00184	
3.00	854.79980	0.72800	0.72990	-0.00190	
3.00	1079.00000	0.73400	0.73699	-0.00299	
3.00	1287.99878	0.73700	0.74234	-0.00534	
3.00	1589.00000	0.74600	0.74864	-0.00264	
3.00	2113.00000	0.75500	0.75710	-0.00210	
3.00	2620.00000	0.76200	0.76343	-0.00143	
3.00	3117.99878	0.76700	0.76851	-0.00151	
3.00	3608.00000	0.77200	0.77274	-0.00074	
3.00	4094.99878	0.77600	0.77639	-0.00039	
3.00	5054.99219	0.78200	0.78243	-0.00043	
3.00	5929.99219	0.79000	0.78697	0.00303	
3.00	6864.99219	0.79400	0.79110	0.00290	
3.00	7666.99219	0.80000	0.79421	0.00579	

Table 2. Analysis of Regression Equation for V_{BE} , C_1 $V_{CE} = 3.0 V_{DC}$

a voltage, but this leads to the matrix solution problem similar to that discussed in Section 3.2, where now node voltage is the independent variable. Note that both Table 1 and Table 2 were calculated using the Regression Model Evaluation Program listed in Appendix D.

3.5 Extension of the Regression Model

Two approaches requiring only minor Regression Model modification were explored. First, V_{BE} was set equal to the cutin voltage with the result that satisfactory predictions of network behavior can be made for operating conditions close to cutoff. Obvious inaccuracies are introduced as each transistor's operating point passed well into the cutoff state. The second approach consisted of adding a large impedance, Z_{OFF} , in series with the base circuit of the transistor for the purpose of simulating ideal diode behavior. The Z_{OFF} impedance of 5,555,555.0 was switched into the circuit by a logical operation statement in Subroutine ITRATE whenever the I_C current became less than I_0 . This latter approach was tested using the circuit of Figure 1-B with the result that current convergence was not obtainable.

A check was made of the effects of setting BETA equal to zero and V_{BE} equal to V_γ , by examining the matrices used in the matrix equation:

$$Y_N * V_N = J_T.$$

The solution to this set of simultaneous equations will exist provided the Y_N matrix has an inverse. By inspection of Figure 19, it is apparent that this will always be the case provided the admittances are real and positive; since BETA appears only in nonmajor diagonal terms. The possible range of variations in V_{BE} also will not affect the existence of Y_N inverse since V_{BE} only appears in the J_T matrix of Figure 20. This means a solution for V_N will exist even if J_T is a zero vector.

3.6 Conclusion

Summarizing briefly, the computer program NLAP solves for the linear current in each of the branches. The resulting collector current is then used as the dependent variable in the Regression Model equations of Figure 9 by Subroutine ITRATE. The iterative process is started in accordance with Guth's flow chart³⁶ of Figure 21 until convergence. Then the proper values of BETA and V_{BE} are obtained as a function of the collector current in the active region. The calculations made by the program may be checked both before iteration starts and after convergence is obtained by using the PRINT MI input code described in 4.3. A set of matrices obtained in this are shown in Figures 22 and 23, respectively.

One interesting example of the accuracy of NLAP is a DC option analysis of the linear test circuit of Figure 17. The NLAP computed results are compared with manually calculated results, for the nodal conductance matrix, in Figure 24, and for the equivalent current vector matrix in Figure 25. The results compare closely out to the sixth decimal place.

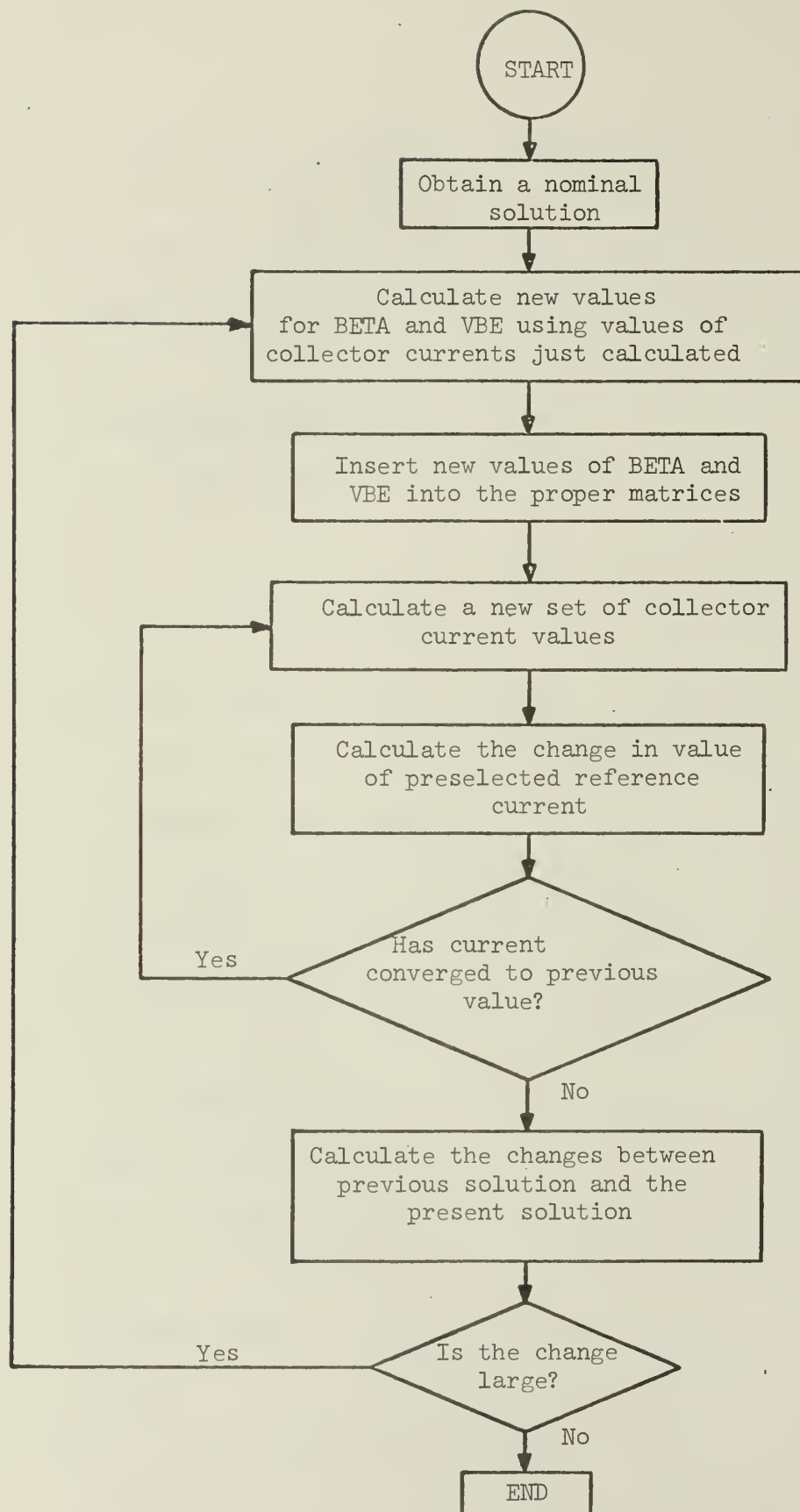


Figure 21. Flow Chart of Iterative Regression Model Solution Method.

NODAL CONDUCTANCE MATRIX

ROW COLS

1	1	-	4	0.238679200-01	-0.49999990D-02	0.0	0.0
1	5	-	5	0.0			
2	1	-	4	-0.50499988D	00	0.10050732D	03-0.13333332D-03-0.21758056D-02
2	5	-	5	-0.10000002D	03		
3	1	-	4	0.49999988D	00-0.50013321D	00	0.10000015D
3	5	-	5	0.0			
4	1	-	4	0.0		-0.21758056D-02	0.0
4	5	-	5	0.0			0.10000219D
5	1	-	4	0.0		-0.10000002D	03
5	5	-	5	0.10000003D	03	0.0	

EQUIVALENT CURRENT VECTOR

NODE NO.

CURRENT

1	0.22717916D-01
2	-0.38884987D
3	0.11538497D
4	-0.29000000D
5	0.0

NODAL IMPEDANCE MATRIX

ROW COLS

1	1	-	4	0.52935884D	02	0.52172248D	00	0.69562887D-06	0.11351418D-04
1	5	-	5	0.52172243D	00				
2	1	-	4	0.52693899D	02	0.24904866D	01	0.33206435D-05	0.54186960D-04
2	5	-	5	0.24904864D	01				
3	1	-	4	-0.11396619D-02	0.98471243D-02	0.99999983D-02	0.21424959D-06		
3	5	-	5	0.98471233D-02					
4	1	-	4	0.11464917D-02	0.54186960D-04	0.72249166D-10	0.99997821D-02		
4	5	-	5	0.54186955D-04					
5	1	-	4	0.52693894D	02	0.24904864D	01	0.33206432D-05	0.54186955D-04
5	5	-	5	0.25004861D	01				

Figure 22. DC Solution Matrix Obtained Prior to Iteration

NODAL CONDUCTANCE MATRIX

ROW COLS

1	1 - 4	0.23867920D-01-0.49999990D-02	0.0	0.0
1	5 - 5	0.0		
2	1 - 4	-0.49911976D 00 0.10050144D 03-0.13333332D-03-0.21758056D-02		
2	5 - 5	-0.10000002D 03		
3	1 - 4	0.49411976D 00-0.49425310D 00 0.10000015D 03	0.0	
3	5 - 5	0.0		
4	1 - 4	0.0	-0.21758056D-02	0.0
4	5 - 5	0.0		0.10000219D 03
5	1 - 4	0.0	-0.10000002D 03	0.0
5	5 - 5	0.10000003D 03		

EQUIVALENT CURRENT VECTOR

NODE NO.

CURRENT

1	0.22654877D-01
2	-0.37802932D 00
3	0.11537421D 03
4	-0.29000000D 03
5	0.0

NODAL IMPEDANCE MATRIX

ROW COLS

1	1 - 4	0.52935133D 02 0.52783296D 00 0.70377616D-06 0.11484368D-04
1	5 - 5	0.52783291D 00
2	1 - 4	0.52690314D 02 0.25196555D 01 0.33595354D-05 0.54821605D-04
2	5 - 5	0.25196553D 01
3	1 - 4	-0.11394418D-02 0.98453338D-02 0.99999983D-02 0.21421063D-06
3	5 - 5	0.98453328D-02
4	1 - 4	0.11464137D-02 0.54821605D-04 0.73095358D-10 0.99997821D-02
4	5 - 5	0.54821600D-04
5	1 - 4	0.52690309D 02 0.25196553D 01 0.33595350D-05 0.54821600D-04
5	5 - 5	0.25296550D 01

Figure 23. NL Solution Matrix Obtained After Completion of Iteration

$$Y_N = \begin{bmatrix} +0.00229606 & +0.00000000 & -0.00200000 \\ +0.10000000 & +0.00303040 & -0.10000000 \\ -0.10200000 & +0.00000000 & +0.10570380 \end{bmatrix}$$

a) Manual Calculations

$$Y_N = \begin{bmatrix} +0.22960991D-02 & 0.00000000D+00 & -0.19999999D-02 \\ +0.99999964D-01 & 0.30304029D-02 & -0.10000000D+00 \\ -0.10199996D+00 & -0.99999966D-07 & +0.10570377D+00 \end{bmatrix}$$

b) NLAP Calculations

Figure 24. Nodal Conductance Matrix Calculations for BETA = 50

$$J_T = \begin{bmatrix} +0.00400000 \\ +0.17954545 \\ -0.12750000 \end{bmatrix}$$

a) Manual Calculations

$$J_T = \begin{bmatrix} +0.39999976D-02 \\ +0.17954527D+00 \\ -0.12749982D+00 \end{bmatrix}$$

b) NLAP Calculations

Figure 25. Nodal Current Vector Calculations
for BETA = 50 and $V_{BE} = -1.25$ Volts

A second example of the accuracy of NLAP is a NL option analysis, the output of which is compared with laboratory measured performance in the graph of Figure 26 for the emitter follower of Figure 27.

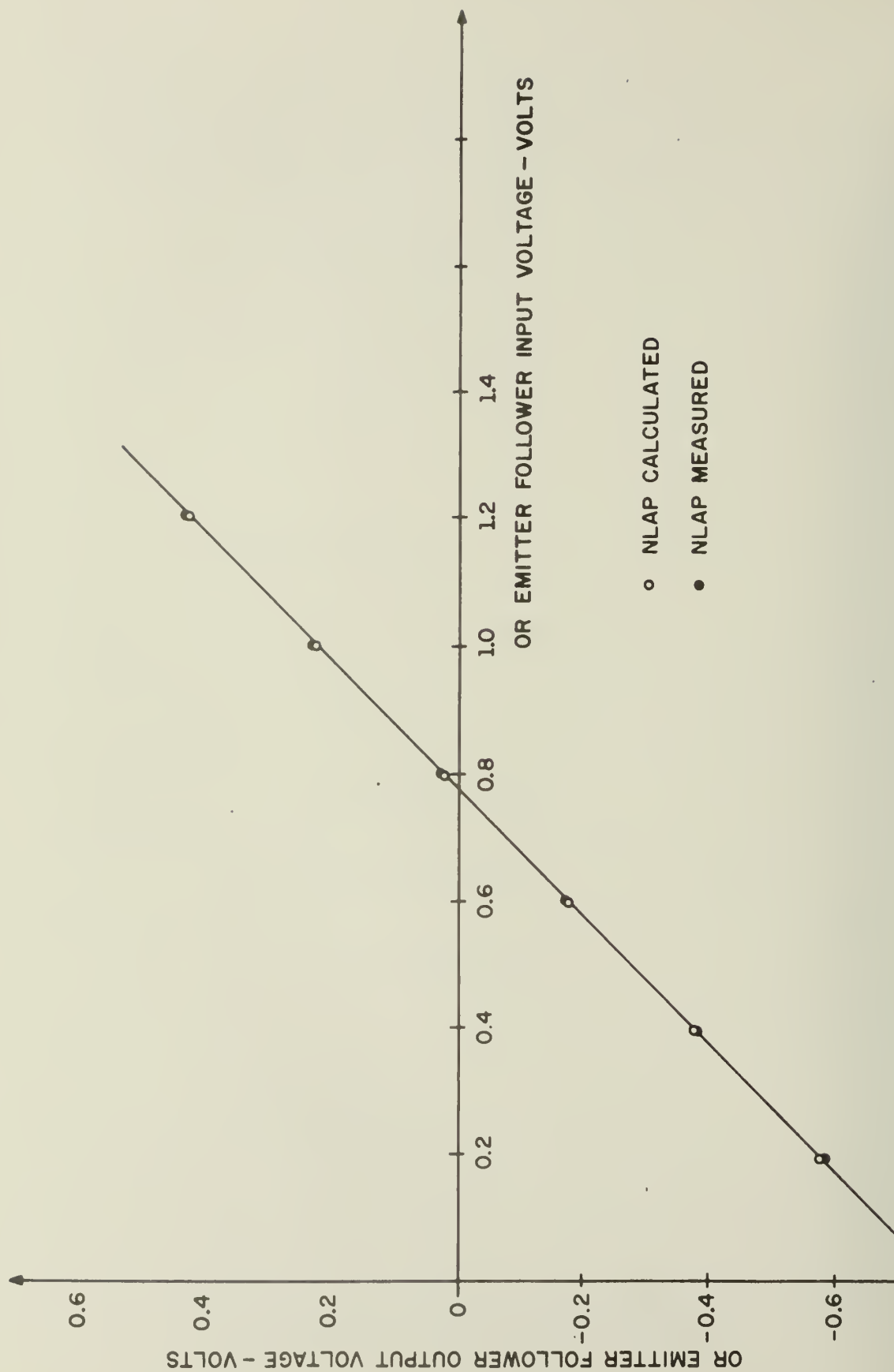


Figure 26. OR Emitter Follower Voltage Offset Characteristic

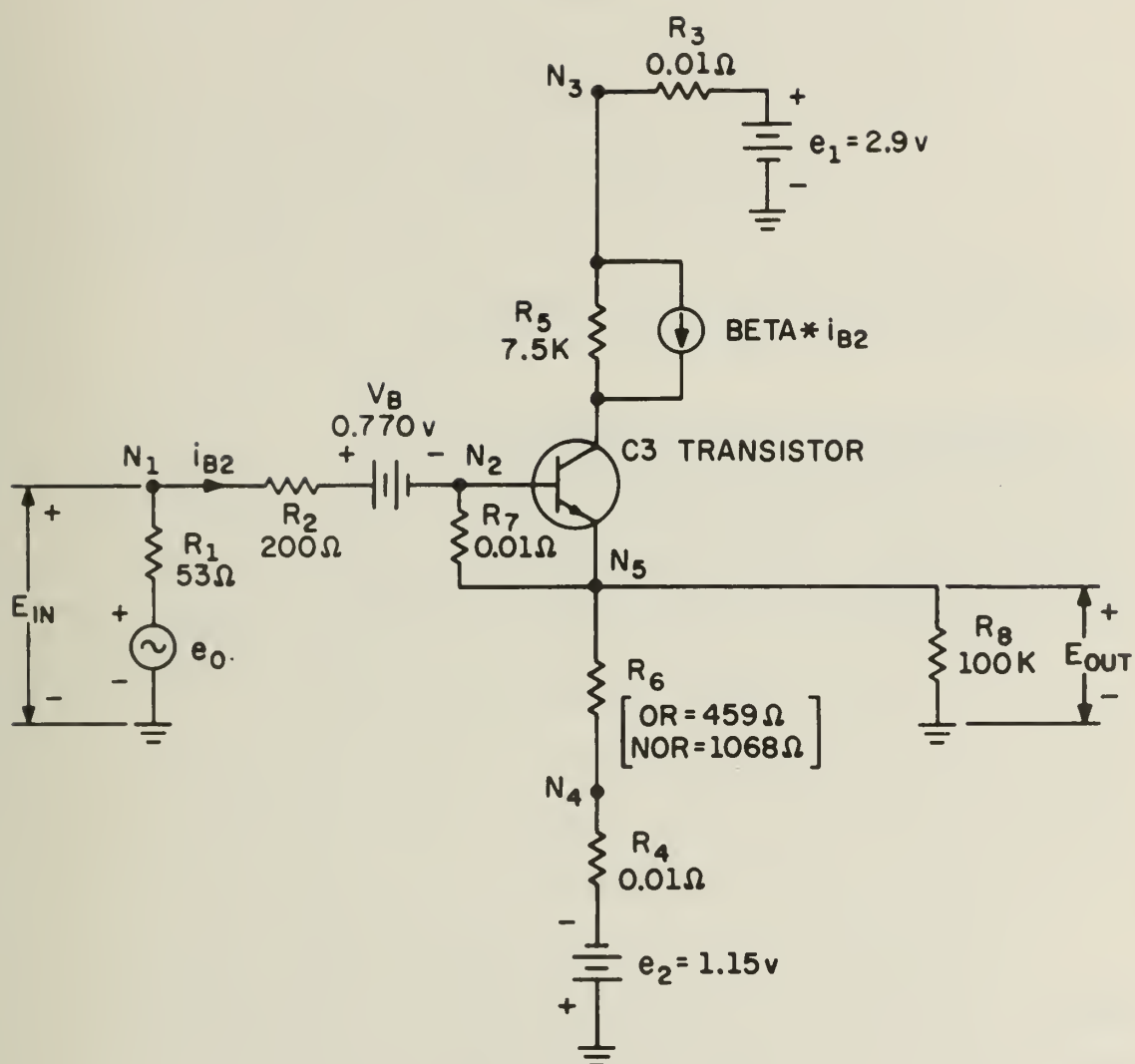


Figure 27. OR Emitter Follower Schematic Diagram

4. APPLICATION OF NLAP TO LOGIC CIRCUIT ANALYSIS

4.1 Introduction

NLAP is intended to be used for analyzing nonsaturating logic circuitry such as emitter coupled logic blocks. The capability now exists within the program for linear region parameter variation analysis. Should the user desire to perform special calculations, a subroutine may be coded and called just prior to the return of control to the main program by Subroutine ITRATE. The NLAP calling procedure and its associated system procedure is given in Figure 28.

4.2 Preparation of NLAP Input Data Deck

The input language to NLAP is similar to ECAP's³⁶ and is aligned closely with the language of the electronic engineer. Each of the circuit elements use a simple descriptive letter coding and the topology of the circuit interconnections is identified by a sequence of branch and node numbers. The polarity of positive current flow is inserted by ordering the nodal connection using identifying numbers in a from node m to node n arrangement.

The general branch, or B_j , statement consists of a branch number, j ; the from and to node numbers, m and n , respectively; the branch resistance, R , in ohms; the independent voltage source E , in volts; and the independent current source I , in amperes. In other words, the general branch statement is:

$$B_j = N(m,n), R = \gamma, E = e, I = i$$

```

/*FORMAT PR,DDNAME=FT10F001,COPIES=1

//JOB LIB DD DSNAME=SYS1.CKTLIB,DISP=(OLD,PASS)
// EXEC NLAP
//NLAP EXEC PGM=NLAP
//
// *
// * EXECUTE NLAP -- JOB LIB CARD REQUIRED
// * //JOB LIB DD DSNAME=SYS1.CKTLIB,DISP=(OLD,PASS)
// *
//FT05F001 DD DDNAME=SYSIN
//FT06F001 DD SYSOUT=A,DCB=( RECFM=FBA,LRECL=133,BLKSIZE=798)
//FT07F001 DD UNIT=( CTC,,DEFER),DCB=( RECFM=F,LRECL=80,BLKSIZE=80)
//FT08F001 DD UNIT=( CTC,,DEFER),DCB=( RECFM=F,LRECL=80,BLKSIZE=80)
//FT09F001 DD UNIT=( CTC,,DEFER)=DCB=( RECFM=F,LRECL=80,BLKSIZE=80)
//FT10F001 DD UNIT=( CTC,,DEFER),DCB=( RECFM=F,LRECL=80,BLKSIZE=80)
//FT11F001 DD UNIT=( CTC,,DEFER),DCB=( RECFM=F,LRECL=80,BLKSIZE=80)
//FT12F001 DD UNIT=( CTC,,DEFER),DCB=( RECFM=F,LRECL=80,BLKSIZE=80)
//NLAP.SYSIN DD *
                * NLAP DATA DECK GOES HERE

/*

```

Figure 28. NLAP Calling Sequence

where j , m , n , γ , e and i are place holders for specific numeric values which vary from branch to branch. An example of the specific coding for the circuit of Figure 27 is listed in Figure 29.

The dependent current sources are denoted by a T_k statement containing the controlling and the controlled branch identification numbers, wotether with the associated current gain value, BETA.

The regression equation coefficients for the BETA and V_{BE} equations are entered in T_k and B_j statements, respectively, which are of the form:

$$T_k \quad \text{BETA}(i) = B_1, B_2, B_3$$

$$B_j \quad E(i) = V_1, V_2, V_3$$

where T_k and B_j start in card column one with the BETA (β) and the $E(\beta)$ dependent variable statements starting column seven.

The cyclical iteration process is controlled by two successive statements

$$\text{CURRENT} = \gamma$$

and

$$\text{TOLERANCE} = \delta$$

which imply that the iteration process is to terminate whenever the newest solution for the current in branch γ changes by less than the prespecified amount, δ , from the previous iterations calculated value.

```

ID21  OR  EMITTER FOLLOWER, RE = 459.6 OHMS  -DCAP
      DC
B1    N(0,1),R=53          ,E=1.0
B2    N(1,2),R=200.0,E=-0.770
B3    N(0,3),R=0.01,E=+1.15
B4    N(4,0),R=0.01,E=+2.90
B5    N(3,2),R=7500
B6    N(5,4),R=459.6
B7    N(2,5),R=0.01
B8    N(5,0),R=100000
T1    B(2,5),BETA=100
      PRINT NV,BV,BA,BP,MI
      EX
      END

```

A. DC Circuit Analysis Data Deck

```

ID21  OR  EMITTER FOLLOWER, RE = 459.6 OHMS  -NLAP DATA
      NL
B1    N(0,1),R=53          ,E=+1.0
B2    N(1,2),R=200.0,E=-0.770
B3    N(0,3),R=0.01,E=+1.15
B4    N(4,0),R=0.01,E=+2.90
B5    N(3,2),R=7500
B6    N(2,4),R=459.6
B7    N(2,5),R=0.01
B8    N(5,0),R=100000
T1    B(2,5),BETA=100
      PRINT NV,MI
      EX
T1    BETA(5)=-554.67056,+172.42553,-11.1718
B2    E(5)=-0.54023,-0.02429,-0.00021
      CURRENT = 6
      TOLERANCE = 0.01
      EX
      RETURN
      END

```

B. NL Circuit Analysis Data Deck

Figure 29. Typical NLAP Input Data

The amount of tolerable deviation from current convergence is stated in a decimal, not percent, format. One example is:

$$\text{TOLERANCE} = 0.01$$

which means current convergence to within one percent.

4.3 Solution Control Codes

Two types of analyses are possible using NLAP, linear direct current and iterative nonlinear direct current. The solution control cards are DC and NL, respectively.

A DC problem deck must contain only those cards up to the first EX or EXECUTE card as shown in Figure 29-A. The full set of ECAP/360 DC solution options³⁷ SE, WO, ST, and MI are available to the DC user. These options³⁸ obtain for the user: element sensitivities, worst case tolerance analysis, standard deviations of the node voltages assuming component values which are statistically independent, random, and normally distributed about their mean values, and a set of solution matrices, respectively.

An NL problem deck must contain the same network description cards as the equivalent DC problem deck, plus the regression equation cards for BETA and V_{BE} and the CURRENT, TOLERANCE, EXECUTE, RETURN and END cards as shown in Figure 29-B. These last three cards are self descriptive and the user should observe that the END card is used to signal the end of the input data so that control may be passed to the system monitor.

It should be noted that the only case where the PR or print card is essential is when the user desires to print out the nodal

conductance matrix, the equivalent current vector, and the nodal impedance matrix. To obtain these matrices the required code is:

```
PRINT NV, MI
```

This coding was used to obtain the matrices shown in Figures 22 and 23.

4.4 Solution Output and Identification

When the user desires to perform a parameter variation analysis, careful attention should be given to the preparation of the title card which is placed at the beginning of each problem deck for solution identification purposes.

The letters ID are placed in card columns one and two for the purpose of signal by the subroutine ITRATE to search for subsequent code. Card column three is reserved for a problem identification number from one to nine which is read and written by the program in A1 format³⁹. Card column 5 is reserved for a flag which resets the solution number to one after a series of related solutions have been run for a given problem and the user desires to switch to a new solution series of the same or different problem. Any integral value between one and nine will reset the solution counter to one.

There are a variety of output options which may be selected through the use of IBM 360 Job Control Language⁴⁰. The two principal modes of output communication are 80 column card images and 133 column printed text. In planning the FTXXFOO1 data sets listed in the system procedure of Figure 24, the user was given a very flexible

list of data sets, numbers FT07 through FT12, upon which to call and use for parameter variation studies. As a result, these later data sets are all 80 bytes long and are blocked at 80 bytes so that the user may employ either cards or directed access devices for data transmission to an appropriate plotter. The NLAP output routine ECB25 is listed in Appendix E. Thus, the user may select the required data set by consulting this subroutine and the definitions of the array names given in Table 3.

A typical NLAP solution obtained without use of the PRINT statement of ECAP is contained in Figure 30 and is the output of the FT06F001 data set.

4.5 Conclusion

The range of validity of the Regression Model has been found to be limited to the active region. The modification of these equations and the subsequent testing were outside the scope of this investigation and are, therefore, a subject for further study.

<u>OUTPUT VARIABLE</u>	<u>NLAP STORAGE ARRAY</u>
Branch Voltage	CCSAV (1, J)
Branch Current	CCSAV (2, J)
Element Voltage	CCSAV (3, J)
Element Current	CCSAV (4, J)
Branch Power Dissipation	CCSAV (5, J)
Node Voltage	CCSAV (6, J)
Transconductance	CDSAV (1, J)
BETA	CDSAV (2, J)
Element Admittance	Y(J)
Element Impedance	X(J)

Table 3. Summary of NLAP Output Variable Storage Arrays

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APPENDIX A

A NETWORK ANALYSIS PROCEDURE

1. Introduction

The formulation of an electronic circuit's mesh solution begins by writing the branch level matrices of Figure A2 for the network shown in Figure A1. Each of these matrices is a column matrix containing one row element for each network branch.

2. Matrix Equation Formulation

The impedance matrix, Z , of Figure A3 is generated using the relation:

$$\text{Matrix element } Z_{ii} = Z_{\text{branch}_i}$$

The Kirchoff's Voltage Law coefficient matrix, A , of Figure A3 is formed by summing the voltages, V_i , around each mesh with the algebraic sign determined by the agreement (+), or disagreement (-), with the arbitrarily preselected positive current direction. This A matrix has as many rows as the network has meshes and as many columns as the network has branches.

The quantities, Z , JG , E , and A , are processed by a series of matrix equations to arrive at the solution for the network's branch current matrix, I_B . These equations are:

- a) All Norton equivalent current sources are converted Thevenin equivalent voltage sources:

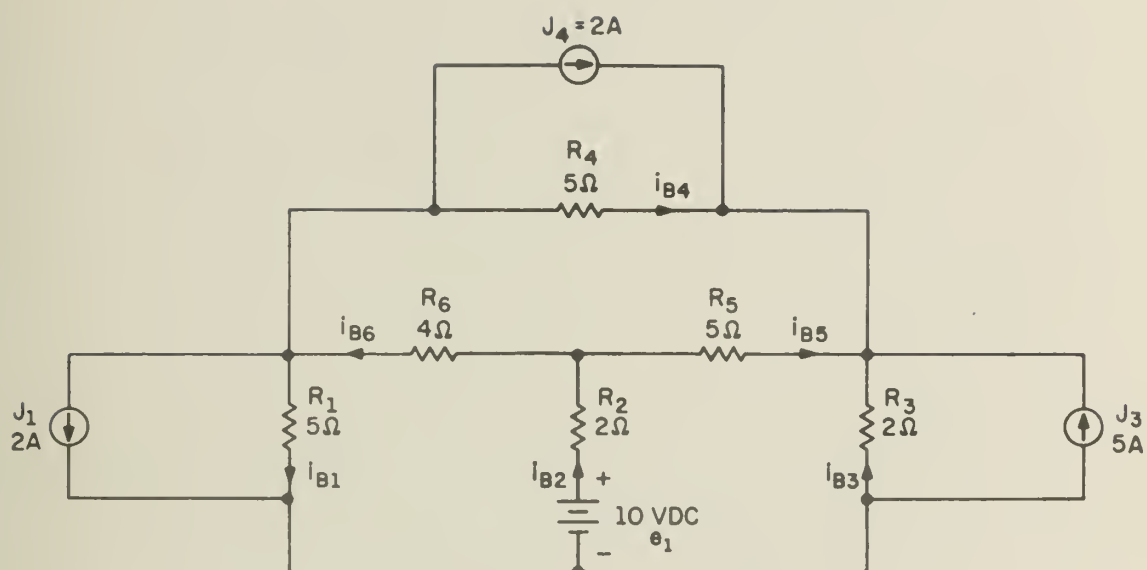


Figure A1. An Equivalent Network

$$E = \begin{bmatrix} 0 \\ +10 \\ 0 \\ 0 \\ 0 \\ 0 \end{bmatrix} \quad \text{Volts}$$

$$JG = \begin{bmatrix} +2 \\ 0 \\ +5 \\ +2 \\ 0 \\ 0 \end{bmatrix} \quad \text{Amps}$$

$$V = \begin{bmatrix} v_1 \\ v_2 \\ v_3 \\ v_4 \\ v_5 \\ v_6 \end{bmatrix} \quad \text{Volts}$$

$$I = \begin{bmatrix} i_1 \\ i_2 \\ i_3 \\ i_4 \\ i_5 \\ i_6 \end{bmatrix} \quad \text{Amps}$$

Figure A2. Branch Level E, JG, V, and I Matrices

$$Z = \begin{bmatrix} 5 & 0 & 0 & 0 & 0 & 0 \\ 0 & 2 & 0 & 0 & 0 & 0 \\ 0 & 0 & 2 & 0 & 0 & 0 \\ 0 & 0 & 0 & 5 & 0 & 0 \\ 0 & 0 & 0 & 0 & 5 & 0 \\ 0 & 0 & 0 & 0 & 0 & 4 \end{bmatrix} \text{ Amps}$$

$$A = \begin{bmatrix} -1 & -1 & 0 & 0 & 0 & -1 \\ 0 & +1 & -1 & 0 & +1 & 0 \\ 0 & 0 & 0 & +1 & -1 & +1 \end{bmatrix}$$

Figure A3. Branch Level Z and A Matrices

$$N = Z * JG$$

b) The converted current sources are summed with the native Thevenin equivalent voltage sources:

$$EE = E + N.$$

c) The voltage sources around each mesh are summed by a matrix equation:

$$EM = A * EE.$$

d) The mesh impedance matrix is formed by transposing the A matrix, premultiplying the Z matrix by A, and then post-multiplying $A * Z$, the $A * Z$ product by A^T :

$$AM = A * Z * A^T.$$

e) The network's mesh current is calculated by premultiplying the EM matrix by the inverse of the ZM matrix:

$$IM = YM * EM.$$

f) The final step is to obtain the individual currents in each branch by summing up the mesh currents passing through each branch and then subtracting the current generator matrix, JG:

$$IB = A^T * IM - JG.$$

3. Evaluation of Matrix Equations

The above matrix equations are herein evaluated for the network of Figure A1.

$$\begin{array}{lcl}
 \text{a)} & & \\
 N = Z * JG = & \begin{bmatrix} 5 & 0 & 0 & 0 & 0 & 0 \\ 0 & 2 & 0 & 0 & 0 & 0 \\ 0 & 0 & 2 & 0 & 0 & 0 \\ 0 & 0 & 0 & 5 & 0 & 0 \\ 0 & 0 & 0 & 0 & 5 & 0 \\ 0 & 0 & 0 & 0 & 0 & 4 \end{bmatrix} & * \begin{bmatrix} 2 \\ 0 \\ 5 \\ 2 \\ 0 \\ 0 \end{bmatrix} = \begin{bmatrix} 10 \\ 0 \\ 10 \\ 10 \\ 0 \\ 0 \end{bmatrix} \text{ Volts}
 \end{array}$$

$$\begin{array}{lcl}
 \text{b)} & & \\
 EE = E + N = & \begin{bmatrix} 0 \\ 10 \\ 0 \\ 0 \\ 0 \\ 0 \end{bmatrix} & + \begin{bmatrix} 10 \\ 0 \\ 10 \\ 10 \\ 0 \\ 0 \end{bmatrix} = \begin{bmatrix} 10 \\ 10 \\ 10 \\ 10 \\ 0 \\ 0 \end{bmatrix} \text{ Volts}
 \end{array}$$

$$\begin{array}{lcl}
 \text{c)} & & \\
 EM = & \begin{bmatrix} -1 & -1 & 0 & 0 & 0 & -1 \\ 0 & +1 & -1 & 0 & +1 & 0 \\ 0 & 0 & 0 & +1 & -1 & +1 \end{bmatrix} & * \begin{bmatrix} 10 \\ 10 \\ 10 \\ 10 \\ 0 \\ 0 \end{bmatrix} = \begin{bmatrix} -20 \\ 0 \\ 10 \end{bmatrix} \text{ Volts}
 \end{array}$$

$$d) \quad AM = [A * Z * A^T] = \begin{bmatrix} -1 & -1 & 0 & 0 & 0 & -1 \\ 0 & +1 & -1 & 0 & +1 & 0 \\ 0 & 0 & 0 & +1 & -1 & +1 \end{bmatrix} * \begin{bmatrix} 5 & 0 & 0 & 0 & 0 & 0 \\ 0 & 2 & 0 & 0 & 0 & 0 \\ 0 & 0 & 2 & 0 & 0 & 0 \\ 0 & 0 & 0 & 5 & 0 & 0 \\ 0 & 0 & 0 & 0 & 5 & 0 \\ 0 & 0 & 0 & 0 & 0 & 4 \end{bmatrix} * \begin{bmatrix} -1 & 0 & 0 \\ -1 & +1 & 0 \\ 0 & -1 & 0 \\ 0 & 0 & +1 \\ 0 & +1 & -1 \\ -1 & 0 & +1 \end{bmatrix} = \begin{bmatrix} 11 & -2 & -4 \\ -2 & +9 & -5 \\ -4 & -5 & 14 \end{bmatrix} \text{ ohms}$$

$$e) \quad IM = \begin{bmatrix} IM_1 \\ IM_2 \\ IM_3 \end{bmatrix} = YM * EM = \frac{10}{831} \begin{bmatrix} +101 & -48 & -46 \\ -48 & +138 & -63 \\ +46 & -63 & +95 \end{bmatrix} \begin{bmatrix} -2 \\ 0 \\ +1 \end{bmatrix} = \frac{1}{831} \begin{bmatrix} -156 \\ -33 \\ +3 \end{bmatrix} \begin{bmatrix} -1.88 \\ -0.397 \\ -0.0367 \end{bmatrix} \text{ amps}$$

$$f) \quad IB = A^T * IM - JG = \begin{bmatrix} -1 & 0 & 0 \\ -1 & +1 & 0 \\ 0 & -1 & 0 \\ 0 & 0 & +1 \\ 0 & +1 & -1 \\ -1 & 0 & +1 \end{bmatrix} \begin{bmatrix} -1.88 \\ -0.397 \\ +0.036 \end{bmatrix} - [J] = \begin{bmatrix} +1.88 \\ +1.48 \\ +0.40 \\ +0.036 \\ -0.44 \\ +1.42 \end{bmatrix} = \begin{bmatrix} -0.12 \\ +1.48 \\ +4.60 \\ -1.96 \\ -0.44 \\ +1.92 \end{bmatrix} \text{ amps}$$

A network analysis computer program utilizing the above matrix equations is listed in Figure A4, with a sample output shown in Figure A5.

```

* 1.00  FLOAT;
* 2.00  ARRAY A 3 6 F; ARRAY E 6 1 F;
* 3.00  ARRAY JG 6 1 F; ARRAY Z 6 6 F;
* 4.00  ARRAY N 6 1 F; ARRAY EE 6 1 F;
* 5.00  ARRAY EM 3 1 F; ARRAY AT 6 3 F;
* 6.00  ARRAY ZAT 6 3 F; ARRAY AM 3 3 F;
* 7.00  ARRAY YM 3 3 F; ARRAY IM 3 1 F;
* 8.00  ARRAY IBM 6 1 F; ARRAY IB 6 1 F;
* 9.00  ARRAY IBX 6 6 F; ARRAY IBS 6 1 F;
* 10.00 ARRAY PD 6 1 F; ARRAY P 6 6 F;
* 11.00 ARRAY RP 6 6 F; ARRAY S 6 1 F;
* 12.00 ARRAY SP 6 1 F;
* 13.00 A[0,0]=-1; A[0,1]=-1; A[0,5]=-1;
* 14.00 A[1,1]= 1; A[1,2]=-1; A[1,4]= 1;
* 15.00 A[2,3]= 1; A[2,4]=-1; A[2,5]= 1;
* 16.00 E[1,0]=10;
* 17.00 JG[0,0]= 2; JG[2,0]= 5; JG[3,0]= 2;
* 18.00 RP[0,0]= 1; RP[1,1]= 1; RP[2,2]= 1;
* 19.00 Z[0,0]= 5; Z[1,1]= 2; Z[2,2]= 2; Z[3,3]= 5;
* 20.00 A[3,3]= 5; Z[4,4]= 5; Z[5,5]= 4;
* 21.00 N = Z * JG; EE = E + N; EM = A * EE;
* 22.00 FOR I = 0, 1, 2; BEGIN FOR K = 0, 1, 5; BEGIN
* 23.00 AT[K, I] = A[I, K]; END END
* 24.00 ZAT = Z * AT; AM = A * ZAT; YM = ZM** -1.0;
* 25.00 IM = YM * EM; IBM = AT * IM; IB = IBM - JG;
* 26.00 IBX[0,0] = IB[0,0];
* 27.00 IBX[3,3] = IB[3,0];
* 28.00 IBS = IBX * IB;
* 29.00 PD = Z * IBS; P = RP** -1.0;
* 30.00 S = P * PD; S = 100 *S;
* 31.00 FORMAT LINE, S27, C*MATCK DATA OUTPUT*//
* 32.00 PRINT LINE;
* 33.00 FORMAT HDR, C*      I      Z      IB      PD      RP
* 34.00      S      SP*/;
* 35.00 PRINT HDR;
* 36.00 FORMAT UNITS, C* BRANCH OHMS  AMPS  WATTS
* 37.00      WATTS      NONE      PERCENT*/;
* 38.00 PRINT UNITS;
* 39.00 FORMAT MATCK, I6 ,6(F10.2);
* 40.00 FOR I = 0,1,5; BEGIN
* 41.00 PRINT MATCK, I,Z[I,I],IB[I,0],PD[I,0],RP[I,I],5[I,0],SP[I,0];
* 42.00 END;

```

Figure A4. Network Analysis Program

MATCH DATA OUTPUT

I	Z	IB	PD	RP	S	SP
BRANCH	OHMS	AMPS	WATTS	WATTS	NONE	PERCENT
0	5.00	-0.12	0.08	1.00	0.08	7.53
1	2.00	1.48	4.38	1.00	4.38	438.17
2	2.00	-4.60	42.37	1.00	42.37	4237.32
3	5.00	-1.96	19.28	1.00	19.28	1928.45
4	5.00	-0.43	0.94	1.00	0.94	93.84
5	4.00	1.91	14.64	1.00	14.64	1464.37

Figure A5. Output of Network Analysis Test Program

APPENDIX B

REGRESSION MODEL SUBROUTINE

1 SUBROUTINE ITERATE LISTING

```

COMMON CCSAV(6,200),IDWORD(74)
DOUBLE PRECISION ZPRL(50,50)
COMMON NMAX,NNODE,NTERMS,NUMBL,NUMBR,NUMBC,IRTN,NTRACE,NSWICH,KTD,
1 NPRINT(10)
COMMON E(200),EMIN(200),EMAX(200),AMP(200),AMPMIN(200),AMPMAX(200)
COMMON Y(200),YMIN(200),YMAX(200),NINIT(200),NFIN(200),MODE1(200)
COMMON YTERM(200),YTERMH(200),YTERML(200),IRUWT(200),ICOLT(200)
COMMON ERROR1,ISEQ,MSEQ,MO,NUMMO,VFIRST(50),VSECND(50),VLAST(50)
COMMON MOBRN(50),MOPARM(50),MOSTEP(50),IWCOUT(4)
C
C THE FOLLOWING VARIABLES ARE USED ONLY IN THE ECAP D.C. ANALYSIS
COMMON AX1,SMLEP(50),CURR(200),SMLE(200),EQUCUR(50),EX(200)
COMMON EB(200),AMPX(200),AMPB(200),VNOM(50),STDSQ(50),L,M,IITOL
COMMON JX1,JX4,JX5,DELTA,DUM1(28)
COMMON NWORDS(72),NMCD(2,20),KLABEL(4),KPUNC(5),INDC(2,20)
COMMON INPUT8(9),NBCD(20),KTYPE(5),NBLANK,NOEXEC,ITOL,NEQUIM,IPC
COMMON INVAL,LL,ICOL,LTYPE,KCCL,NQUIT,ITRANS,KO,KS,KELAST,NUM,M1
COMMON M2,M3,KCARD,KG,NP,NTR,MAC,HNODE,TNUM,NOEL,NOE,NOI,NOIC
COMMON EQUIVN(20),KOUT(2,10)
COMMON MATA(200,4,3),YX(200),YB(200),YTERMX(200),YTERMB(200)
COMMON WCMAX(50),WCMIN(50)
COMMON CCSAV(2,200)
DOUBLE PRECISION SMLEP,CURR,SMLE,EQUCUR
C
C THE FOLLOWING VARIABLES ARE USED ONLY IN SUBROUTINE ITRATE
DIMENSION NITER(6,2),COEFS(50,5),ICRES(50),IPTYPE(50),IPLCC(50)
DIMENSION ICURR(25),TOL(25),AMPOLD(25),BETA(200),GM(200)
DOUBLE PRECISION MACUR(200)
REAL*8 IREF
C
C INITIALIZE AND DEFINE DICTIONARY AND INDICATORS
IF (NTRACE) 1,3,1
1 WRITE(6,2)
2 FORMAT (' SUBROUTINE ITRATE, REGRESSION MODEL VERSION ENTERED')
3 NITER(1,1)= -482328512
NITER(1,2)= -985644992
NITER(2,1)= -1019199424
NITER(2,2)= -465551296
NITER(3,1)= -482328512
NITER(3,2)= -700432320
NITER(4,1)= -985644992
NITER(4,2)= -415219648
NITER(5,1)= -733986752

```

NITER(5,2)=	-700432320	
NITER(6,1)=	-650100672	
NITER(6,2)=	-985644992	
DO 300 I=1,50		GNL00440
ICRES(I)=0		GNL00450
IPATYPE(I)=0		GNL00460
IPLDC(I)=0		GNL00470
DO 300 J=1,5		GNL00480
300 COEFS(I,J)=0.0		GNL00490
DO 301 I=1,25		GNL00500
ICURR(I)=0		GNL00510
TOL(I)=0.0		GNL00520
301 AMPOLD(I)=0.0		GNL00530
DO 302 I=1,200		WNL00532
BETA(I)=0.0		WNL00534
MACUR(I) = 0.0		WNL00536
302 GM(I)=0.0		WNL00538
INDCUR=0		GNL00540
INDTOL=0		GNL00550
INDTEM=0		GNL00560
TEMP=0.0		GNL00570
TEMPI=0.0		GNL00580
TEMPF=0.0		GNL00590
TEMPC=0.0		GNL00600
IINUM=0		GNL00610
ITEMP2=1		GNL00620
		GNL00630
C		GNL00640
C	READ AND LIST DATA CARD	GNL00660
1000	READ (5,4) NWCDS	GNL00670
4	FORMAT (72A1)	GNL00680
	WRITE (6,5) NWORDS	GNL00690
5	FORMAT (1X,72A1)	GNL00700
	KCARD=KCARD+1	GNL00710
	NOEXEC=NOEXEC+NQUIT	
C		
C	CHECK FOR 'ID' CARD	
	IF (NWORDS(1)-INDC(1,15)) 1004,1001,1004	
1001	IF (NWORDS(2)-NMCD(1,1)) 1004,1002,1004	
1002	DO 1003 ICOL=1,72	
1003	IDWORD(ICOL)=NWORDS(ICOL)	
	GO TO 100C	
C		
1004	CONTINUE	GNL00720
	IF (NWORDS(1)-INPUTB(8)) 2000,100C,2000	GNL00730
C		GNL00740
C	SUPPRESS BLANKS FROM COLUMNS 7-72	GNL00750
C		GNL00760
2000	KCOL=6	GNL00770
	DO 7 ICOL=7,72	GNL00780
	IF (NWORDS(ICOL)-NBLANK) 6,7,6	GNL00790
6	KCOL=KCOL+1	GNL00800
	NWORDS(KCOL)=NWORDS(ICOL)	GNL00810
7	CONTINUE	GNL00820
C		GNL00830
C	CHECK CONTENTS OF COLUMNS 1-6	GNL00840
C		GNL00850
	DO 11 ICOL=1,5	GNL00860
	IF (NWORDS(ICOL)-NBLANK) 8,11,8	GNL00870
8	DO 9 LTYPE=1,2	

IF (NWORDS(ICOL)-KLABEL(LTYPE)) 9,200,9	GNL00880
9 CONTINUE	GNL00890
M3=5	GNL00900
15 ITRANS=6	GNL00910
10 WRITE (6,3006) M3	GNL00920
WRITE (6,3007) KCARD,ICOL	GNL00921
WRITE (6,3008)	GNL00922
NQUIT=1	GNL00923
3006 FORMAT ('O ***** ERRCR NO.',I3,' ***** MSG FROM SUBROUTINE ITRATE')	
3007 FORMAT (' CARD NO.=',I3,3X, 'APPROXIMATE COLUMN NO. IS',I3,	
1'MSG FROM SUBROUTINE ITRATE')	
3008 FORMAT (//)	GNL00926
GO TO 1000	GNL00930
16 FORMAT ('O','SUBROUTINE ITRATE ERROR MSG - CHECK YOUR INPUT DATA O	
IVER CAREFULLY, PGM SAYS YOU HAVE MADE A GOOF')	
11 CONTINUE	GNL00950
IF (KCOL-6) 500,12,13	GNL00960
12 M3=4	GNL00970
GO TO 15	GNL00980
500 ITRANS=5	GNL00990
GO TO 10	GNL01000
	GNL01010
C	
C CHECK FOR TEMPERATURE, CURRENT, TOLERANCE, EXECUTE, MODIFY OR	
C RETURN STATEMENT, INDEX NUMBERS 1, 2, 3, 4, 5, 6 RESPECTIVELY.	
C	GNL01030
13 ICOL=7	GNL01040
DO 20 IDENT=1,6	
IF (NWORDS(ICOL)-NITER(IDENT,1)) 20,14,20	GNL01060
14 IF (NWORDS(ICOL+1)-NITER(IDENT,2)) 20,25,20	GNL01070
20 CONTINUE	GNL01080
M3=12	GNL01090
GO TO 15	GNL01100
21 M3=34	GNL01110
GO TO 15	GNL01120
25 GO TO (26,26,26,8000,4000,9999),IDENT	
C	GNL01140
C GET PAST '=' SIGN ON TOLERANCE, TEMPERATURE OR CURRENTS	GNL01150
C	GNL01160
26 ICOL=ICOL+1	GNL01170
IF (ICOL-KCOL) 27,21,21	GNL01180
27 IF (NWORDS(ICOL)-KPUNC(1)) 26,28,26	GNL01190
28 ICOL=ICOL+1	GNL01200
GO TO (50,29,39),IDENT	GNL01210
C	GNL01220
C PROCESS TOLERANCES AND/OR CURRENTS	GNL01230
C	GNL01240
29 IF (INDCUR) 21,30,21	GNL01250
30 INDCUR=1	GNL01260
41 I=0	GNL01270
31 CALL EC809	GNL01280
I=I+1	GNL01290
NUM=TNUM	GNL01300
IF (I-25) 42,42,21	GNL01310
32 ICURR(I)=NUM	GNL01320
IT=I	GNL01330
33 ICOL=ICOL+1	GNL01340
IF (ICOL-KCOL) 34,34,1000	GNL01350
34 IF (NWORDS(ICOL)-KPUNC(3)) 36,35,36	GNL01360
35 ICOL=ICOL+1	GNL01370

GO TO 31	GNL01380
36 M3=34	GNL01390
GO TO 15	GNL01400
39 IF (INDTOL) 21,40,21	GNL01410
40 INDTOL=1	GNL01420
GO TO 41	GNL01430
42 GO TO (500,32,43),IDENT	GNL01440
43 TOL(I)=TNUM	GNL01450
JT=I	GNL01460
GO TO 33	GNL01470
C	GNL01480
C PROCESS TEMPERATURE	GNL01490
C	GNL01500
50 IF (ICOL-KCOL) 51,51,36	GNL01510
51 IF (INDTEM) 36,52,36	GNL01520
52 INDTM=1	GNL01530
CALL ECB09	GNL01540
TEMPI=TNUM	GNL01550
ICOL=ICOL+1	GNL01560
IF (ICOL-KCOL) 54,54,53	GNL01570
53 TEMP=TEMPI+273.0	GNL01580
ITEMP2=1	GNL01590
GO TO 1000	GNL01600
54 IF (NWORDS(ICOL)-KPUNC(2)) 36,55,36	GNL01610
55 ICOL=ICOL+1	GNL01620
CALL ECB09	GNL01630
TEMPC=TNUM	GNL01640
ITEMP2=2	GNL01650
ICOL=ICOL+1	GNL01660
IF (ICOL-KCOL) 56,56,36	GNL01670
56 IF (NWORDS(ICOL)-KPUNC(4)) 36,57,36	GNL01680
57 ICOL=ICOL+1	GNL01690
CALL ECB09	GNL01700
TEMPF=TNUM	GNL01710
GO TO 1000	GNL01720
C	GNL01730
C GET COEFFICIENTS AND DATA TYPE	GNL01740
C	GNL01750
200 ICOL=ICOL+1	GNL01760
IF (ICOL-KCOL) 201,201,21	GNL01770
201 IINUM=IINUM+1	GNL01780
IF (IINUM-50) 203,203,202	GNL01790
202 M3=36	GNL01800
GO TO 15	GNL01810
203 CALL ECB09	GNL01820
NUM=TNUM	GNL01830
IPLOC(IINUM)=NUM	GNL01840
IF (NWORDS(7)-INPUTB(5)) 204,207,204	GNL01850
204 IF (NWORDS(7)-INPUTB(2)) 205,208,205	GNL01860
205 IF (NWORDS(7)-INPUTB(4)) 206,209,206	GNL01870
206 IF (NWORDS(7)-INPUTB(3)) 225,224,225	GNL01880
207 MTYPE=1	GNL01890
GO TO 210	GNL01900
208 MTYPE=2	GNL01910
GO TO 210	GNL01920
209 MTYPE=3	GNL01930
210 IPTYPE(IINUM)=MTYPE	GNL01940
211 ICOL=ICOL+1	GNL01950
IF (ICOL-KCOL) 212,212,21	GNL01960

212	IF (NWORDS(ICOL)-KPUNC(2)) 211,213,211	GNL01970
213	ICOL=ICOL+1	GNL01980
	IF (ICOL-KCOL) 214,214,21	GNL01990
214	CALL ECB09	GNL02000
	NUM=TNUM	GNL02010
	ICRES(I(NUM))=NUM	GNL02020
	ICOL=ICOL+1	GNL02030
	IF (ICOL-KCOL) 215,215,21	GNL02040
215	IF (NWORDS(ICOL)-KPUNC(4)) 206,216,206	GNL02050
216	ICOL=ICOL+1	GNL02060
	IF (ICOL-KCOL) 217,217,21	GNL02070
217	IF (NWORDS(ICOL)-KPUNC(1)) 206,218,206	GNL02080
218	IICOL=0	GNL02090
222	ICOL=ICOL+1	GNL02100
	IF (ICOL-KCOL) 220,220,219	GNL02110
219	IF (IICOL) 500,206,1000	GNL02120
220	IICOL=IICOL+1	GNL02130
	IF (IICOL-5) 223,223,206	GNL02140
223	CALL ECB09	GNL02150
	COEFS(IINUM,IICOL)=TNUM	GNL02160
	ICOL=ICOL+1	GNL02170
	IF (ICOL-KCOL) 221,221,1000	GNL02180
221	IF (NWORDS(ICOL)-KPUNC(3)) 206,222,206	GNL02190
224	MTYPE=4	GNL02200
	GO TO 210	GNL02210
225	M3=36	GNL02220
	GO TO 15	GNL02230
C		GNL02240
C	BEGIN EXECUTION OF ITERATION TECHNIQUE	GNL02250
C		GNL02260
8000	IF (NTRACE) 8901,8900,8901	GNL02270
8901	WRITE (6,8908)	GNL02280
	WRITE (6,8902) (TCL(I),I=1,IT)	GNL02290
	WRITE (6,8903) (ICURR(I),I=1,IT)	GNL02300
	WRITE (6,8906)	GNL02310
	WRITE (6,8904) ((COEFS(I,J),J=1,5),I=1,IINUM)	GNL02320
	WRITE (6,8907)	GNL02330
	WRITE (6,8905) (1,ICRES(I),IPTYPE(I),IPLOC(I),I=1,20)	GNL02340
	WRITE (6,8911)	GNL02350
	WRITE (6,8910) (CLRR(J),J=1,NMAX)	GNL02360
8902	FORMAT (1H0,1CF10.4)	GNL02370
8903	FORMAT (1HC,1C(5X,15))	GNL02380
8904	FORMAT (1X,5E17.7)	GNL02390
8905	FORMAT (1X,13,5X,15,5X,15,5X,15)	GNL02400
8906	FORMAT (1H0,12HCOEFFICIENTS/)	GNL02410
8907	FORMAT (1H0,2X,1H1,7X,5HICRES,4X,6HIPTYPE,5X,5HIPLOC/)	GNL02420
8908	FORMAT (1H0,23HTOLERANCES AND CURRENTS)	GNL02430
8910	FORMAT (1X,8E16.7)	GNL02450
8911	FORMAT (1H0,8HCURRENTS/)	GNL02460
8900	IF (INDCUR+INDTOL-2) 8001,8002,8001	GNL02480
8001	M3=35	GNL02490
	GO JO 15	GNL02500
8002	IF (IT-JT) 8003,8004,8003	GNL02510
8003	M3=36	GNL02520
	GO TO 15	GNL02530
8004	CONTINUE	GNL02540
	NUM=0	GNL02550
	GO TO (8058,8050),ITEMP2	GNL02560
C		GNL02570

C	SINGLE TEMPERATURE	GNL02580
C		GNL02590
8008	CONTINUE	GNL02600
	GO TO 1000	
C		GNL02620
C	RANGE OF TEMPERATURES	GNL02630
C		GNL02640
8050	TEMPC=(TEMPF-TEMP1)/TEMPC	GNL02650
	TEMPF=TEMPF+273.0	GNL02660
	TEMP1=TEMP1+273.0	GNL02670
	TEMP=TEMP1	GNL02680
	GO TO 8098	GNL02690
8053	TEMP=TEMP+TEMPC	GNL02700
	NUM=0	GNL02710
	IF (TEMP-TEMPF) 8098,8098,8054	GNL02720
8054	CONTINUE	GNL02730
	GO TO 1000	
C		GNL02750
C	STORE PRESENT CURRENT VALUES	GNL02760
C		GNL02770
8098	DO 8099 I=1,IT	GNL02780
	J=ICURR(I)	GNL02790
8099	AMPOLD(I)=CURR(J)	GNL02800
	NUM=NUM+1	GNL02810
C		GNL02820
C	CALCULATE NEW DEPENDENT VALUES	GNL02830
C		
8100	DO 8105 I=1, IINUM	WNL02850
	J=ICRES(I)	WNL02851
	IREF = 1000000.C	
	CUTOFF = 1.0	
	ZOFF = 5555555.CC00	
	MACUR(J) = (CURR(J))*IREF	
	SAVE = SNGL(MACUR(J))	WNL
	MTYPE=IPTYPE(I)	WNL02853
	K=IPLOC(I)	WNL02854
	NFBR = ICOLT(K)	WNL02855
C		WNL02856
	GOTO (8101,8102,8103,8104),MTYPE	WNL02860
C		WNL02861
C	CALCULATE NEW VBE	
8101	IF(SAVE .LE. CUTOFF) WRITE(6,8920) J,SAVE,J	WNL028X
8920	FORMAT(' ',20X,'CALCULATION OF VBE',5X,' CURR(',I3,') = ' ,	
	1 F20.8, 5X,'FROM BRANCH =',I3)	
	IF(SAVE .LE. CUTOFF) GOTO 614	
	ALCUR = ALOG(SAVE)	WNL02870
	VALUE=COEFS(I,1) + ALCUR*(COEFS(I,2)+ COEFS(I,3)*ALCUR)	WNL02872
	E(K) = VALUE + CCSAV(3,K)	WNL0287
	GOTO 616	WNL02873
614	VALUE = COEFS(I,1)	WNL02875
	E(K) = VALUE	WNL02876
616	CONTINUE	
C 616	WRITE(6,8928)J,SAVE,J,CURR(J),MTYPE,K,NFBR,ALCUR,VALUE	
8928	FORMAT('0',10X,'CALCULATION OF VBE',5X,'J='I3,5X,' IC ='F8.3,	
	15X,'CURR('I3,')= 'F12.6,5X,'MTYPE ='I3,5X,'K ='I3,/	
	2' ',34X,'NFBR ='I3,5X,'LN(IC) ='F12.6,5X,' VBE ='F12.6/)	
	GOTO 8105	
C		
C		WNL02878

C	CHECK TOLERANCES	GNL03250
C		GNL03260
8200	DO 8201 I=1,IT	GNL03270
	J=ICURR(I)	GNL03280
	SAVE=CURR(J)	
	IF (ABS(AMPOLD(I)-SAVE) - ABS(AMPOLD(I)*TOL(I))) 8201,8201,8098	
8201	CONTINUE	GNL03300
C		GNL03320
C	OUTPUT RESULTS	GNL03330
C		GNL03340
8302	WRITE (6,8303) NUM	GNL03350
8303	FORMAT ('-', 'NUMBER OF ITERATIONS = ',I3/)	GNL03360
	IF (INDTEM) 8202,8203,8202	GNL03370
8202	TEMPA=TEMP-273.0	GNL03380
	WRITE (6,9000) TEMPA	GNL03390
9000	FORMAT (1H0,14HTEMPERATURE = ,F10.3/)	GNL03400
8203	DO 8204 I=1,NMAX	GNL03410
	YX(I)=Y(I)	GNL03420
	EX(I)=E(I)	GNL03430
8204	AMPX(I)=AMP(I)	GNL03440
	IF (NTERMS) 8205,8207,8205	GNL03450
8205	DO 8206 I=1,NTERMS	GNL03460
8206	YTERM(I)=YTERM(I)	GNL03470
8207	CALL ECB22(ZPRL)	GNL03480
	CALL ECB23	GNL03490
C	THE FOLLOWING CODE RECOGNIZES AND EXECUTES THE PRINT NV,MI CONTROL	
C	INPUT DATA STATEMENT. RESULTANT OUTPUT IS THE DC AND NL MATRICES.	
	IF(NPRINT(10)) 107,107,108	
108	JX1=1	
	CALL ECB24(ZPRL)	
107	CALL ECB26(ZPRL)	
	NTR=1	
	IF(NPRINT(10)) 103,103,104	
104	JX1=2	
	CALL ECB24(ZPRL)	
103	CALL ECB25	
	NTR=4	
	WRITE (6,9001)	GNL03530
	WRITE (6,9002) (I,ICCLT(I),IROWT(I),BETA(I),GM(I),YTERM(I),	GNL03540
1	I=1,NTERMS)	GNL03550
9001	FORMAT (//,1X,9H T-NUMBER,7X,6H ICCLT,11X,6H IROWT,6X,4HBETA,11X,	GNL03580
	12HGM,11X,5HYTERM/)	GNL03590
9002	FORMAT (3X,I4,11X,I4,13X,I4,2F15.7,E15.7)	GNL03600
	GO TO (8008,8053),ITEMP2	GNL03630
8300	WRITE (6,8301)	GNL03640
8301	FORMAT (1H0,34HNO CONVERGENCE AFTER 20 ITERATIONS/)	GNL03650
	GO TO 8302	GNL03660
C		
C	BEGIN MODIFY ROUTINE	
C		
4000	CONTINUE	
	GO TO 1000	
C		
C	EXIT TO MAIN ROUTINE	
C		
9999	RETURN	
	END	GNL03670

2 COMMENTS ON PROGRAM CHANGES

1. ORIGINAL VERSION OF THIS SUBROUTINE WAS WRITTEN BY G. GUTH. CHANGES MADE BY D. WOOD IN INPUT-OUTPUT ROUTINE TO PERMIT PARAMETER VARIATION ANALYSIS, USE OF VARYING REFERENCE CURRENTS, IREF, AND MODIFICATION OF THE BASIC ROUTINE TO PERMIT IT TO HANDLE BOTH CUTOFF AND ACTIVE TRANSISTOR OPERATING REGIONS.
2. INSERTED MACUR(J) TO IMPROVE THE FLEXIBILITY OF REGRESSION MODEL. THUS BY THE USE OF A SCALE FACTOR OF $IO = IREF$, THE CURRENT NORMALIZATION IN THE REGRESSION MODEL MAY BE CHANGED BY A FUTURE MODIFICATION PERMITTING IREF TO BE READ IN AT EXECUTION TIME.
3. CUTOFF IS THE COLLECTOR CURRENT VALUE, IC , AT WHICH BETA IS SET EQUAL TO ZERO. CUTOFF IC IS THAT VALUE OF IC , DETERMINED FROM THE REGRESSION MODEL EQUATIONS, FOR WHICH $BETA = 0$.
4. ZOFF IS THE IMPEDANCE LEVEL SWITCHED INTO THE BASE BRANCH WHENEVER THE COLLECTOR CURRENT BECOMES \leq CUTOFF. ZOFF SET EQUAL TO $= 555555.0$ IN PROGRAM, THUS ENABLING THE USER TO SPOT IN THE IMPEDANCE LISTINGS, EXACTLY WHEN THE PROGRAM PREDICTED ENTRY INTO THE CUTOFF MODE OF OPERATION.
5. DUE TO THE THE UNIT OF CURRENT, AMPERES, ASSUMED BY THE ECAP SUBROUTINES, SET $IREF=1.0$, WHEN A 1.0 AMPERE REFERENCE IS DESIRED. IF MICROAMPERES IS DESIRED, SET $IREF=1000000.0$, AND IF MILLIAMPERES IS DESIRED, SET $IREF=1000.0$.
6. THE ARRAY IN COMMON, CDSAV(2,200) IS USED TO PASS YTERM(200) AND BETA(200) VALUES TO NLAP OUTPUT ROUTINE ECB25. $CDSAV(1,J) = YTERM(J)$ AND $CDSAV(2,K) = BETA(K)$.
7. THE FOLLOWING INFORMATION IS TO ASSIST PGMR IN ADDING MODIFY OPTION TO THIS SUBROUTINE, TO ELIMINATE PRESENT REQUIREMENT FOR DUPLICATING DATA DECKS FOR THE CASE OF PARAMETER VARIATION OPTION RUNS.
 - A. MODIFY ROUTINE IS ECA30
 - B. $M =$ MODIFY NO., $NUMMO =$ NO. MODS, $MOSTEP =$ NO. MOD STEPS
 - C. $MCPARM(M)$ IS KIND OF PARAMETER TO BE MODIFIED
 - D. $MOBRN(M)$ IS CARD SEQUENCE NUMBER
 - E. $NTERM$ IS TOTAL NUMBER OF DATA CARDS
 - F. $VFIRST(M)$ CONTAINS VALUE OF ALL PARMS TO BE MODIFIED
8. NOTE THAT GM AND Y NEW VALUE CODES HAVE NOT BEEN MODIFIED.
9. THIS SUBROUTINE AS NOW CODED WILL GIVE ACCURATE RESULTS FOR THE NL OPTION OF NLAP, PROVIDED THAT THE USER IS VERY CAREFUL TO KEEP INPUT DATA SO THAT THE CIRCUIT DOES NOT GO DEEP INTO THE CUTOFF REGION OF OPERATION, OTHERWISE CURRENT CONVERGENCE MAY NOT BE OBTAINED DUE TO PRESENT REGRESSION MODEL EQUATION FOR VBE NOT HAVING AN EXTERNAL CIRCUIT CURRENT VARIABLE INCLUDED AS AN INDEPENDENT VARIABLE.

APPENDIX C

LINEAR REGRESSION PROGRAM

1 LINEAR REGRESSION PROGRAM LISTING

```

COMMON  A,ACHG,DLD,ICDCT
COMMON  AI(40),ANAM(25,40),FMT(18),KZ(20),KCHG,TITLE(18)
DOUBLE PRECISION AI(40),ACHG(40,4),DLD,ICDCT
DOUBLE PRECISION      AID(20),CS(20),C(20,20),V(20),BB(20)
DOUBLE PRECISION      TST,      SSS,STDV,SPST
DOUBLE PRECISION AMEAN,CD,AKNT,SOUT,SIGN,PCT,STER,AST
DOUBLE PRECISION BETA,BVAR,BSTD,TRAT,SIZE,AM,DF,RR,R,ADJR,ADJRR
REAL      DSAV(10,101)

```

C

```

1056 FORMAT (18A4)
1000 FORMAT(6X,I2,1X,I2,1X,3(I1,1X),F9.0)
510  FORMAT (6X,24A1)
1001 FORMAT (6X,16A4)
1057 FORMAT ('-',2X,'INPUT DATA FORMAT = ',2X,16A4 )
1002 FORMAT ('1', 2X,18A4)
8001 FORMAT(6X,F2.0,1X,F2.0,1X,F2.0,1X,F6.0 )
8002 FORMAT ('0', 2X,'ACHG(',I2,') = ',F3.0,1X,F3.0,1X,F3.0,1X,F6.0 )
615  FORMAT('-',2X,'INPUT DATA', 4X,15(9A1,3X))
9000 FORMAT (1H0,1CH C(I,J)= ,6F6.2,/)
9002 FORMAT(1H ,7H SIZE= ,F10.2)
1066 FORMAT ('-',2X,'VAR NO.',6X,'NAME',17X,'MEAN',3X, 'POP STD DEV',
12X, 'SAMP STD DEV' )
1067 FORMAT (' ',15,5X,20A1, 3F12.5)
1006 FORMAT (6X,10(F1.0,1X))
488  FORMAT (44HCTOO FEW DEGREES OF FREEDOM, TRY ANOTHER EQN,/,14H.SAMP
1LE SIZE =,/,18HINDEP VAR IN EQN =,F5.0)
2000 FORMAT (8H0VAR NO.,13,20HLEADS TO SINGULARITY,5X8HVALUE IS,F12.8)
446  FORMAT ('0',/, '0',2X, 'INTERCORRELATION MATRIX' )
459  FORMAT (' ',35X,8I6,/, '0',24X,9I5)
455  FORMAT (' ',6X,20A1,5X,I4,2X,16F6.2)
4002 FORMAT ('2',I1,119('-',) )
660  FORMAT ('0', 2X,18A4 )
3009 FORMAT('-',18X,'DEPENDENT VARIABLE IS NUMBER -',I3,' -',3X, 20A1)
490  FORMAT('0'15X , 'SAMPLE SIZE =',F6.1,7X,'DEGREES FREEDOM ='F6.1 )
3010 FORMAT('0',6X,'R**2 = ',F5.3,7X,'R = ',F5.3,8X,'STD ERR OF EST =',
1F8.3 )
472  FORMAT('0',2X,'ADJ R**2 = ',F5.3,3X,'ADJ R = ',F5.3,4X,'ADJ STD ER
1R OF EST =' ,F8.3 )
475  FORMAT('-', 2X,'LINEAR REGRESSION EQUATION CCOEFFICIENTS' )
3012 FORMAT('0', 2X'VAR NO.'4X'NAME'19X6HREG WT,4X,'BTA WT',4X,'WT SIG'
1,3X,'T-RATIO')
3053 FORMAT (' ',2X , I4,3X, 21A1, F12.5,3F11.5 )
469  FORMAT (1HC,/)
3091 FORMAT('-',2X, 'RESULTS ARE IN RAW SCORES')

```



```

3086 FORMAT ('C',2X, 'END OF PROBLEM'// '2')
430 FORMAT(' ',2X,'END OF REGRESSION PGM'// '1')
      TOL=0.00005
      DO 14 I=1,20
        AID(I)=0.0
        DO 14 J=1,20
          14 C(I,J)=0.0
C READ TITLE
      READ (5,1056)(TITLE(I),I=1, 18)
C READ NUMBER OF VARIABLES CARD , NVAR = 10 MAX
      16 READ (5,1000 ) NIND,NVAR,ICOR,IPRT,ICRG,TST
      NIND=NIND+1
      ICDCT=0
      NVARM=NVAR+1
      M=NVARM
      IF(NVARM .LT. 1) GOTO 850
      20 DO 24 I=2, NVARM
C READ IN NAMES OF DATA VARIABLES CARD COLS 7 - 27.
      24 READ (5,510)(ANAM(J,I),J=1,24)
C READ IN DATA FORMAT
      READ (5,1001)(FMT(I),I=1,16 )
C WRITE TITLE OF OUTPUT DATA
      WRITE (6,1002)(TITLE(K),K=1,18)
C WRITE FORMAT USED TO READ IN AND WRITE OUT THE PGM'S INPUT DATA
      WRITE(6,1057)(FMT(K),K=1,16 )
      IF(ICRG .LE. 0) GOTO 38
      KCRG=0
      NTRANS = 40
      DO 35 L=1, NTRANS
C READ IN DESIRED VAR. TRANSFORMATIONS, MAX = 10.
      READ (5,8001)(ACHG(L,J),J=1,4)
      IF(ACHG(L,1) .LE. 0) GOTO 38
C WRITE OUT TRANSFORMATIONS
      WRITE (6,8002) L,(ACHG(L,J),J=1,4)
      KCRG=KCRG+1
      35 CONTINUE
C 38 WRITE(6,8003)
C WRITE NAMES OF INPUT DATA VARIABLES.
      38 WRITE(6,615) ((ANAM(JK,IJ), JK=1,9),IJ=2,NIND)
C. READ IN NIND COLS OF DATA PER DATA FORMAT CARD, REF. STMT 1001
      40 READ (5,FMT)(A(I),I=2,NIND)
      IF(A(2) .GE. TST) GOTO 60
C WRITE LIST OF INDEPENDENT VARIABLE INPUT DATA.
      WRITE (6,FMT)(A(I),I=2,NIND)
      A(1)=1.0
      ICDCT=ICDCT+1
      IF(ICRG .GT. 0) CALL CHANGG
      DO 55 I=1,NVARM
        DO 55 J=I,NVARM
          55 C(I,J)=C(I,J)+A(I)*A(J)
          GOTO 40
      60 SIZE=C(1,1)
C
C WRITE ROW OF ** IF A(2) .GE. TST, PROVIDED LAST DATA CARD HAS ALL 9'S
C OTHERWISE THE LAST DATA VARIABLE IS LISTED IN THE OUTPUT TWICE.
      WRITE (6,FMT)(A(I),I=2,NIND)
      V(1)=DSQRT(C(1,1))
      DO 74 I=2,NVARM
        IF (C(I,1) .LE. 0) GOTO 72

```

```

      V(I)=(SIZE*C(I,I)-C(1,I)*C(1,I))/(SIZE*SIZE)
      IF (V(I) .LE. 0) GOTO 72
      V(I)=DSQRT(V(I))*V(I)
      GOTO 74
72  V(I)=1.0*V(I)
74  CONTINUE
      SSS=DSQRT(SIZE)
      SSS=1.0/SSS
C   WRITE DATA STATISTICS HEADING
      WRITE(6,1066)
      DO 76 I=2,NVARM
      STDV=V(I)*SSS
      SPST=V(I)*SSS
      SPST=SPST*SPST
      CD=(SIZE*SIZE)/((SIZE-1.0)*(SIZE-1.0))
      SPST=SPST*CD
      SPST=DSQRT(SPST)
      AMEAN=C(1,I)/SIZE
      K=I-1
C   WRITE DATA STATISTICS
      WRITE (6,1067)K,(ANAM(J,I), J=1,20),AMEAN,STDV,SPST
76  CONTINUE
C   READ MODEL DEFINATION CARDS (INVERT CARDS)
80  READ (5,1068)(AI(I),I=2,NVARM)
      AI(I)=1.0
      IF (AI(2)-3.0) 82,800,850
82  AKNT=0.0
      DO 84 I=1,NVARM
      IF(A(I) .NE. 1.0) GOTO 84
      AKNT=AKNT+1.0
84  CONTINUE
      IF (SIZE .GT. AKNT) GOTO 86
C
      WRITE (6,488)SIZE,AKNT
      GOTO 80
86  DO 92 I=1,NVARM
      IF (AID(I) .GT. 0) GOTO 90
      CS(I)=1.0/V(I)
      GOTO 92
90  CS(I)=V(I)
92  CONTINUE
      DO 94 I=1,NVARM
      DO 94 J=1,NVARM
94  C(I,J)=C(I,J)*CS(I)*CS(J)
      DO 180 N=1,M
      IF (AI(N) .EQ. 1) GOTO 96
      SOUT=0.0
      GOTO 98
96  SOUT=1.0
98  IF (SOUT .EQ. AID(N)) GOTO 180
      IF(C(N,N) .LE. 0) GOTO 170
      IF (C(N,N) .LE. TCL) GOTO 170
101 C(N,N)=1.0/C(N,N)
      IF (SOUT .GT. 0) GOTO 106
102 DO 105 I=1,M
      IF (I-N)103,105,104
103 C(I,N)=(1.0-2.0*AID(I))*C(I,N)
      GO TO 105
104 C(N,I)=(1.0-2.0*AID(I))*C(N,I)

```

```

105 CONTINUE
106 DO 111 I=1,M
    DO 111 J=1,M
        SIGN=1.0-2.0*DABS(SOUT-AID(I)*AID(J))
        IF (I-N)107,111,110
107 IF (J-N)108,111,109
108 C(I,J)=C(I,J)+SIGN*C(I,N)*C(J,N)*C(N,N)
    GO TO 111
109 C(I,J)=C(I,J)+SIGN*C(I,N)*C(N,J)*C(N,N)
    GO TO 111
110 C(I,J)=C(I,J)+SIGN*C(N,I)*C(N,J)*C(N,N)
111 CONTINUE
    IF (SOUT .LE. C) GOTO 116
112 DO 115 I=1,M
    SIGN=1.0-2.0*AID(I)
    IF (I-N)113,115,114
113 C(I,N)=SIGN*C(I,N)*C(N,N)
    GO TO 115
114 C(N,I)=SIGN*C(N,I)*C(N,N)
115 CONTINUE
    GO TO 169
116 DO 168 I=1,M
    IF (I-N) 161, 168, 162
161 C(I,N)=C(I,N)*C(N,N)
    GO TO 168
162 C(N,I)=C(N,I)*C(N,N)
168 CONTINUE
169 AID(N)=SOUT
    GOTO 180
170 K=N-1

C
    WRITE (6,200C)K,C(N,N)
    AI(N)=2.0
    GOTO 190
180 CONTINUE
190 DO 250 I=1,NVARM
    IF (AID(I))250,241,242
241 CS(I)=V(I)
    GOTO 250
242 CS(I)=1.0/V(I)
250 CONTINUE
    IF(ICOR .LE. 0) GOTO 444
C WRITE TITLE 'INTERCORRELATION MATRIX'
    WRITE (6,446)
    MKB=M-1

C
    WRITE (6,459)(IJ,IJ=1,MKB)
    DO 447 II=1,M
    DO 447 JJ=II,M
447 C(JJ,II)=C(II,JJ)
    DO 450 II=2,M
    MK=II-1
C WRITE INTERCORRELATION MATRIX DATA.
    WRITE (6,455)(ANAM(JN,II),JN=1,20),MK,(C(II,JJ),JJ=2,II)
450 CONTINUE
    DO 458 II=1,M
    DO 458 JJ=1,M
458 C(II,JJ)=C(II,JJ)*CS(II)*CS(JJ)
    ICOR=0

```

```

      GOTO 80
444 DO 254 I=1,NVARM
      DO 254 J=1,NVARM
254 C(I,J)=C(I,J)*CS(I)*CS(J)
      AM=0.0
      DO 299 I=1,NVARM
      IF (AID(I)-1.0)299,280,299
280 AM=AM+1.0
299 CONTINUE
      DO 300 I=2,NVARM
      IF (AI(I) .LE. 1.0) GOTO 300
301 PCT=C(I,1)/(V(I)+V(I))
      STER=C(I,1)/SIZE
      AST=SIZE/(SIZE-AM)
      ADSSR=STER*AST
      STER=DSQRT(STER)
      ADSSR=SQRT(ADSSR)
      DF=SIZE-AM
      RR=1.0-PCT
      R = OSQRT(RR)
      ADJRR=1.0-((1.0-RR)*((SIZE-1.0)/(SIZE-AM)))
      IF (ADJRR .GT. 0.0) GOTO 340
      ADJRR=0.0
      ADJR=0.0
      GOTO 344
340 ADJR=DSQRT(ADJRR)
344 K=I-1
C WRITE REGRESSION EQUATION STATISTICS
  WRITE (6,4002)IPRT
  WRITE (6, 66C) (TITLE(K), K=1,18)
  WRITE (6,3009)K,(ANAM(MK,I),MK=1,20)
  WRITE (6,490)SIZE,OF
  WRITE (6,3010)RR,R,STER
  WRITE (6,472)AOJRR,AOJR,AOSSR
  WRITE(6,475)
C WRITE TITLES FOR REGRESSION EQUATION COEFFICIENT TABLE.
  WRITE (6,3012)
  KJ=0
  DO 320 J=1,NVARM
  IF (AIO(J) .NE. 1.0) GOTO 320
  IF (I-J)324,320,325
324 BETA=C(I,J)
  GOTO 326
325 BETA=C(J,I)
326 BVAR=C(I,1)*C(J,1)/(SIZE-AM)
  BSTD = OSQRT(BVAR)
  TRAT=BETA/BSTD
  K=J-1
  KJ=KJ+1
  KZ(KJ)=K
  BB(KJ)=BETA
  BVAR=BETA*V(J)/V(I)
C WRITE REGRESSION EQUATION COEFFICIENTS
  WRITE (6,3053)K,(ANAM(NJ,J),NJ=1,21),BETA,BVAR,BSTD,TRAT
320 CONTINUE
300 CONTINUE
C
  WRITE (6,3051)
  GOTO 80

```

C

```

800 WRITE (6,3086)
    IF(NVARM .LE. 0) GOTO 850
820 GOTO 10
850 WRITE(6,430)
    STOP
    END
    BLOCK DATA
    COMMON A,ACHG,DLD,ICDCT
    COMMON AI(40),ANAM(25,40),FMT(18),KZ(20),KCHG,TITLE(18)
    DOUBLE PRECISION A(40),ACHG(40,4),DLD,ICDCT
    DATA ANAM/'C','O','N','S','T','A','N','T',' ','T','E','R','M',
1 987*'/
    END
    SUBROUTINE CHANGG
    COMMON A,ACHG,DLD,ICDCT
    COMMON AI(40),ANAM(25,40),FMT(18),KZ(20),KCHG,TITLE(18)
    DOUBLE PRECISION A(40),ACHG(40,4),DLD,ICDCT

```

C

```

DO 100 I=1,KCHG
K8AB=ACHG(I,1)
ND=IDINT( ACHG(I,2) )
MD=IDINT( ACHG(I,3) )
LD=IDINT( ACHG(I,4) )
MD=MD+1
ND=ND+1
LD=LD+1
DLD=ACHG(I,4)
GO TO (1,2,3,4,5,6,7,8,9,10,11,12),K8AB
1 A(MD)=A(ND)**DLD
GO TO 100
2 A(MD)=1.0/(A(ND)**DLD)
GO TO 100
3 A(MD)=A(ND)*A(LD)
GO TO 100
4 A(MD)=A(ND)/A(LD)
GO TO 100
5 A(MD)=A(ND)-A(LD)
GO TO 100
6 A(MD)=DSQRT(A(ND))
GO TO 100
7 A(MD)=DLOG(A(ND))
GO TO 100
8 A(MD)=DEXP(A(ND))
GO TO 100
9 A(MD)=A(ND)+A(LD)
GO TO 100
10 A(MD)=ICDCT
GO TO 100
11 A(MD)=A(ND)+DLD
GO TO 100
12 A(MD)=A(ND)*(DLD)
100 CONTINUE
RETURN
END

```

2 TYPICAL OUTPUT

C3 MILLIAMPERE LINEAR REGRESSION PGM, C3 IC-NOMINAL DATA, VCE = 2.0 VOLT

INPUT DATA FORMAT = (16X,3F10.3)

ACHG(1) = 7. 1. 4. 0.0

ACHG(2) = 3. 4. 5. 4.

INPUT DATA	COLLECTOR	BETA	VBE
	0.106	0.0	0.658
	0.540	108.375	0.702
	1.080	108.000	0.720
	1.293	106.500	0.725
	1.616	107.667	0.730
	2.140	104.800	0.738
	2.658	103.600	0.745
	3.183	105.000	0.749
	3.688	101.000	0.754
	4.192	100.800	0.758
	5.213	102.100	0.763
	6.176	96.300	0.770
	7.207	103.100	0.772
	8.230	102.300	0.775

INPUT DATA STATISTICS

VAR NO.	NAME	MEAN	POP STD DEV	SAMP STD DEV
1	COLLECTOR CURRENT	3.38018	2.44564	2.63377
2	BETA	96.39586	26.92444	28.99555
3	VBE	0.73993	0.03071	0.03307
4	LN(IC, MILLIAMPS)	0.79623	1.12882	1.21565
5	LN(IC, MILLIAMPS)**2	1.90821	1.64586	1.77246

INTERCORRELATION MATRIX

	1	2	3	4	5	
COLLECTOR CURRENT	1	1.00				
BETA	2	0.29	1.00			
VBE	3	0.86	0.67	1.00		
LN(IC, MILLIAMPS)	4	0.86	0.68	1.00	1.00	
LN(IC, MILLIAMPS)**2	5	0.59	-0.59	0.13	0.12	1.00

C3 MILLIAMPERE LINEAR REGRESSION PGM, C3 IC-NOMINAL DATA, VCE = 2.0 VOLT

DEPENDENT VARIABLE IS NUMBER - 18 - BETA

SAMPLE SIZE = 14.0 DEGREES FREEDOM = 11.0

R**2 = 0.918 R = 0.958 STD ERR OF EST = 7.705

ADJ R**2 = 0.903 ADJ R = 0.950 ADJ STD ERR OF EST = 8.692

LINEAR REGRESSION EQUATION COEFFICIENTS

VAR NO.	NAME	REG WT	BTA WT	WT SIG	T-RATIO
0	CONSTANT TERM	103.31701	3.83729	3.79670	27.21229
4	LN(IC, MILLIAMPS)	18.08139	0.75807	2.07263	8.72391
5	LN(IC, MILLIAMPS)**2	-11.17180	-0.68292	1.42151	-7.85908

DEPENDENT VARIABLE IS NUMBER - 18 - VBE

SAMPLE SIZE = 14.0 DEGREES FREEDOM = 11.0

R**2 = 0.999 R = 1.000 STD ERR OF EST = 0.001

ADJ R**2 = 0.999 ADJ R = 1.000 ADJ STD ERR OF EST = 0.001

LINEAR REGRESSION EQUATION COEFFICIENTS

VAR NO.	NAME	REG WT	BTA WT	WT SIG	T-RATIO
0	CONSTANT TERM	0.71791	23.37929	0.00038	1879.57800
4	LN(IC, MILLIAMPS)	0.02716	0.99830	0.00021	130.24236
5	LN(IC, MILLIAMPS)**2	0.00021	0.01114	0.00014	1.45294

RESULTS ARE IN RAW SCORES

END OF PROBLEM

C3 MICROAMPERE LINEAR REGRESSION PGM, C3 IC-NOMINAL DATA, VCE = 2.0 VOLT

INPUT DATA FORMAT = (16X,3F10.3)

ACHG(1) = 7. 1. 4. 0.0

ACHG(2) = 3. 4. 5. 4.

INPUT DATA	COLLECTOR	BETA	VBE
	106.500	0.0	0.658
	540.000	108.375	0.702
	1080.000	108.000	0.720
	1292.999	106.500	0.725
	1615.999	107.667	0.730
	2139.999	104.800	0.738
	2658.000	103.600	0.745
	3183.000	105.000	0.749
	3688.000	101.000	0.754
	4191.996	100.800	0.758
	5212.996	102.100	0.763
	6175.996	96.300	0.770
	7206.996	103.100	0.772
	8229.996	102.300	0.775

INPUT DATA STATISTICS

VAR NO.	NAME	MEAN	POP STD DEV	SAMP STD DEV
1	COLLECTOR CURRENT	3380.17693	2445.64334	2633.76975
2	BETA	96.39586	26.92444	28.99555
3	VBE	0.73993	0.03071	0.03307
4	LN(IC, MICROAMPS)	7.70398	1.12882	1.21565
5	LN(IC, MICROAMPS)**2	60.62560	15.87491	17.09606

INTERCORRELATION MATRIX

	1	2	3	4	5	
COLLECTOR CURRENT	1	1.00				
BETA	2	0.29	1.00			
VBE	3	0.86	0.67	1.00		
LN(IC, MICROAMPS)	4	0.86	0.68	1.00	1.00	
LN(IC, MICROAMPS)**2	5	0.90	0.60	1.00	0.99	1.00

C3 MICROAMPERE LINEAR REGRESSION PGM, C3 IC-NOMINAL DATA, VCE = 2.0 VOLT

DEPENDENT VARIABLE IS NUMBER - 18 - BETA

SAMPLE SIZE = 14.0 DEGREES FREEDOM = 11.0

R**2 = 0.918 R = 0.958 STD ERR OF EST = 7.705

ADJ R**2 = 0.903 ADJ R = 0.950 ADJ STD ERR OF EST = 8.692

LINEAR REGRESSION EQUATION COEFFICIENTS

VAR NO.	NAME	REG WT	BTA WT	WT SIG	T-RATIO
0	CONSTANT TERM	-554.67056	-20.60101	68.90291	-8.05003
4	LN(IC, MICROAMPS)	172.42553	7.22899	19.99124	8.62505
5	LN(IC, MICROAMPS)**2	-11.17180	-6.58700	1.42151	-7.85908

DEPENDENT VARIABLE IS NUMBER - 18 - VBE

SAMPLE SIZE = 14.0 DEGREES FREEDOM = 11.0

R**2 = 0.999 R = 1.000 STD ERR OF EST = 0.001

ADJ R**2 = 0.999 ADJ R = 1.000 ADJ STD ERR OF EST = 0.001

LINEAR REGRESSION EQUATION COEFFICIENTS

VAR NO.	NAME	REG WT	BTA WT	WT SIG	T-RATIO
0	CONSTANT TERM	0.54023	17.59311	0.00693	77.93624
4	LN(IC, MICROAMPS)	0.02429	0.89277	0.00201	12.07571
5	LN(IC, MICROAMPS)**2	0.00021	0.10742	0.00014	1.45295

RESULTS ARE IN RAW SCORES

3 INSTRUCTIONS FOR PREPARING LINEAR REGRESSION PROGRAM CONTROL CARDS

1. TITLE CARD WITH FORMAT = 18A4, MAY START IN COL 1, ALL OTHER
CONTROL CARDS MUST START IN COL 7.

2. MAIN PARAMETER CD - PROVIDES I/O PARAMETERS TO PGM.

A. COL 7-8 NIND = 12, NUMBER OF INDEPENDENT INPUT VARIABLES

B. COL 10-11 NVAR = NIND + NO. VAR CREATED BY TRANSFORMATIONS

C. COL 13 ICOR = 11, IF ICOR=1, THEN INTERCORRELATION MATRIX
APPEARS IN THE OUTPUT, OTHERWISE NO MATRIX IS PRINTED.
IF NVAR .GE. 15 SET ICOR = 0. THIS RESTRICTION DUE TO FMT.
BE SURE TO INCLUDE A BLANK CARD AS THE FIRST INVERT CARD
WHENEVER ASKING FOR THE INTERCORRELATION MATRIX.

D. COL 15 IPRT=CARRIAGE CONTROL, SETS PAGE SPACING BETWEEN EQNS

0 MEANS FOR PRINTER TO SKIP TWO LINES
- MEANS FOR PRINTER TO SKIP THREE LINES
1 MEANS FOR PRINTER TO SKIP TO NEW PAGE
2 MEANS FOR PRINTER TO SKIP TO NEW HALF PAGE

E. COL 17 ICHG=1 TO TRANSFORM VARIABLES, FOR NO TRANS, ICHG=0

F. COL 19-27 TST = F FORMAT NO. .GE. MAX. DATA VAR + 0.5
TST USED BY PGM TO SIGNAL END OF DATA.

3. DATA VAR NAME CDS, ONE NAME PER CD. FORMAT IS 6A4.

4. INPLT DATA FORMAT CD, EX. (16X,6F10.3) = ENTRY NEEDED TO READ
6 SETS OF INPUT DATA. PARENTHESES ARE REQUIRED IN ENTRY.
IF A DIFFERENT FORMAT DESIRED CHECK INTO DATA TITLES OF
FORMAT STMT NO. 615.

5. CHANGE CARDS DEFINE THE VARIABLE TRANSFORMATIONS FOR FORMING
LINEAR REGRESSIONS EQUATIONS AS DEFINED BY THE INVERT CDS

A. TRANSFORMATION CARD INPUT CODES ARE...

I COLS 7-8 IN FIXED POINT FORMAT ONLY
J COLS 10-11 IN FIXED POINT FORMAT ONLY
K COLS 13-14 IN FIXED POINT FORMAT ONLY
L OR DL COLS 19-27 IN FLOATING POINT FORMAT ONLY

B. TRANSFORMATIONS OPERATIONS CODE IS..

```

01 A(K)=A(J)*DL
02 A(K)=1./(A(J)**DL)
03 A(K)=A(J)*A(L)
04 A(K)=A(J)/A(L)
05 A(K)=A(J)-A(L)
06 A(K)=SQRT(A(J))
07 A(K)=ELOG(A(J))
08 A(K)=EXP(A(J))
09 A(K)=A(J)+A(J)
10 A(K)=ICDT
11 A(K)=A(J)+DL
12 A(K)=A(J)*(DL)

```

C. AN EXAMPLE TRANSFORMATION SPECIFICATION CODE IS...

```

INDEX      II JJ KK LLLLLL
CARD COL   7890123456789
TRANS CODE 04 03 07 06.

```

THIS CODE INSTRUCTS THE PGM THAT DESIRED TRANSFORMATION IS 04 $A(K)=A(J)/A(L)$. PGM IS TO DIVIDE VAR 3 BY VAR 6 AND STORE THE RESULT IN VAR A(7).

D. NOTE DL IS USED OCCASIONALLY AS A FIXED POINT CONSTANT MULTIPLIER OR EXPONENT. DL IS ENTERED IN COLS 8-12 IN PLACE OF L.. NOTE THAT L AND DL ARE NEVER REQUIRED IN THE SAME TRANSFORMATION.

E. ENTRY 00 IN COLS 7-8 MEANS MC MORE CHANGE CARDS PRESENT.

7. AN END OF DATA CARD IS PUT AT THE CONCLUSION OF EACH SET. THIS END CARD MUST HAVE A VALUE (IN THE FIELD OF THE FIRST VARIABLE) THAT IS GREATER THAN TST BY 0.1 OR MORE, NOTE VALUE FOR TST WAS ENTERED ON THE MAIN PARAMETER CARD 2. SEVERAL SETS OF DATA CAN BE CONCATENATED IN ONE CMPTR RUN.

8. INVERT CARDS DEFINE MODELS USING COLS 7 - 37, WITH COL 7 FOR VAR(1).

A. AN EXAMPLE INVERT CARD CODE IS....

```

CARD COL 7 8 9 0 1 2 3
ENTRY    2 0 0 1 1 0 C

```

B. REGRESSION MODEL CODES....

```

COL 7=C = VARIABLE NOT USED
          1 = INDEPENDENT VARIABLE
          2 = DEPENDENT VARIABLE
          3 = RESTART PGM WITH ALL NEW VARIABLES, CAUSES
PGM START THRU THE SET OF MODELS ONCE AGAIN AS DEFINED BY
THE INVERT CD USING NEW DATA.
COL 7=4 = END OF PGM CARD, TERMINATES ALL PROGRAM CALC.
          3 = RESTART PGM WITH ALL NEW VARIABLES

```


5 LINEAR REGRESSION INPUT DATA TRANSFORMATION PROGRAM

THIS PROGRAM CALCULATES, USING MEASURED CARD INPUT DATA, BETA,
MEAN COLLECTOR CURRENT, ICM, DATA FORMAT CONVERSION,
AND PUNCHES CARDS WHICH ARE THEN USED AS INPUT DATA TO LINEAR
REGRESSION MODEL COEFFICIENT CALCULATING PROGRAM.

```

COMMON VCE(260),IB(260),IC(260),VCB(260),VBE(260)
COMMON BETA(260),TVCE(260),VCEDEV(260)
COMMON DIC(260),DIB(260),ICA(260),ICM(260)
200 FORMAT(' ',4X,F9.3,1X,F10.6,1X,F10.5,1X,F6.3,5X,F6.3)
300 FORMAT('1')
301 FORMAT('2',2X,'VCE',6X,'IB',5X,'IC-MEAN',5X,'BETA',7X,'VBE',7X,
1   'VCB',6X,'VCEDEV'//)
C 400 FORMAT(' ',F5.2,2F10.6,F10.3,3F10.3,6X,'C1DAT',I3)      MA.REGSN
400 FORMAT(' ',F5.2, F10.6,F10.3,F10.3,3F10.3,6X,'C1DAT',I3)  MICR.REG
C 401 FORMAT(' ',F5.2 ,2F10.6,F10.3,3F10.3,6X,'C1DAT',I3,5X,3F12.3) MA.REGSN
401 FORMAT(' ',F5.2,1F10.6,F10.3,F10.3,3F10.3,6X,'C1DAT',I3,5X,3F12.3)MICR.REG
402 FORMAT(' ',22X'***** END OF DATA *****')
REAL IB,IC,ICA,ICM
N=000
BETA(1) = C.CCC
DIB(1) = 0.
DIC(1) = 0.
VBE(1) = 0.0
IC(1) = C.C00C001
IB(1) = C.CCC00C1
VCE(1) = 0.5
WRITE(6,3CC)
DO 13 J=2,261
12 N=N+1
BETA(J) = C.000
10 READ(5,20C,END=14)VCE(J),IB(J),IC(J),VBE(J),VCB(J)
13 CONTINUE
14 DO 16 J=2, N
IF(VCE(J+1) .NE. VCE(J)) GOTO 15
8 DIB(J+1) = IB(J+1) - IB(J)
DIC(J+1) = IC(J+1) - IC(J)
IF(IB(J+1) .EQ. IB(J)) GOTO 15
ICM(J+1) = (IC(J+1) + IC(J))/2.0
ICM(J+1) = ICM(J+1)*1000.0
BETA(J+1) = DIC(J+1)/DIB(J+1)
15 TVCE(J)=VBE(J) + VCB(J)
VCEDEV(J) = VCE(J) - TVCE(J)
ICA(J) = ( IC(J) )/1.0
16 CONTINUE
VCE(N+1) = 1CC.C
30 DO 40 J=2, N
K=J-1
IF(VCE(J+1) .GT. VCE(J)) WRITE(6,301)
WRITE(6,401)VCE(J),IB(J),ICM(J),BETA(J), VBE(J),VCB(J),VCEDEV(J),K
1,BETA(J ),DIC(J ),DIB(J )
WRITE(7,400)VCE(J),IB(J),ICM(J),BETA(J),VBE(J),VCB(J),VCEDEV(J),K
40 CONTINUE
WRITE(6,4C2)
STOP
END

```


APPENDIX D

REGRESSION MODEL EFFECTIVENESS PROGRAM

1 REGRESSION MODEL EFFECTIVENESS PROGRAM LISTING

```

COMMON VCE(200), BETAM(200),VBEM(200),BETAC(200),VBEC(200)
COMMON VDIFF(200),BDIFF(200),B(5),V(5),K,M,TITLE(8),UNITS(5)
COMMON INT
REAL ICM(200)
102 FORMAT(6X,8A4)
104 FORMAT(6X,4F12.5,21X,5A1)
106 FORMAT(6X,4F12.5,21X,5A1)
108 FORMAT(11,F5.2,10X,3F10.3)
200 FORMAT('1', 5X,'ANALYSIS OF REGRESSION EQUATION FOR BETA - 'BA4/
1'-',5X,'BETA = ',F10.5,' + ',F10.5,' * LN (IC) + ',F10.5,' * '
2'(LN(IC))**2',/ )
202 FORMAT('0',7X,'VCE',11X,'IC',10X,'MEASURED',6X,'CALCULATED'8X,
1 'BETA',/,36X,'BETA',11X,'BETA',8X,'MEAS-CALC',/,
2 7X,'VOLTS',6X,('5A1,'AMPS)',7X,'(--)',11X,'(--)',11X,'(--)' )
204 FORMAT(6X,F6.2,4F15.5)
205 FORMAT('1', 5X,'ANALYSIS OF REGRESSION EQUATION FOR VBE - ',BA4,/
1'-',5X,'VBE = ',F9.5,' + ',F9.5,' * LN (IC) + ', F9.5, ' * '
2'(LN(IC))**2',/ )
206 FORMAT('0',7X,'VCE',11X,'IC',10X,'MEASURED',6X,'CALCULATED'8X,
1 'VBE',/,37X,'VBE ',10X,' VBE',8X,'MEAS-CALC',/ ,
2 7X,'VOLTS',6X,('5A1,'AMPS)',7X,'(--)',11X,'(--)',11X,'(--)' )
208 FORMAT(6X,F6.2,4F15.5)
10 K=0
M=1
READ(5,102,END=40) (TITLE(II), II=1,8)
READ(5,104) B(1),B(2),B(3),B(4),(UNITS(KK), KK=1,5)
READ(5,106) V(1),V(2),V(3),V(4),(UNITS(KK), KK=1,5)
B(4) = 0.C
V(4) = 0.C
DO 15 I=1,200
READ(5,108,END=20) INT,VCE(I),ICM(I),BETAM(I),VBEM(I)
IF(INT .GE. M) GOTO 20
K = K + 1
15 CONTINUE
20 DO 30 J=1,K
BETAC(J) = B(1) + B(2)*(ALOG(ICM(J))) + B(3)*((ALOG(ICM(J)))**2)
VBEC(J) = V(1) + V(2)*(ALOG(ICM(J))) + V(3)*((ALOG(ICM(J)))**2)
BDIFF(J) = BETAM(J) - BETAC(J)
VDIFF(J) = VBEM(J) - VBEC(J)
30 CONTINUE
WRITE(6,200) (TITLE(JJ),JJ=1,8), B(1),B(2),B(3)
WRITE(6,202) (UNITS(KK), KK=1,5)
WRITE(6,204) (VCE(I),ICM(I),BETAM(I),BETAC(I),BDIFF(I), I=1,K)
WRITE(6,205) (TITLE(JJ),JJ=1,8), V(1),V(2),V(3)
WRITE(6,206) (UNITS(KK), KK=1,5)
WRITE(6,208) (VCE(I),ICM(I),VBEM(I),VBEC(I),VDIFF(I), I=1,K)
INT = 0
GOTO 10
40 STOP
END

```


ANALYSIS OF REGRESSION EQUATION FOR BETA - C3 IC-NOMINAL VCE=2.0 VDC

$$BETA = 103.31700 + 18.08138 * LN(IC) + -11.17180 * (LN(IC))^{**2}$$

VCE VOLTS	IC (MILLIAMPS)	MEASURED BETA (--)	CALCULATED BETA (--)	BETA MEAS-CALC (--)
0.0	0.10600	0.0	6.46486	-6.46486
0.0	0.54000	108.37500	87.93373	20.44127
0.0	1.08000	108.00000	104.64238	3.35762
0.0	1.29300	106.50000	107.22557	-0.72557
0.0	1.61600	107.66699	109.42172	-1.75473
0.0	2.14000	104.79999	110.60689	-5.80690
0.0	2.65800	103.59999	110.31653	-6.71654
0.0	3.18300	105.00000	109.27560	-4.27560
0.0	3.68800	101.00000	107.88643	-6.88643
0.0	4.19200	100.79999	106.28398	-5.48399
0.0	5.21300	102.09999	102.71432	-0.61433
0.0	6.17600	96.29999	99.20450	-2.90451
0.0	7.20700	103.09999	95.44937	7.65062
0.0	8.23000	102.29999	91.79503	10.50496

ANALYSIS OF REGRESSION EQUATION FOR VBE - C3 IC-NOMINAL VCE=2.0 VDC

$$VBE = 0.71791 + 0.02716 * LN(IC) + 0.00021 * (LN(IC))^{**2}$$

VCE VOLTS	IC (MILLIAMPS)	MEASURED VBE (--)	CALCULATED VBE (--)	VBE MEAS-CALC (--)
0.0	0.10600	0.65800	0.65801	-0.00001
0.0	0.54000	0.70200	0.70125	0.00075
0.0	1.08000	0.72000	0.72000	-0.00000
0.0	1.29300	0.72500	0.72490	0.00010
0.0	1.61600	0.73000	0.73099	-0.00099
0.0	2.14000	0.73800	0.73869	-0.00069
0.0	2.65800	0.74500	0.74466	0.00034
0.0	3.18300	0.74900	0.74964	-0.00064
0.0	3.68800	0.75400	0.75371	0.00029
0.0	4.19200	0.75800	0.75727	0.00073
0.0	5.21300	0.76300	0.76333	-0.00033
0.0	6.17600	0.77000	0.76806	0.00194
0.0	7.20700	0.77200	0.77237	-0.00037
0.0	8.23000	0.77500	0.77609	-0.00109

ANALYSIS OF REGRESSION EQUATION FOR BETA - C3 IC-NOMINAL VCE=2.0 VDC

$$BETA = -554.67041 + 172.42552 * LN(IC) + -11.17180 * (LN(IC))^{**2}$$

VCE VOLTS	IC (MICROAMPS)	MEASURED BETA (--)	CALCULATED BETA (--)	BETA MEAS-CALC (--)
0.0	106.50000	0.0	6.78583	-6.78583
0.0	540.00000	108.37500	87.93408	20.44092
0.0	1080.00000	108.00000	104.64282	3.35718
0.0	1292.99878	106.50000	107.22583	-0.72583
0.0	1615.99878	107.66699	109.42187	-1.75488
0.0	2139.99878	104.79999	110.60718	-5.80719
0.0	2658.00000	103.59999	110.31689	-6.71690
0.0	3183.00000	105.00000	109.27612	-4.27612
0.0	3688.00000	101.00000	107.88672	-6.88672
0.0	4151.99219	100.79999	106.28442	-5.48444
0.0	5212.99219	102.09999	102.71484	-0.61485
0.0	6175.99219	96.29999	99.20483	-2.90485
0.0	7206.99219	103.09999	95.44971	7.65028
0.0	8229.99219	102.29999	91.79541	10.50458

ANALYSIS OF REGRESSION EQUATION FOR VBE - C3 IC-NOMINAL VCE=2.0 VDC

$$VBE = 0.54023 + 0.02429 * LN(IC) + 0.00021 * (LN(IC))^{**2}$$

VCE VOLTS	IC (MICROAMPS)	MEASURED VBE (--)	CALCULATED VBE (--)	VBE MEAS-CALC (--)
0.0	106.50000	0.65800	0.65820	-0.00020
0.0	540.00000	0.70200	0.70136	0.00064
0.0	1080.00000	0.72000	0.72013	-0.00013
0.0	1292.99878	0.72500	0.72504	-0.00004
0.0	1615.99878	0.73000	0.73114	-0.00114
0.0	2139.99878	0.73800	0.73885	-0.00085
0.0	2658.00000	0.74500	0.74482	0.00018
0.0	3183.00000	0.74900	0.74980	-0.00080
0.0	3688.00000	0.75400	0.75388	0.00012
0.0	4191.99219	0.75800	0.75744	0.00056
0.0	5212.99219	0.76300	0.76351	-0.00051
0.0	6175.99219	0.77000	0.76824	0.00176
0.0	7206.99219	0.77200	0.77256	-0.00056
0.0	8229.99219	0.77500	0.77629	-0.00129

3 PROGRAM COMMENTS

1. INPUT CARDS

- A. TITLE CARD - READ IN TRANSISTOR TYPE, METHOD OF OBTAINING IC - WHETHER NOMINAL VALUE OR MEAN VALUE OF IC IS USED IN THE COLLECTOR CURRENT, IC, DATA, AND THE COLLECTOR TO EMITTER VOLTAGE, VCE.
- B. BETA EQUATION CARD - COEFFICIENTS OF THE REGRESSION MODEL BETA EQUATION ARE READ IN BY FORMAT(6X,4F12.5,5A1). NUMERIC VALUES ARE OBTAINED FROM REGRESSION PROGRAM OUTPUT. THE LAST 5A1 CHARACTERS COMPRISE THE COLLECTOR CURRENT UNIT'S PREFIX OR MULTIPLYING FACTOR. THAT IS MICRO IMPLIES MICROAMPERE UNITS, MILLI IMPLIES MILLIAMPERES UNITS, AND 5 BLANKS SIMPLY MEAN THAT THE CURRENT UNITS ARE IN AMPERES. THE PREFIX READ IN IS PLACED IN THE OUTPUT UNDER THE IC HEADING.
- C. VBE EQUATION CARD - COEFFICIENTS OF THE REGRESSION MODEL VBE EQUATION ARE READ IN BY FORMAT(6X,4F12.5,5A1). NUMERIC VALUES ARE OBTAINED FROM REGRESSION PROGRAM OUTPUT.
- D. DATA CARDS - READ USING FORMAT(I1,F5.2,3F10.3). CARDS MAY BE OBTAINED FROM THE LINEAR REGRESSION'S PROGRAM'S PUNCHED OUTPUT DATA SET.
- E. END OF DATA CARD - ANY INTEGER GREATER THAN 1 ENABLES PROGRAM TO BEGIN READING ANOTHER DATA SET. IF A /* CARD IS ENCOUNTERED, THEN CONTROL IS RETURNED TO SYSTEM MONITOR. INTEGER MUST BE PLACED IN COLUMN 1. PROGRAM WILL NOT WORK WITHOUT THIS CARD.

2. SAMPLE DATA DECK

C1 IC-NOMINAL VCE=2.0 VDC			MILLIAMPERES
104.48077	-5.28263	-3.90085	C1 2. B MILLI
0.74633	C.02786	-0.00499	C1 2. V MILLI
	0.007	0.0	0.404
	C.017	99.500	0.604
	C.029	84.200	0.631
	C.052	92.120	0.651
	0.101	96.080	0.669
	0.198	97.700	0.688
	0.300	101.500	0.699
	0.403	102.900	0.708
	C.808	101.700	0.727
	1.012	102.000	0.734
	6.538	90.100	0.795
	7.293	75.500	0.802

3 (A NO. .GR. 1 IN COL 1 PERMITS RUN OF ANOTHER DATA SET OR TERMINATES PGM RUN)

C1 IC-NOMINAL VCE=2.0 VDC

-45.16509	48.60955	-3.90085	
0.31567	0.09683	-0.80499	
	6.750	0.0	0.404
	16.700	99.500	0.604
	29.330	84.200	0.631
	52.360	92.120	0.651
	706.300	102.000	0.724
	808.000	101.700	0.727
	1011.999	102.000	0.734
	5636.996	83.500	0.792
	6537.996	90.100	0.795
	7292.996	75.500	0.802

MICROAMPERES

C1 2. 8 MICRO

C1 2. V MICRO

3

END OF SAMPLE DATA DECK

4 TYPICAL INPUT DATA DECK

C3 IC-NOMINAL VCE=2.0 VDC

103.31701 18.08139 -11.17180

0.71791 0.02716 0.00021

C.106	0.C	0.658
0.540	108.375	0.702
1.080	108.000	0.720
1.293	106.500	0.725
1.616	107.667	0.730
2.140	104.800	0.738
2.658	103.600	0.745
3.183	105.000	0.749
3.688	101.000	0.754
4.192	100.800	0.758
5.213	102.100	0.763
6.176	96.300	0.770
7.207	103.100	0.772
8.230	102.300	0.775

MILLIAMPERES

C3 2. B MILLI

C3 2. V MILLI

3

C3 IC-NOMINAL VCE=2.0 VDC

-554.67056 172.42553 -11.1718

C.54023 C.02429 0.00021

106.500	0.C	0.658
540.000	108.375	0.702
1080.000	108.000	0.720
1292.999	106.500	0.725
1615.999	107.667	0.730
2139.999	104.800	0.738
2658.000	103.600	0.745
3183.000	105.000	0.749
3688.000	101.000	0.754
4191.996	100.800	0.758
5212.996	102.100	0.763
6175.996	96.300	0.770
7206.996	103.100	0.772
8229.996	102.300	0.775

MICROAMPERES

C3 2. B MICRO

C3 2. V MICRO

3

APPENDIX E

NLAP OUTPUT SUBROUTINE LISTING

	SUBROUTINE ECB25	DC250000
	COMMON CCSAV(6,200),IDWORD(74)	
	DOUBLE PRECISION X(200)	DC250010
	COMMON NMAX,NNODE,NTERMS,NUMBL,NUMBR,NUMBC,IRTN,NTRACE,NSWITCH,KTO,DC250020	
	1 NPRINT(10)	DC250030
	COMMON E(200),EMIN(200),EMAX(200),AMP(200),AMPMIN(200),AMPMAX(200)	DC250040
	COMMON Y(200),YMIN(200),YMAX(200),NINIT(200),NFIN(200),MODE1(200)	DC250050
	COMMON YTERM(200),YTERMH(200),YTERML(200),IROWT(200),ICOLT(200)	DC250060
	COMMON ERROR1,ISEQ,MSEQ,MO,NUMMO,VFIRST(50),VSECNO(50),VLAST(50)	DC250070
	COMMON MOBRN(50),MOPARN(50),MOSTEP(50),IWCOUT(4)	DC250080
C		DC250090
C	THE FOLLOWING VARIABLES ARE USED ONLY IN THE ECAP O.C. ANALYSIS	DC250100
C		DC250110
	COMMON AX1,SMLEP(50),CURR(200),SMLE(200),EQUCUR(50),EX(200)	DC250120
	COMMON E8(200),AMPX(200),AMPB(200),VNOM(50),STOSQ(50),L,M,ITOL	DC250130
	COMMON JX1,JX4,JX5,DELTA,DUM1(28)	DC250140
C		DC250150
	COMMON LANG1(217),NTR,LANG2(47)	
C		DC250170
	COMMON MATA(200,4,3),YX(200),YB(200),YTERMX(200),YTERMB(200)	DC250180
	COMMON WCMAX(50),WCMIN(50)	DC250190
	COMMON CCSAV(2,200)	
C		DC250200
	DOUBLE PRECISION SMLEP,CURR,SMLE,EQUCUR	DC250210
C		DC250220
	1 IF(NTRACE)3,4,3	DC250230
	2 FORMAT(6H ECB25)	
	3 WRITE(6,2)	
C		DC250250
C	OUTPUT NODE VOLTAGES	DC250270
C		DC250280
	4 KNNODE = NNODE + 1	DC250290
	DO 5 I=1,NNODE	DC250292
	5 CCSAV(6,I)=SMLEP(I)	
	DO 6 K=KNNODE, NMAX	
	6 CCSAV(6,K) = .0	DC250293
C		DC250294
C	BRANCH VOLTAGES	DC250400
C		DC250410
	101 DO 10 I=1,NMAX	DC250420
	SMLE(I) = 0.0	DC250430
	J=NINIT(I)	DC250440
	IF(J)11,11,12	DC250450
	12 SMLE(I) = SMLEP(J)	DC250460
	11 K=NFIN(I)	DC250470
	IF (K) 10, 10, 14	DC250480
	14 SMLE(I) = SMLE(I) - SMLEP(K)	DC250490
		DC250500

10	CONTINUE	DC250510
	DO 16 I=1,NMAX	
16	CCSAV(1,I)=SMLE(I)	
C		DC250630
C	ELEMENT VOLTAGES	DC250640
C		DC250650
	DO 17 I=1,NMAX	
	SMLE(I)=SMLE(I)+EX(I)	
17	CCSAV(3,I)=SMLE(I)	
C		DC250780
C	ELEMENT CURRENTS	DC250790
C		DC250800
103	DO 20 I=1,NMAX	DC250810
20	CURR(I)=YX(I)*SMLE(I)	DC250820
	IF(INTERMS)21,22,21	DC250830
21	DO 23 I=1,INTERMS	DC250840
	NR=IROWT(I)	DC250850
	NC=ICOLT(I)	DC250860
	IF(SMLE(NC))24,23,24	DC250870
24	CURR(NR)=CURR(NR)+YTERM(I)*SMLE(NC)	DC250880
23	CONTINUE	DC250890
22	DO 27 I=1,NMAX	
27	CCSAV(4,I)=CURR(I)	
C		DCB25092
C		DCB25093
C	BETA SAVE	DCB25094
C		DCB25095
	DO 28 N = 1,NMAX	DCB25096
	NFBR = ICOLT(N)	
	NTBR = IROWT(N)	
	CDSAV(1,N) = 0.0	
	CDSAV(2,N) = 0.0	
	CDSAV(1,N) = YTERM(N)	
	IF(ICOLT(N) .EQ. 0) GOTO 28	
	CDSAV(2,N) = (CDSAV(1,N))/(Y(NFBR))	
28	CONTINUE	
C		DC251010
C	BRANCH POWER LOSSES	DC251020
C		DC251030
	DO 29 I=1,NMAX	
29	CCSAV(5,I)=CURR(I)*SMLE(I)	
C		DC251140
C	BRANCH CURRENTS	DC251150
C		DC251160
105	DO 30 I=1,NMAX	DC251170
30	CURR(I)=CURR(I)-AMPX(I)	DC251180
C		DC251190
C	CHECK UNBALANCES	DC251200
C		DC251210
	DO 33 I=1,NNODE	DC251220
33	X(I)=0.	DC251230
	DO 36 I=1,NMAX	DC251240
	J=NINIT(I)	DC251250
	K=NFIN(I)	DC251260
	IF(K)34,34,35	DC251270
35	X(K)=X(K)+CURR(I)	DC251280
34	IF(J)36,36,37	DC251290
37	X(J)=X(J)-CURR(I)	DC251300


```

36 CONTINUE                                DC251310
   SUM=0.                                DC251320
   DO 38 I=1,NNODE                        DC251330
38  SUM = SUM + DABS( X( I ) )             DC251340
   IF(SUM-ERROR1)106,106,40              DC251350
40  WRITE(6,141)                          DC251360
   WRITE (6,142)                          DC251370
141 FORMAT( // *3H SOLUTION NOT OBTAINED TO DESIRED TOLERANCE// ) DC251380
142 FORMAT( 6H NODES,15X,19H CURRENT UNBALANCES / ) DC251390
   KMAX=NNODE                             DC251400
   IND=6                                  DC251410
   GO TO 100                              DC251420
106 DO 42 I=1,NMAX
   42 CCSAV(2,I)=CURR(I)
   IF (JX4 .GT. C) GOTO 900
398 GO TO (399,399,399,900),NTR          DCA25104
399 CALL BCDBN1(3,1,IDWORD(4) )          DCA25105
   IF(IDWORD(5) .GE. 1) IDWORD(73) = 0
   IDWORD(73) = IDWORD(73) + 1
C   IDWORD(73) = (IDWORD(73) + 1)/2
   WRITE(6,801) (IDWORD(IK), IK=7,72),IDWORD(3),IDWORD(4),IDWORD(73)
   WRITE (6,800)
   IF (NMAX-NNODE) 400,500,401          DCA25108
400 MAX=NNODE
   MIN=NMAX
   GO TO 402
401 MAX=NMAX
   MIN=NNODE
402 DO 403 I=1,NMAX
403 X(I)=1.0/Y(I)
   WRITE (6,850) (I,E(I),AMP(I),X(I),(CCSAV(J,I),J=1,6),I,I=1,MIN) DCB25117
   IF (MIN-MAX) 404,500,900
404 MIN=MIN+1
   WRITE (6,851)(I,E(I),AMP(I),X(I),(CCSAV(J,I), J=1,5), I= MIN,MAX) DCB251
C   IF (IDWORD(74) .LE. 0) GOTO 900      TEST DCA25121
405 WRITE (8,852) (IDWORD(I), I=1, 73)  DCA25122
   WRITE( 7,852) (IDWORD(I), I=1, 73)
   WRITE (9,852) (IDWORD(I), I=1, 73)
   WRITE(10,852) (IDWORD(I), I=1, 73)
   WRITE(11,852) (IDWORD(I), I=1, 73)
   WRITE(7,853) (IDWORD(3),IDWORD(73),I,E(I),AMP(I),X(I),(CCSAV(J,I),
1 J=1,6), I=1, MAX)
   WRITE(8,854) (IDWORD(3),IDWORD(73),I,E(I),AMP(I),X(I),(CCSAV(J,I),
1 J=1,6), I=1, MAX)
   WRITE(9,855) (IDWORD(3),IDWORD(73),I,E(I),AMP(I),X(I),CCSAV(1,I),
1CCSAV(1,I),CCSAV(2,I),CCSAV(5,I),CCSAV(6,I), I=1, MAX )
   WRITE(10,855) (IDWORD(3),IDWORD(73),I,E(I),AMP(I),X(I),CCSAV(2,I),
1CCSAV(1,I),CCSAV(2,I),CCSAV(5,I),CCSAV(6,I), I=1, MAX )
   WRITE(11,855) (IDWORD(3),IDWORD(73),I,E(I),AMP(I),X(I),CCSAV(2,I),
1CCSAV(1,I),CCSAV(2,I),CCSAV(5,I),CCSAV(6,I), I=1, MAX )
   GO TO 900
800 FORMAT (' BRANCH',3X,'VOLTAGE',5X,'CURRENT',7X,'BRANCH',7X, DCB25121
1'BRANCH',8X,'BRANCH',7X,'ELEMENT',7X,'ELEMENT',5X,'ELEMENT',7X DCB25122
2'NODE',6X,'NODE',' NUMBER',3X,'SOURCE',6X,'SOURCE',6X,'RESISTANCE' DCB25123
3,5X,'VOLTAGE',7X,'CURRENT',6X,'VOLTAGE',7X,'CURRENT',4X, DCB25124
4'POWER LOSS',4X,'VOLTAGE',3X,'NUMBER'/10X,'(VOLTS)',6X,'(MA)',9X, DCB25125
5'(OHMS)',7X,'(VOLTS)',8X,'(MA)',8X,'(VOLTS)',8X,'(MA)',7X, DCB25126
6'(WATTS)',6X,'(VOLTS)')//J)          DCB25127
801 FORMAT('1',40X,66A1/'0',40X,'PROBLEM NO. =',2X,A1,A1,10X,'SOLUTION

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      1 NO. = 'I3,////)
850 FORMAT(' ',I4,2X,F10.3,   3PF12.4,3X,OPF12.2,2X,F11.6,2X,3PF12.6,
      12X,OPF11.6,2X,3PF12.6,2X,OPF10.4,2X,OPF12.6,2X,I5)
851 FORMAT(' ',I4,2X,F10.3,   3PF12.4,3X,OPF12.2,2X,F11.6,2X,3PF12.6,
      12X,OPF11.6,2X,3PF12.6,2X,OPF10.4)
852 FORMAT (1X,'C',1X,72A1,I3)
853 FORMAT('P',A1,'-S',I3,'-B',I2,   F7.3,3PF8.2,OPF11.2,F7.3,3PF8.3,
      1OPF7.3,3PF8.3,OPF6.3,OPF7.3)
854 FORMAT(' P',A1,'-S',I3,'-B',I2,   F7.3,3PF6.2,OPF11.2,F7.3,3PF8.3,
      1OPF7.3,3PF9.3,OPF6.3,OPF7.3)
855 FORMAT(' P',A1,'-S',I3,'-B',I2,   F8.3,3PF8.2,OPF11.2, F9.3,F8.3,
      13PF9.3, OPF7.3,CPF8.3)
856 FORMAT(' P',A1,'-S',I3,'-B',I2,1X,F7.3,3PF8.2,OPF11.2,F7.3,3PF10.3
      1 ,OPF6.3,OPF7.3)
860 FORMAT(' ',5X,'P',A1,'-S',I3,'-B',I2,5X,'EC825',10X,'ICCLT(' ,I3,' )
      1 =' ,I4,10X,'IROWT(' ,I3,' ) =' ,I4 )

C
C      OUTPUT ROUTINE
C
100 LAST=0
150 K=LAST+1
      LAST=LAST+4
      IF(LAST-KMAX)200,200,201
201 LAST=KMAX
200 WRITE(6,203)K,LAST,(X(J),J=K,LAST)
203 FORMAT(1X,I3,1H-,I3,2X,4(3X,E15.8))
      IF(KMAX-LAST)500,500,150

C
500 GOTO 106
900 RETURN
      END

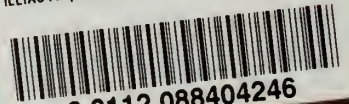
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DC251520
DC251530
DC251540
DC251550
DC251560
DC251570
DC251580
DC251590
DC251600
DC251610
DC251620
DC251630

DC251650
DC251660

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510.84 IL6R v.2 C002 v.271-278(1968)
ILLIAC IV quarterly progress report.



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